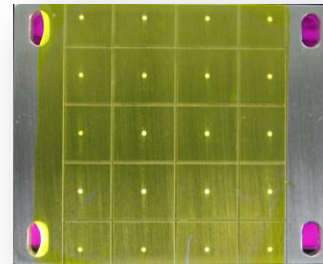


Acceleration and Characterization of Protons and Ions from Nanometer-Scale Thin Polymer Foil



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Advanced Photonics Research Institute, Gwangju Institute of Science and Technology (GIST)
Korea

Targetry for Laser-driven Proton (Ion) Accelerator Sources, Institute for Advanced Study, Garching, Germany, Oct. 9 2013.



Outline

1

PW laser and application facility at GIST

2

Contrast enhancement and laser beam focusing

3

Ultrathin free-standing polymer target

4

Ion acceleration using PW laser and ultrathin target

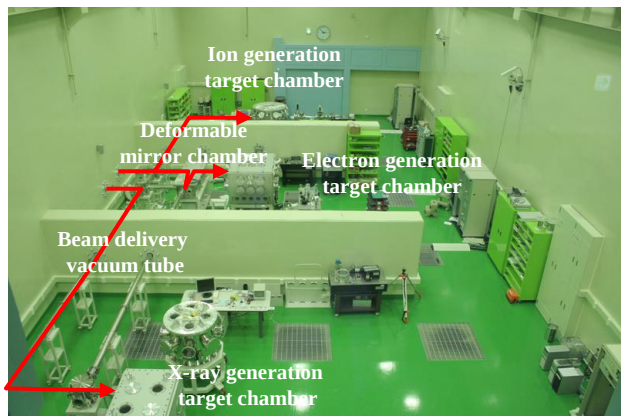
5

Conclusion



100 TW and PW Laser Systems, Interaction Target Chambers

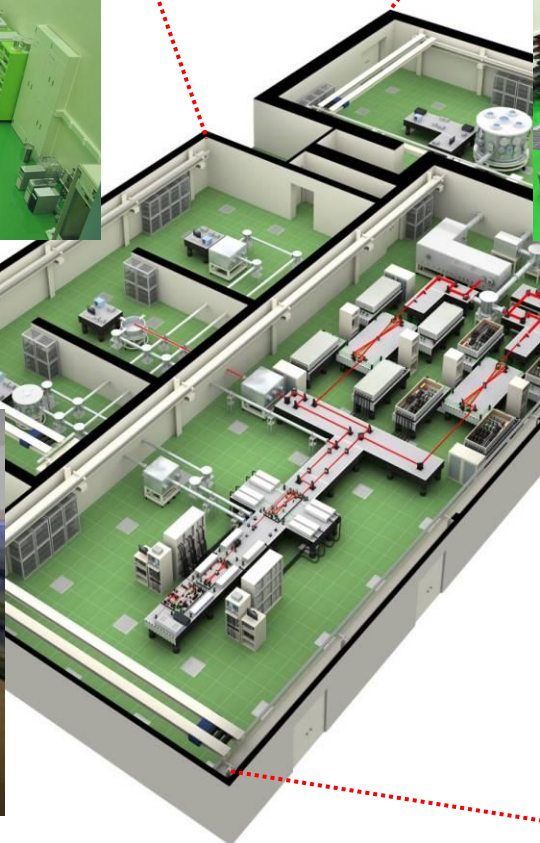
100 TW laser-plasma laboratory



PW laser-plasma laboratory



Control room



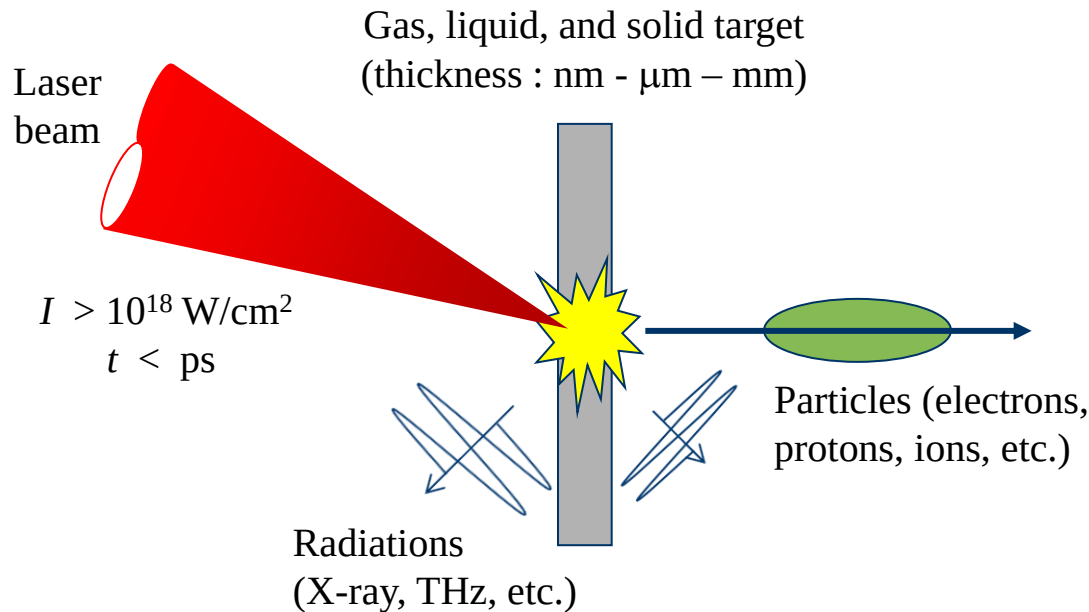
Ultrashort PW laser system



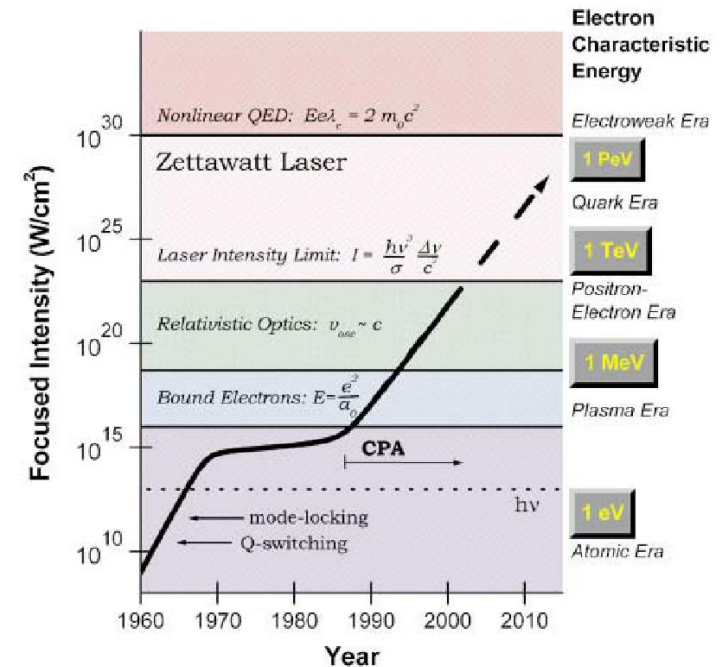
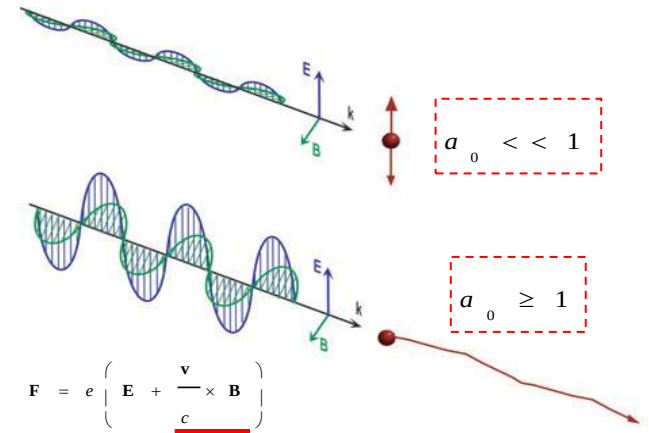
Interaction of Ultrashort Ultraintense Laser with Matter

Interaction of laser and matter in relativistic regime

$$\text{Dimensionless laser amplitude : } a_0 = \frac{e E}{m_0 \omega c} \approx 8.55 \times 10^{-10} I_{\text{W/cm}^2}^{1/2} \lambda_{\mu\text{m}}$$



Opened up exotic research areas, such as the generation of ultrashort x-ray and particle sources, and the study on the high-field physics

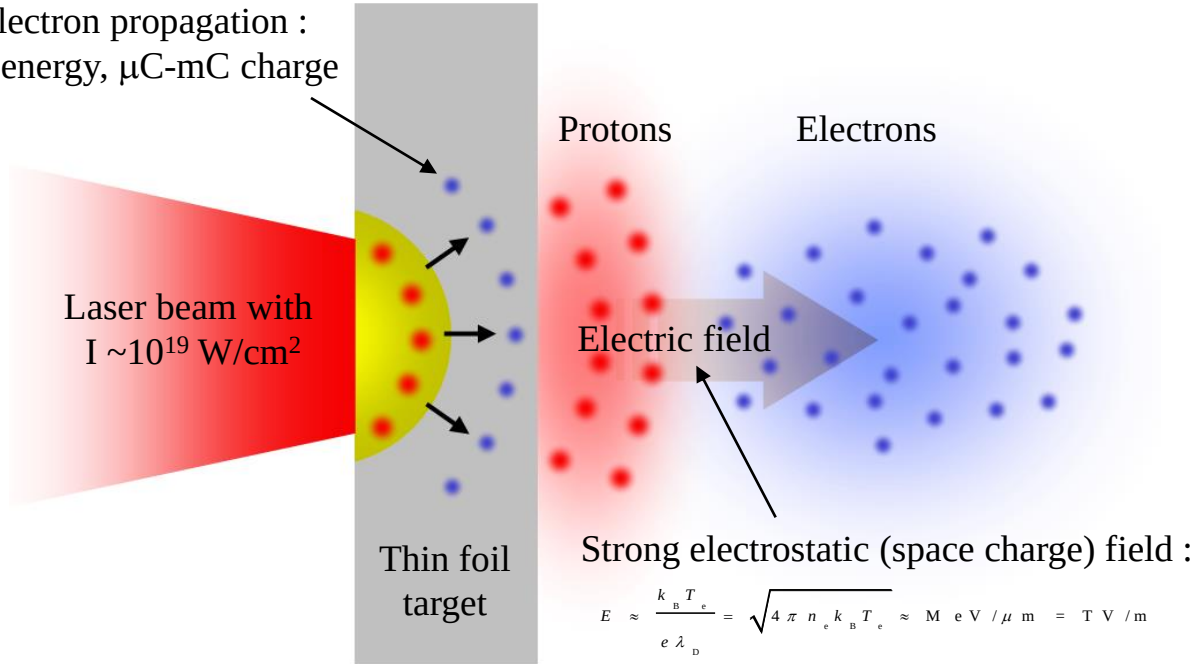


T. Tajima and G. Mourou, PRST-AB 5, 031301 (2002).

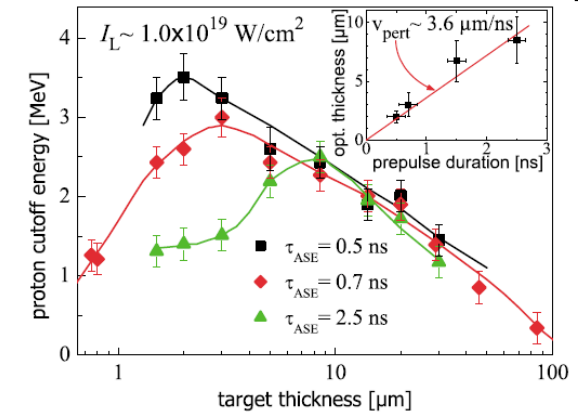


Target Normal Sheath Acceleration (TNSA) and Optimum Thickness

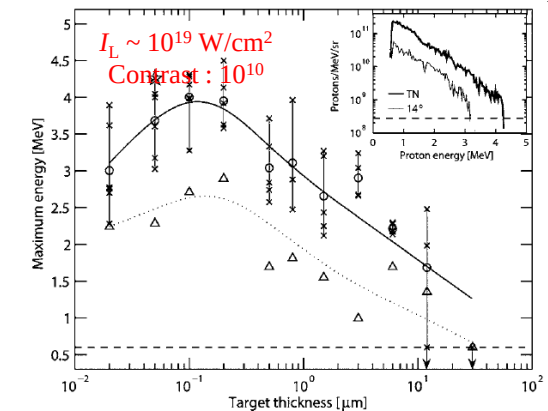
Hot electron propagation :
MeV energy, μC -mC charge



- Transverse spreading
- Surface deformation and density gradient
- Recirculation and refluxing
- Absorption of laser energy in the target



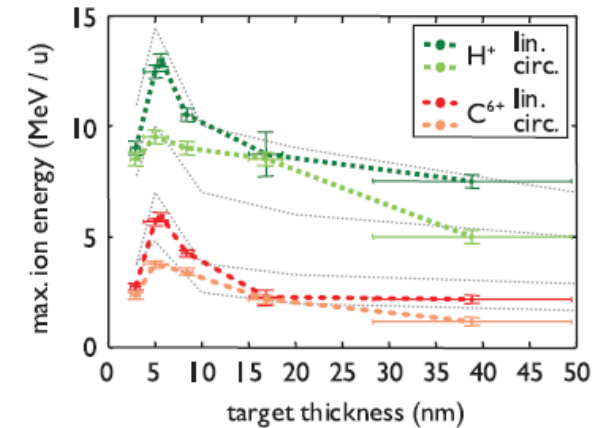
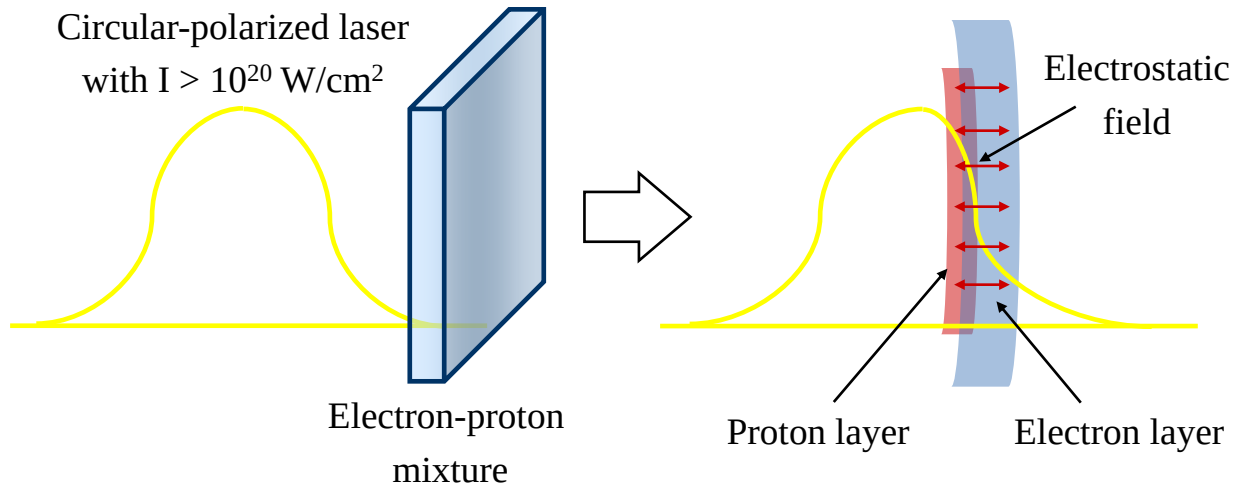
M. Kaluza, PRL **93**, 045003 (2004).



D. Neely, APL **89**, 021502(2006).

- ✓ Optimum thickness : several tens of nm - several μm , depending on the laser contrast, pulse duration, and intensity.

Radiation Pressure Acceleration (RPA) and Optimum Thickness



A. Henig, PRL **103**, 245003 (2009).

- ✓ Laser pulse pushes electrons forward and forms a high-density layer. A strong charge separation force accelerates ions as a thin layer.
- ✓ **Ultrathin targets with nm-scale thickness** are necessary to balance the radiation pressure with the restoring force given by the charge-separation field.

$$\text{Normalized areal density : } \sigma = \frac{n_e d}{n_c \lambda}$$

$$\text{Optimal RPA condition : } a_0 \approx \pi \sigma$$

$$\lambda = 0.8 \mu\text{m}, I = 5 \times 10^{20} \text{ W/cm}^2 \quad (a_0 = 10.8 \text{ for c-pol. laser})$$

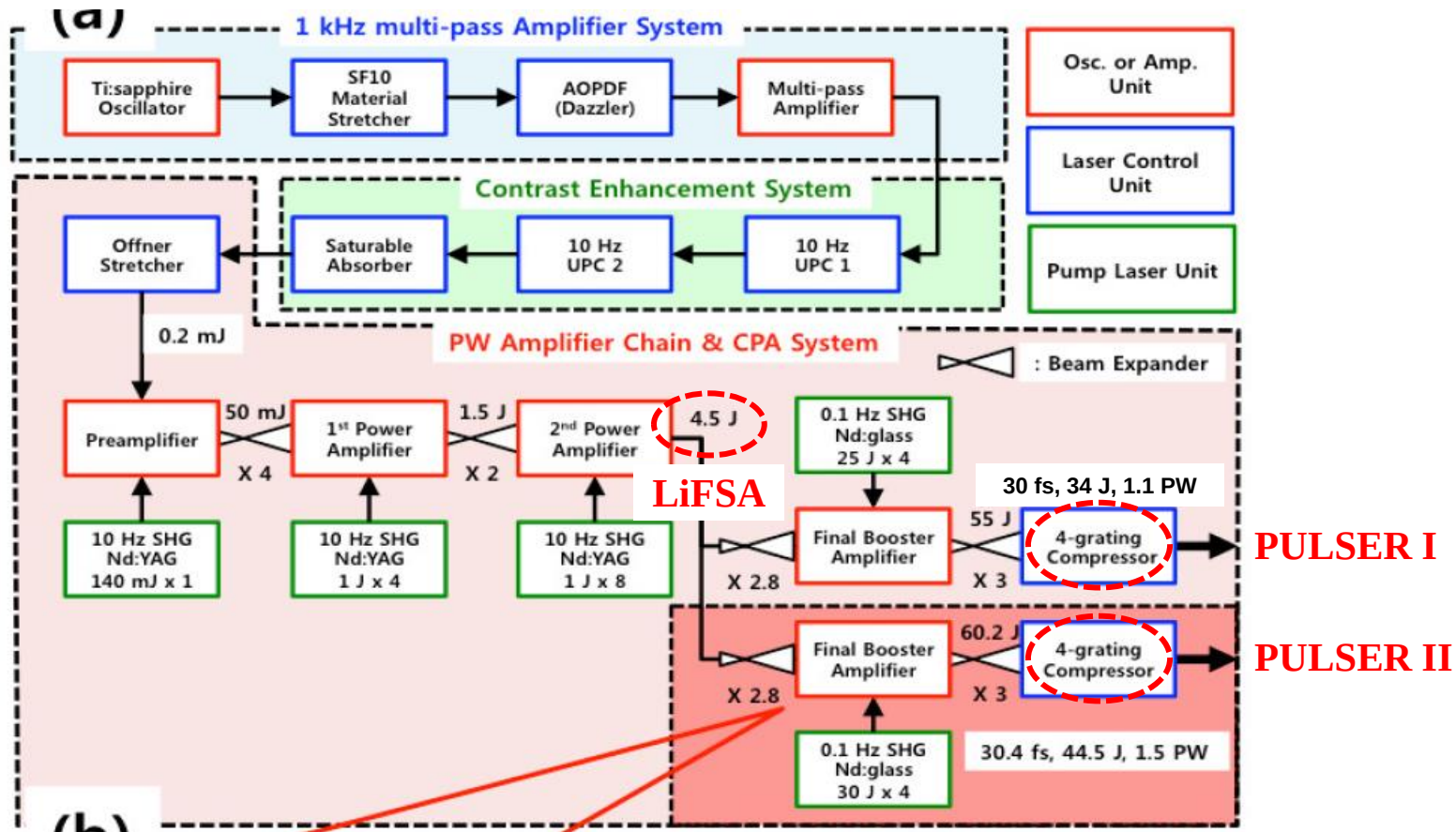
$$n_e = 200 n_c \rightarrow d = 14 \text{ nm}$$



Ti:Sapphire Laser Systems : LiFSA, PULSER

LiFSA (100 TW : Light source for Femto Science and Applications)

PULSER (1 PW : Petawatt Ultrashort Laser Source for Extr^em^e science Research)



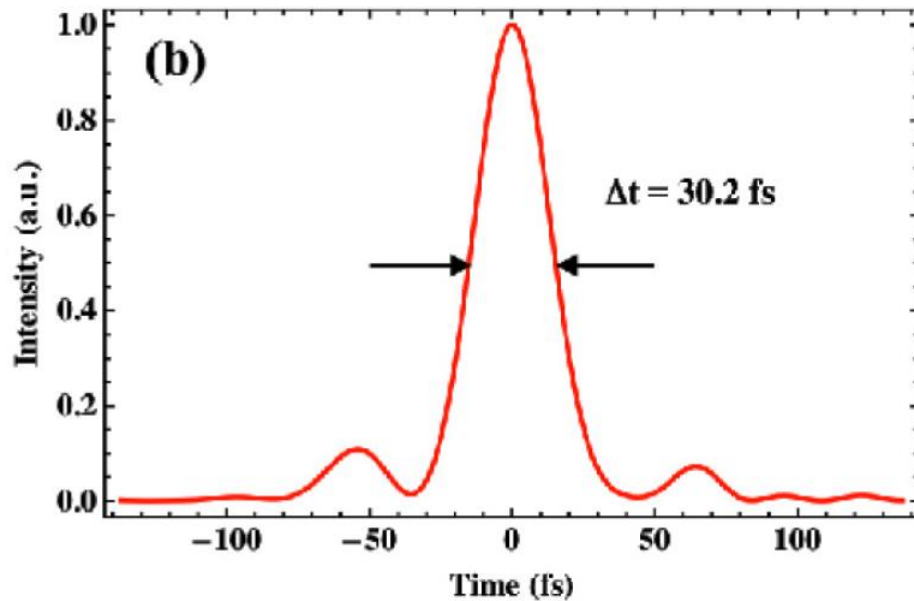
T. J. Yu *et al.*, Opt. Express **20**, 10807 (2012) ; J. H. Sung *et al.*, Opt. Lett. **35**, 3021 (2010).



Temporal Pulse Profile and Contrast Ratio of PULSER II

Spectral bandwidth : 46 nm (FWHM)

Pulse duration : 30.2 ± 1.8 fs for 30 pulses

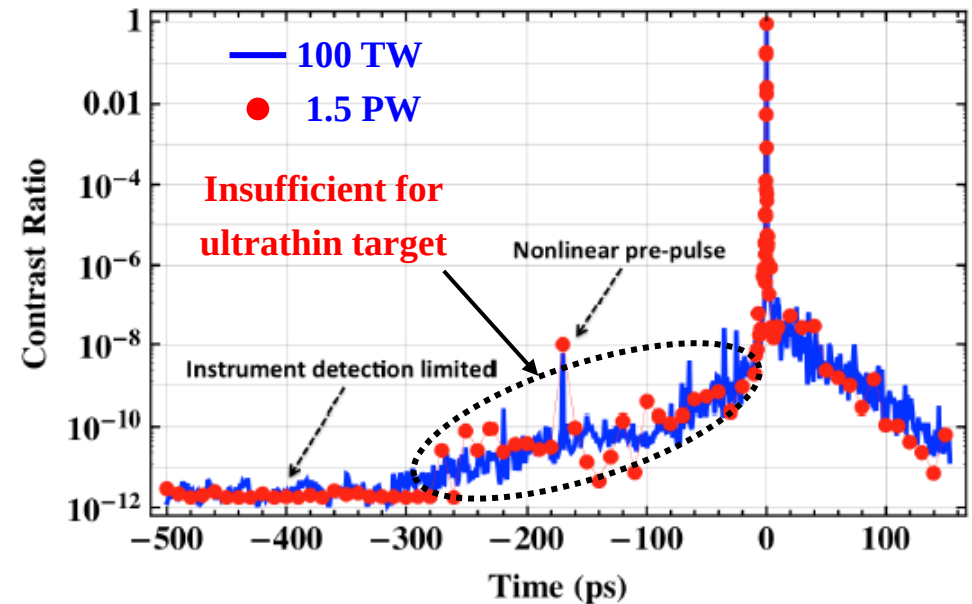


Pulse width after compressor

44.5 J, 30.2 fs $\rightarrow$ 1.5 PW

2.3×10^{-12} at -500 ps

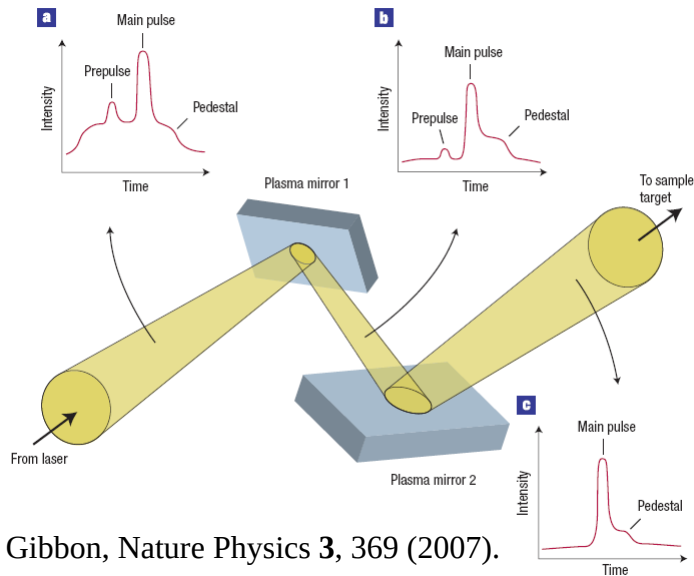
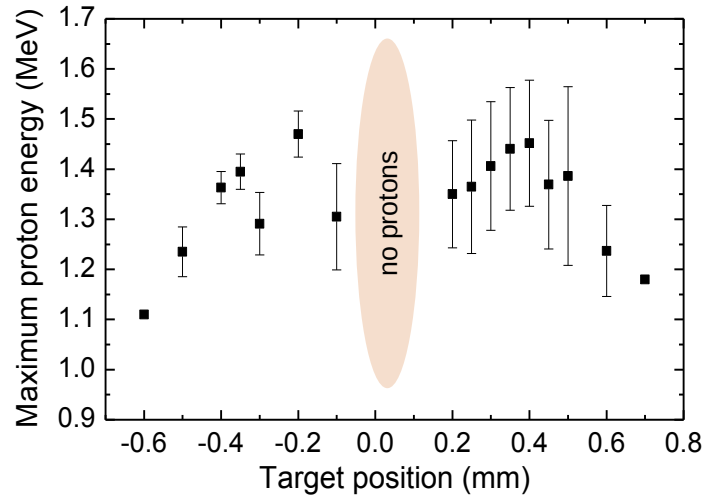
4.8×10^{-10} at -50 ps



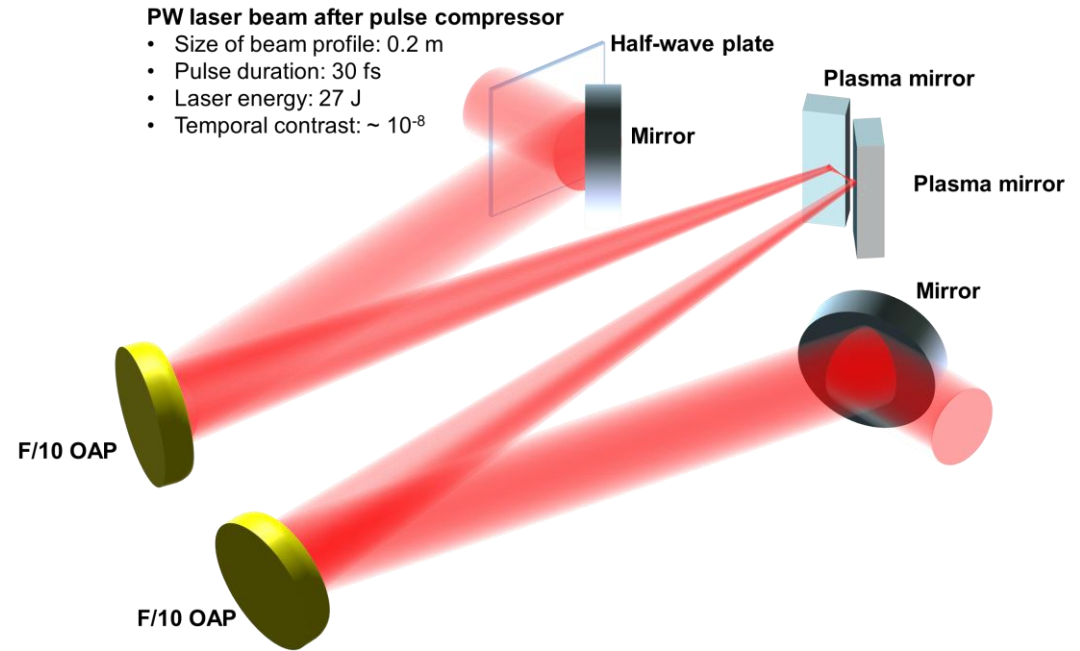
Contrast ratio of 1.5 PW and 100 TW laser pulses
measured using a third-order autocorrelation



Contrast Enhancement Needed with Plasma Mirror



P. Gibbon, Nature Physics 3, 369 (2007).

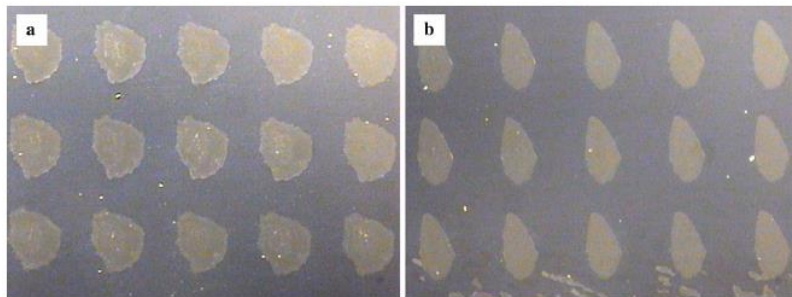
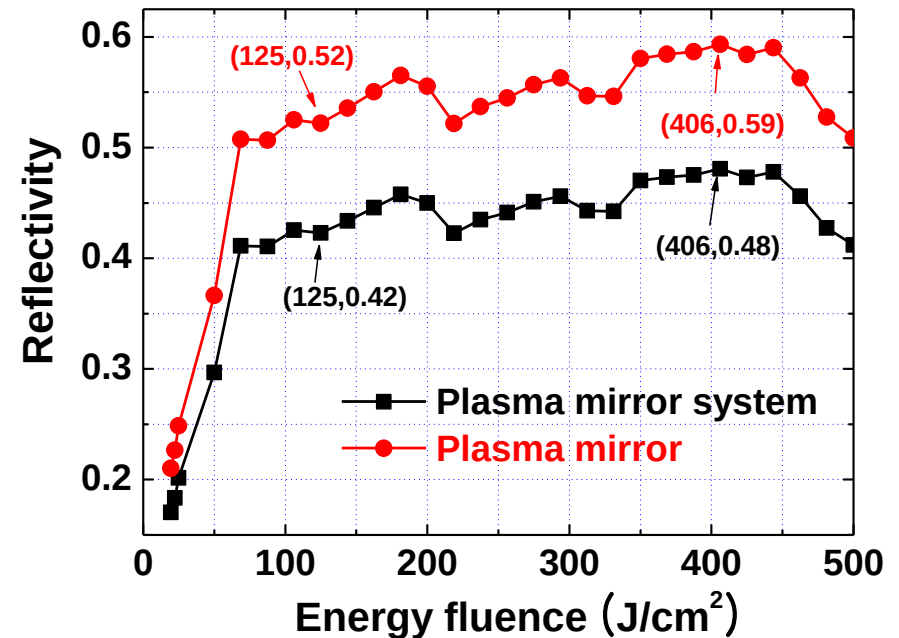
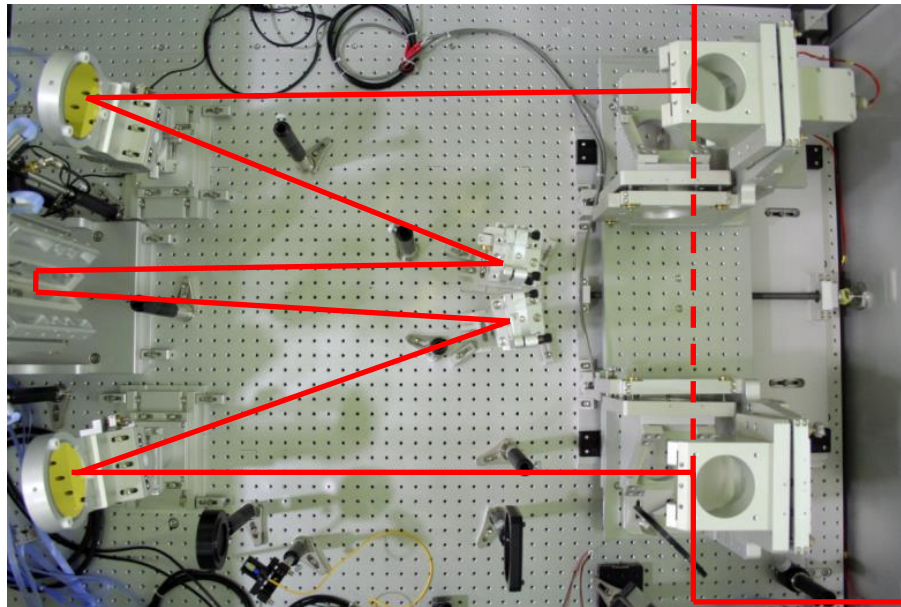


Contrast enhancement with one plasma mirror : ~ 100
 Double plasma mirrors provide **10,000 times** enhancement.



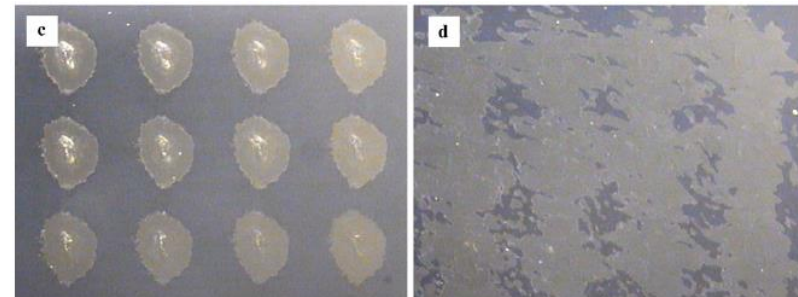
Double Plasma Mirror (DPM) System for 100 TW Laser Pulse

Large area DPM and precise pre-alignment allows **repetitive operation**.



First PM at 90 J/cm²

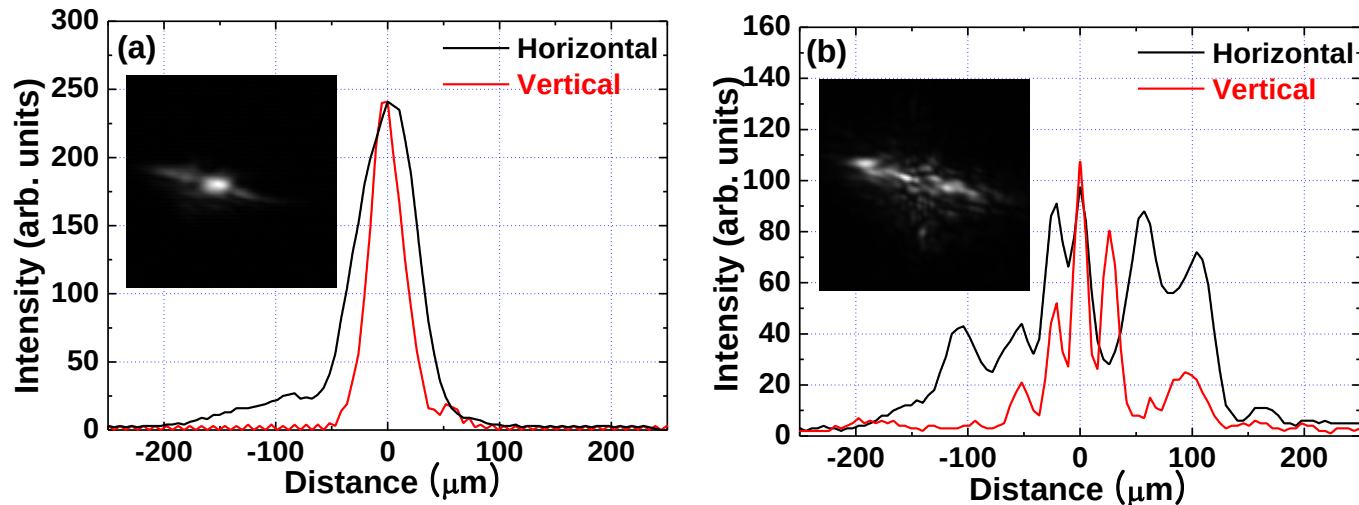
Second PM at 90 J/cm²



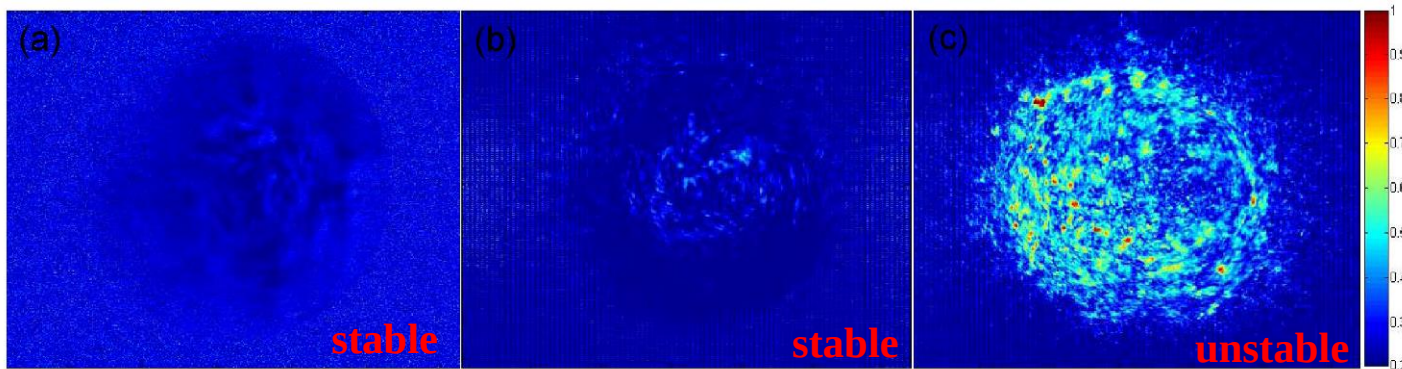
First PM at 290 J/cm²

Second PM at 290 J/cm²

Spatial Characteristics of Laser Beam Profile from DPM



- **Spatial beam profile of the focused laser** after DPM system for the energy fluence of (a) 90 J/cm^2 and (b) 290 J/cm^2 . The insets show the focused image for these energy fluencies respectively

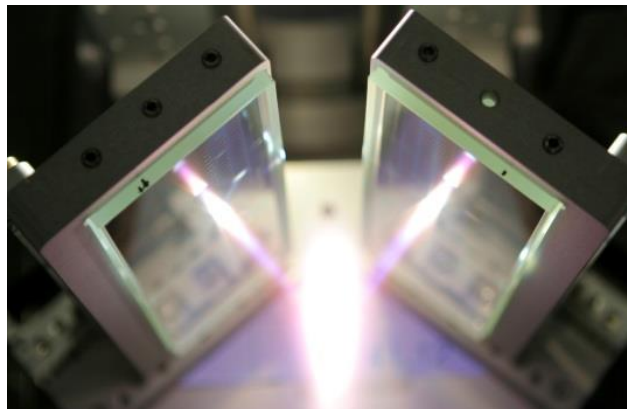
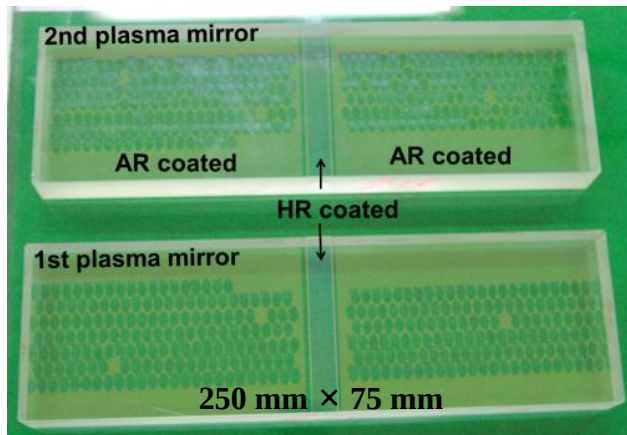


- **2-dimensional Normalized Standard Deviation** distribution of near field for 15 laser shots with and without DPM. (a) without DPM, (b) for 90 J/cm^2 with DPM, (c) for 290 J/cm^2 with DPM.

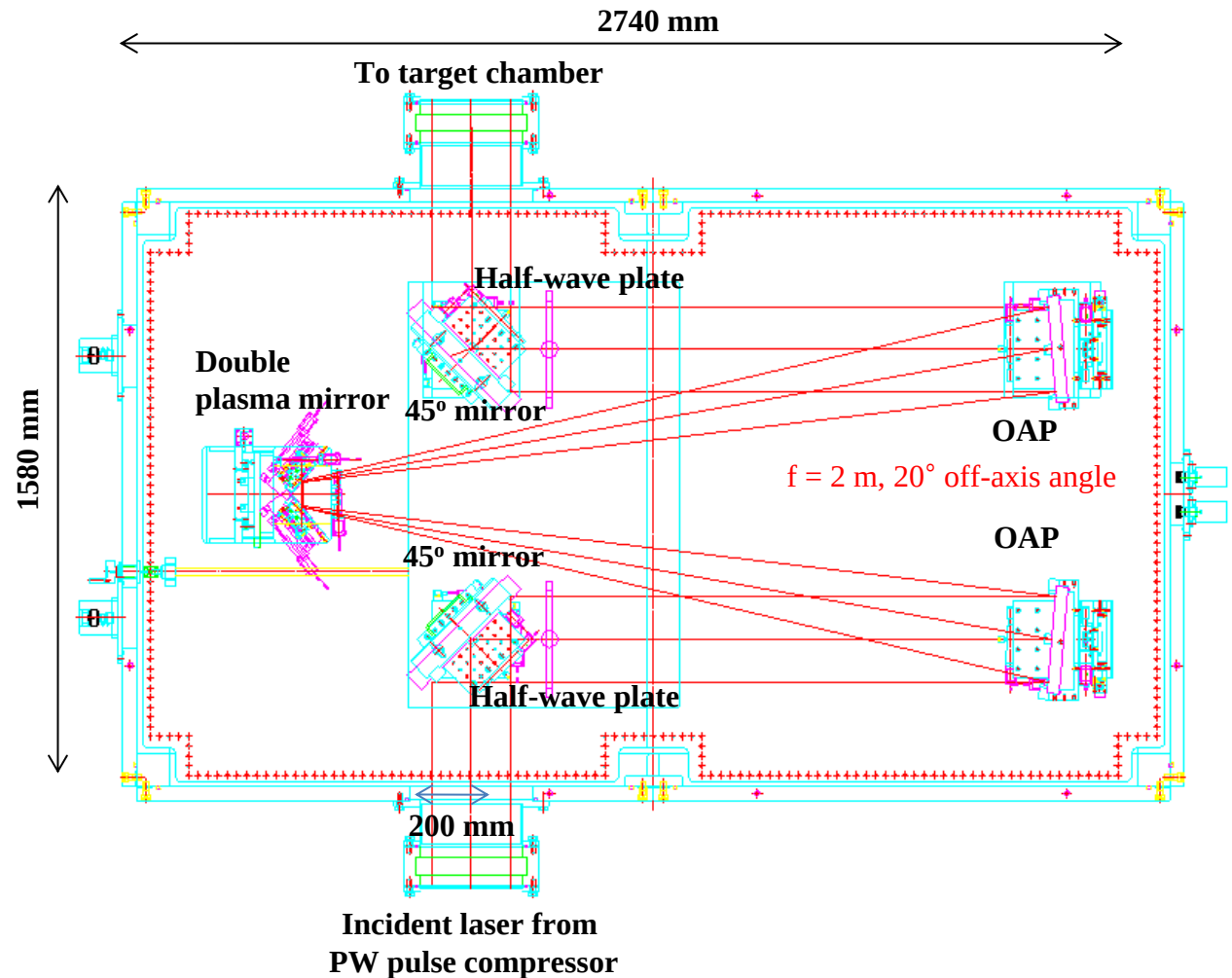


Double Plasma Mirror System for PW Laser Pulse

Repetitive operation is possible by large area DPM and precise pre-alignemnt.

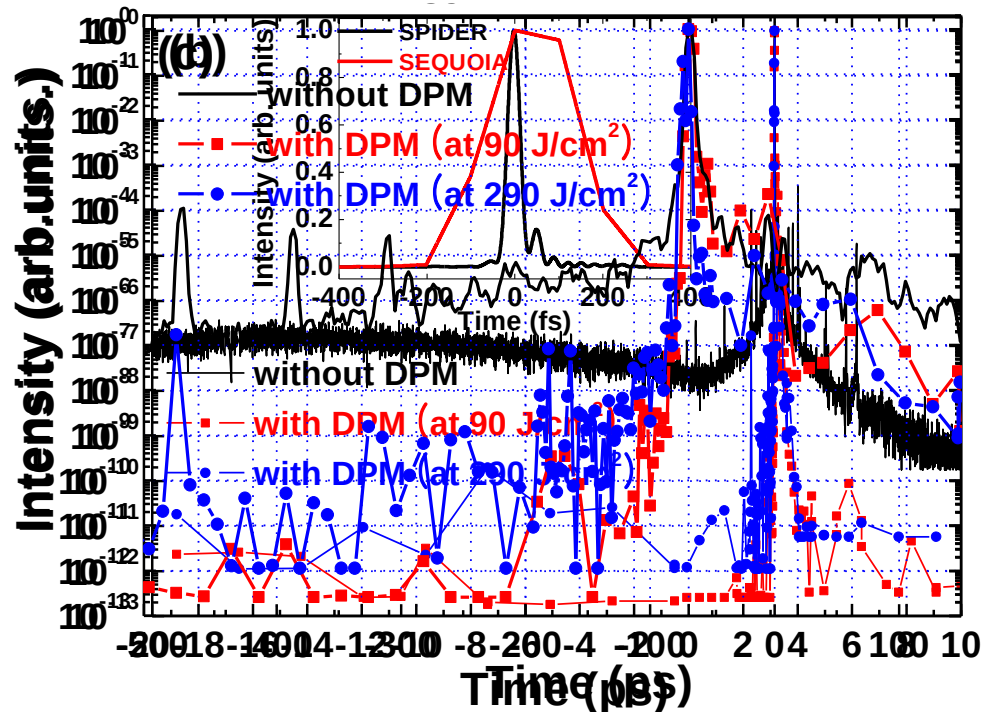


~350 shots available for ~100 J/cm²

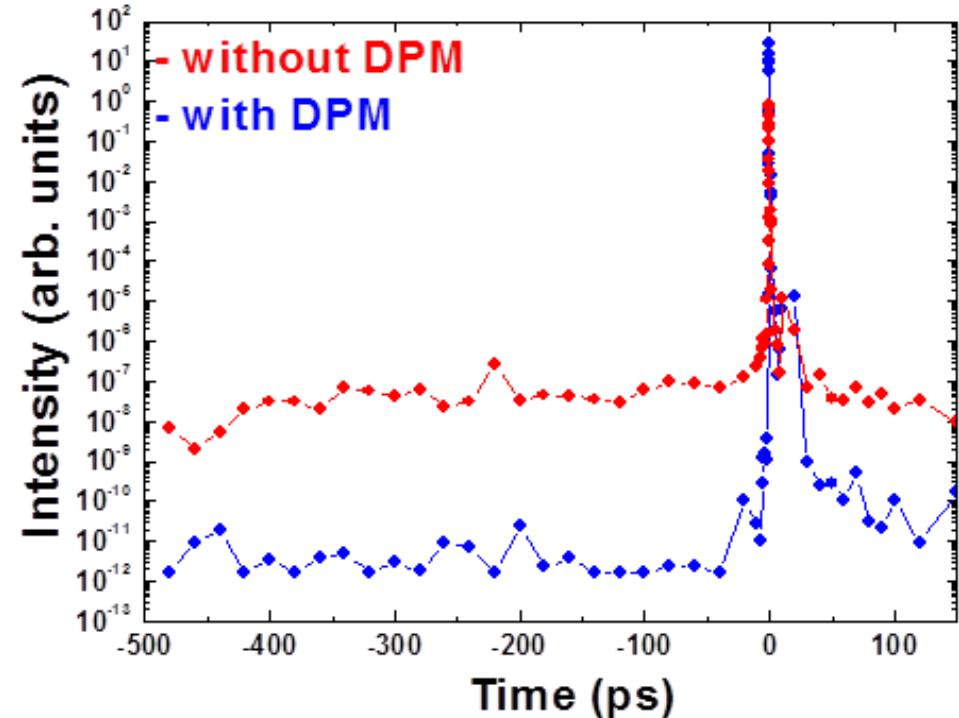


Temporal Contrast Ratio after PW Double Plasma Mirrors

100 TW DPM



PW DPM

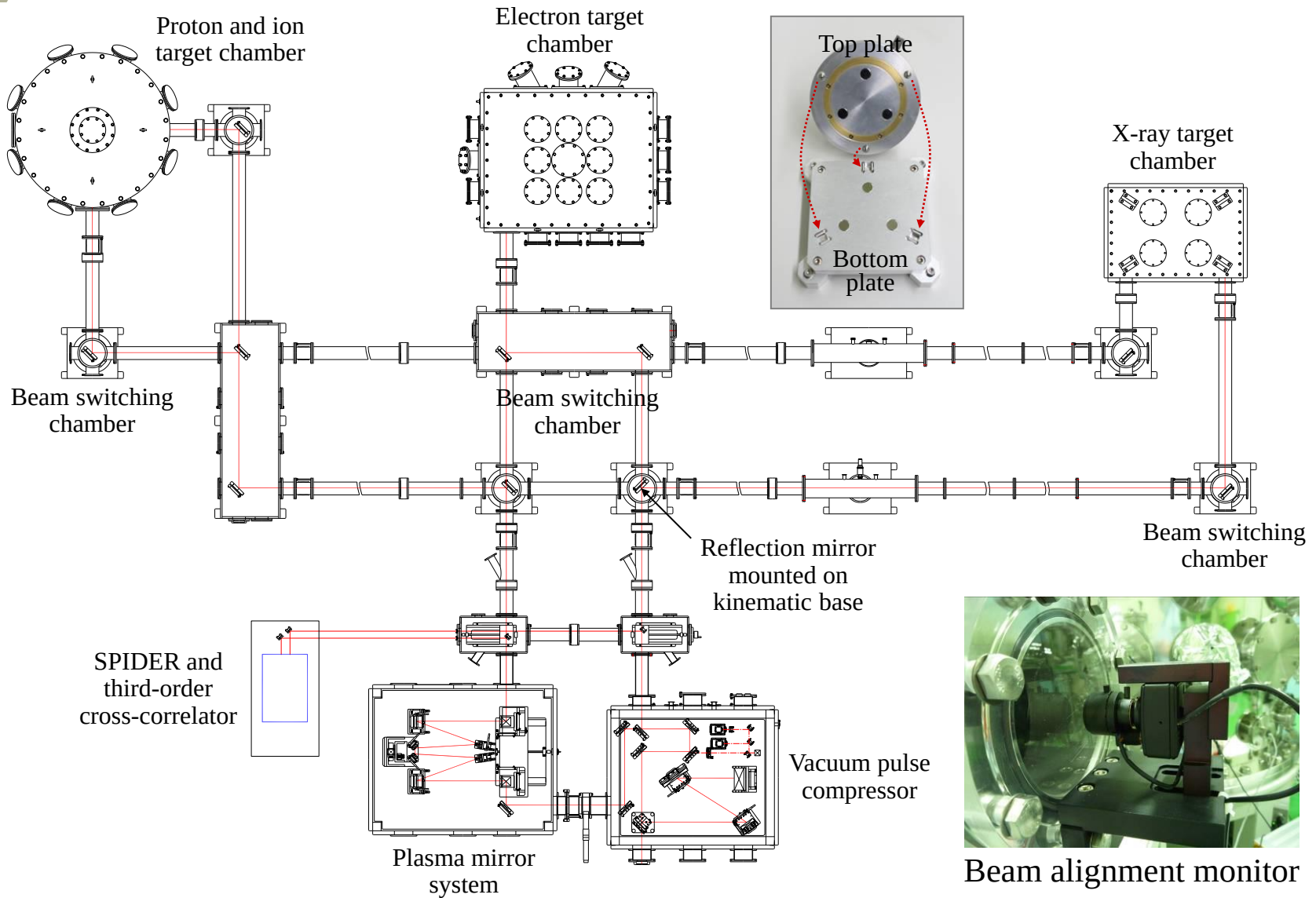


Advantages when using a plasma mirror

- Contrast enhancement : $\sim 10^4$
- $< 3 \times 10^{-11}$ up to 6 ps before the main pulse

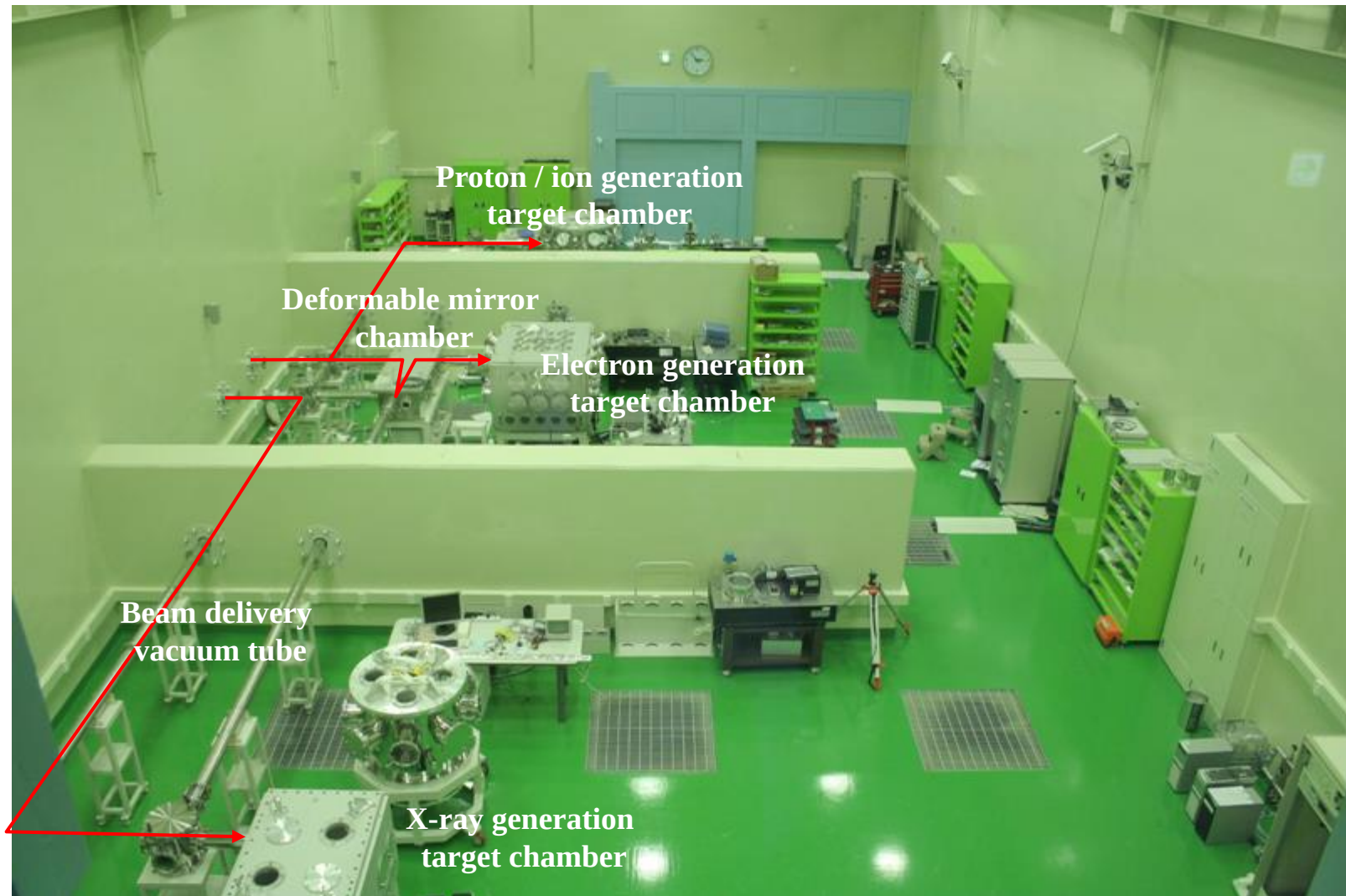
But, the overall reflectivity is only about 40%.

100 TW Laser Beam Delivery and Target Chamber System



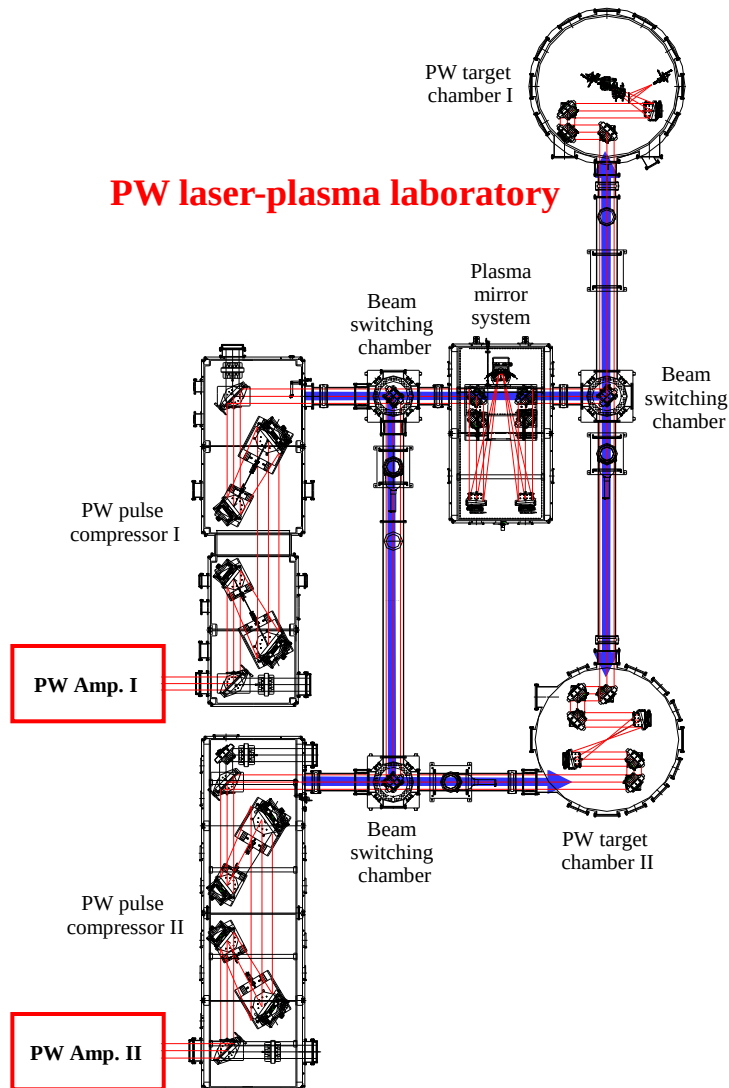


Three Interaction Target Chambers Operated for 100 TW Laser Application





Two PW Target Chambers and Beam Delivery System

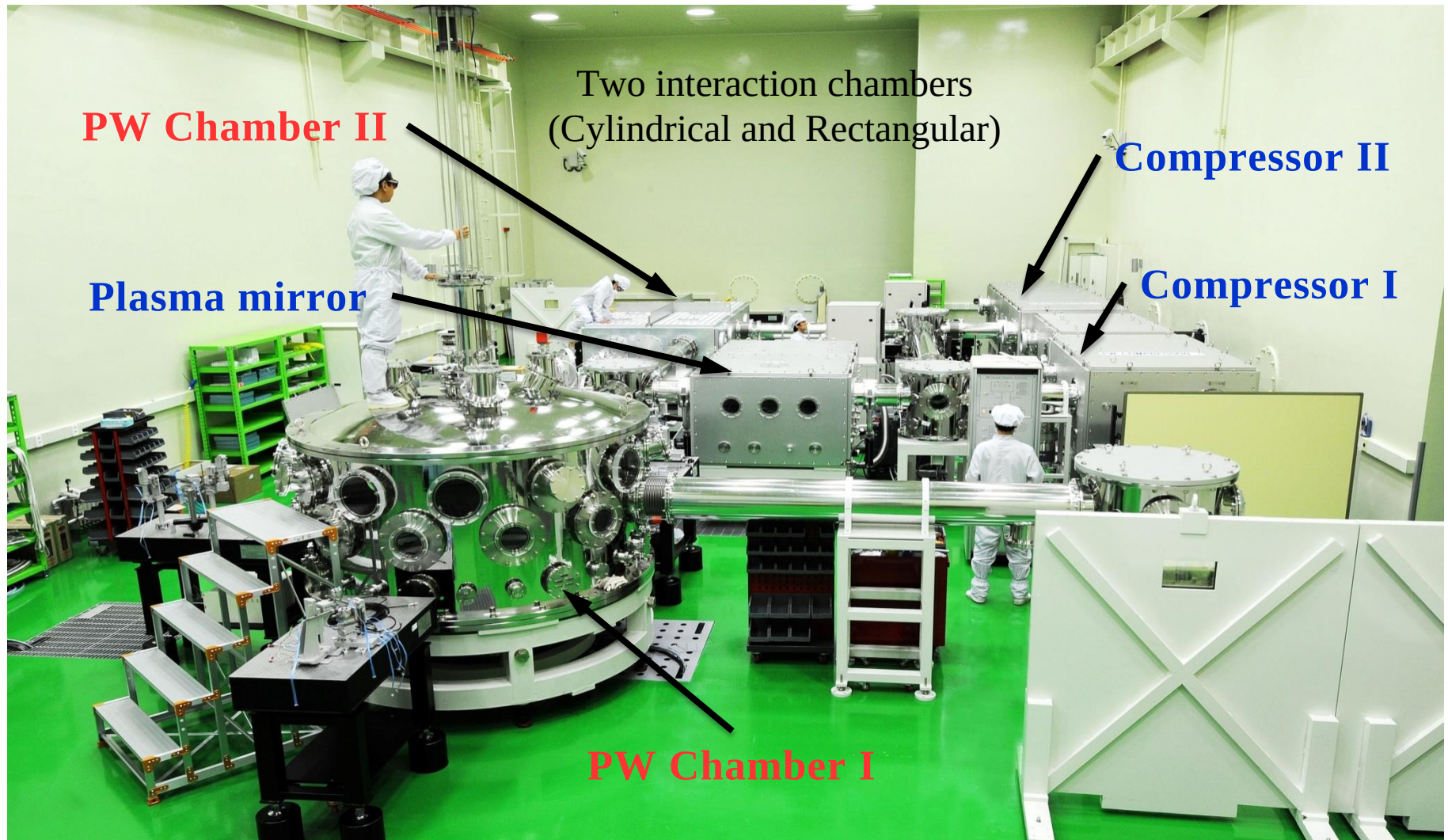


PW target chamber for solid target interaction

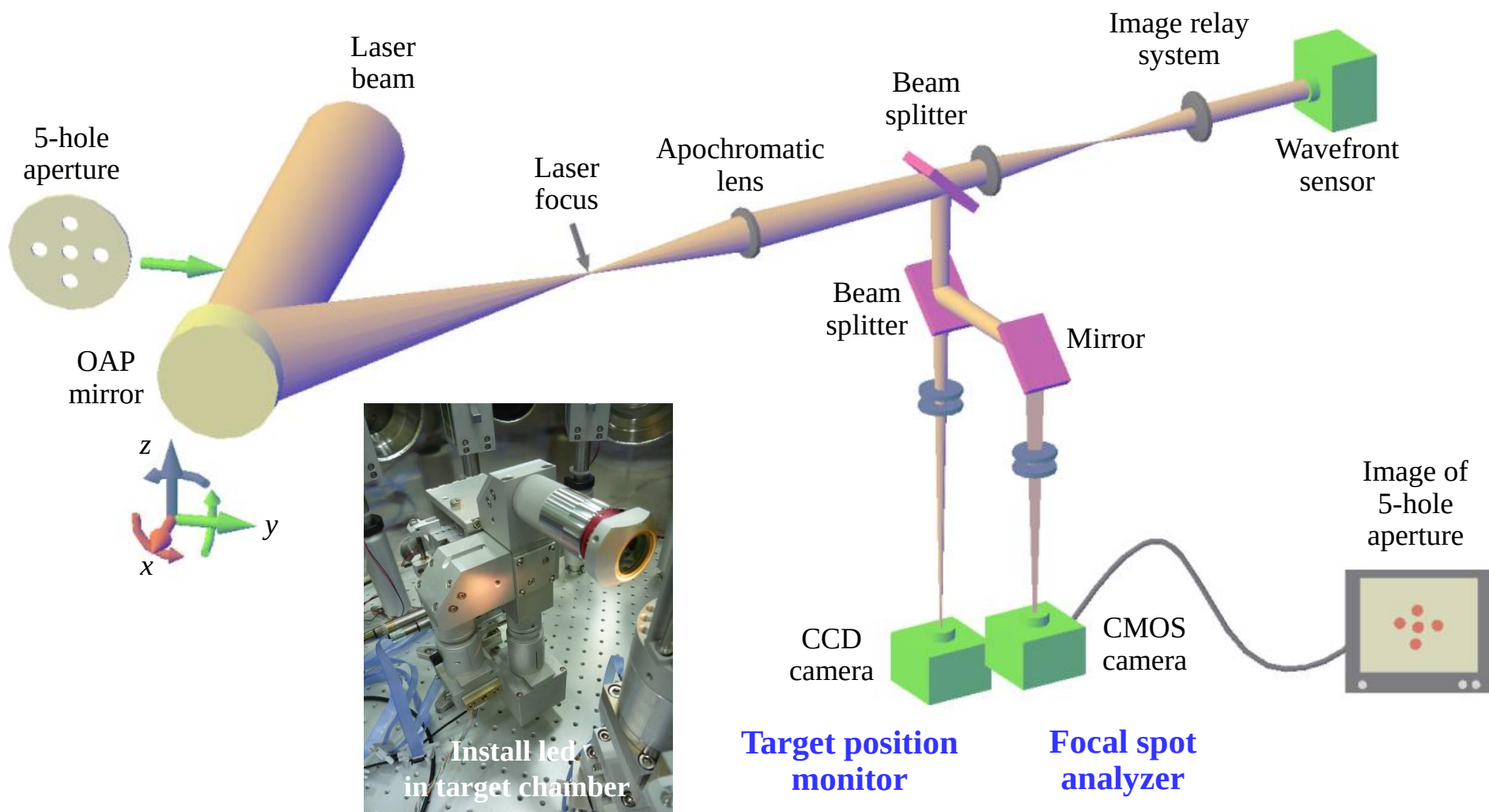
- Inner diameter : 2.2 m
- Depth : 1.07 m from bread board
- Volume : $\sim 4 \text{ m}^3$
- Material : Stainless steel + Aluminum
- Height of laser beam : 1.4 m
- PW laser beam size : $\sim 20 \text{ cm}$



Two Interaction Target Chambers Operated for PW Laser Application



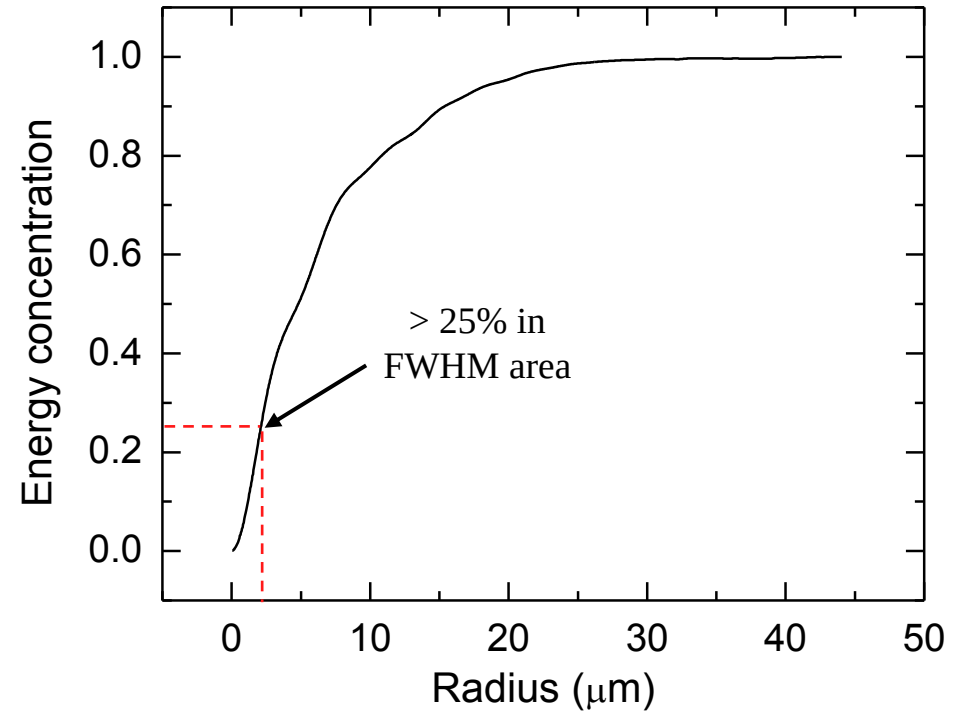
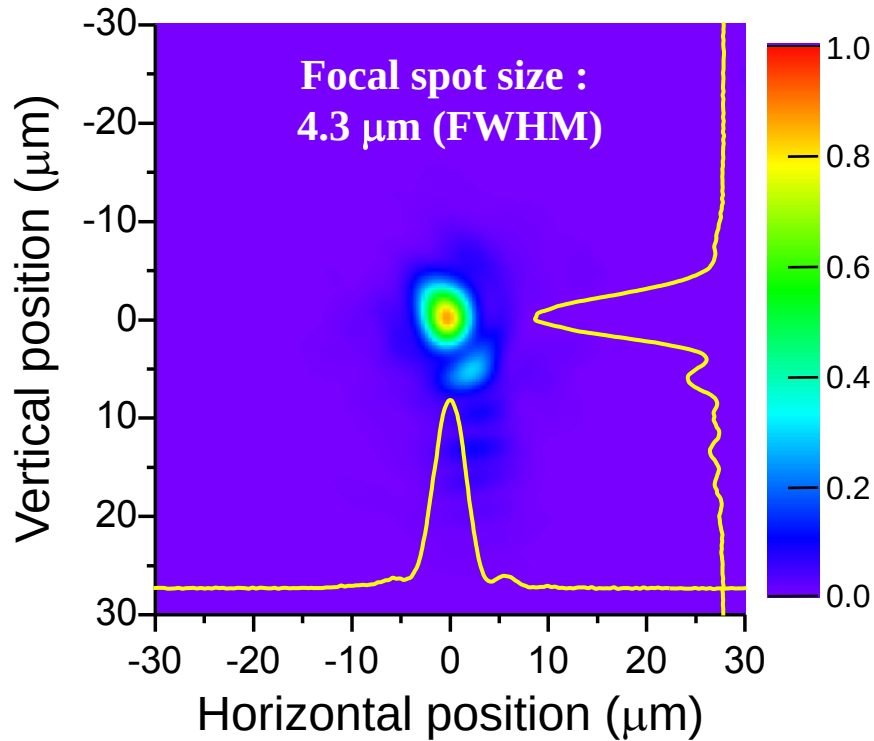
Alignment of Off-Axis Parabolic (OAP) Mirror and Target



I. W. Choi *et al.*, J. Korean Phys. Soc. **55**, 517 (2009).



Focal Spot Characterization and Focusing Intensity



Laser energy and pulse width on target : 8.5 J, 30 fs

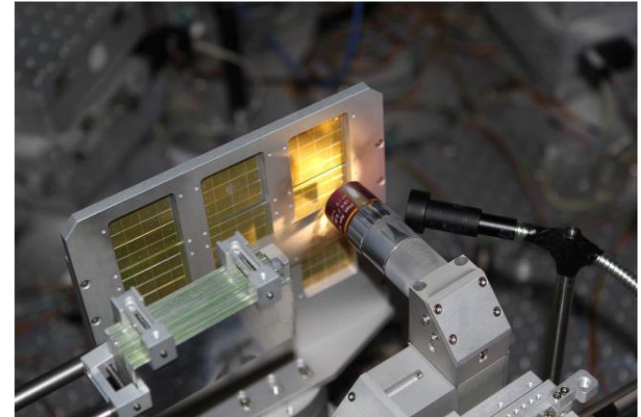
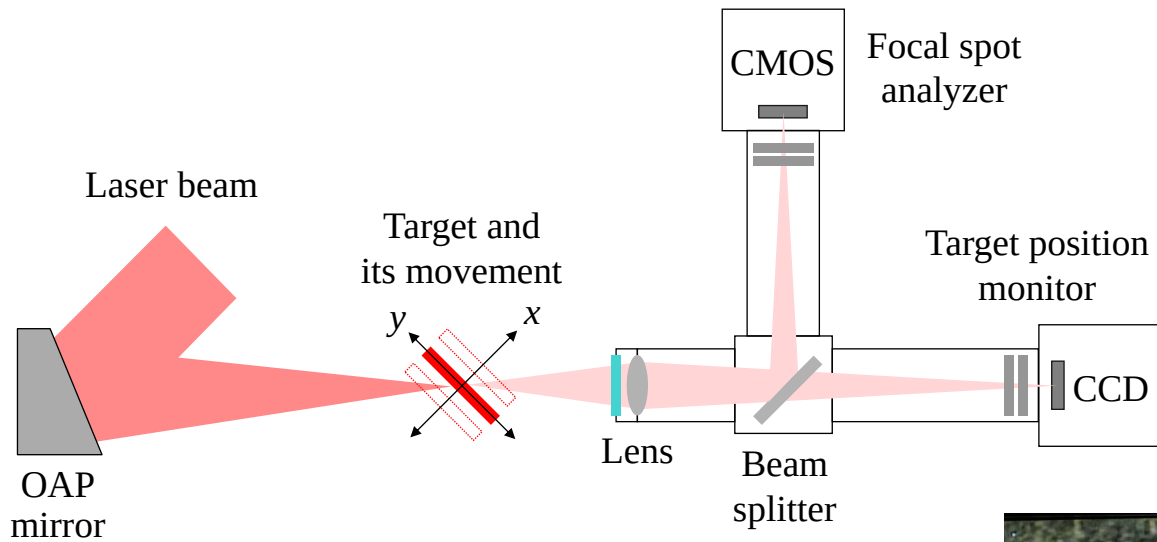
Focal spot size obtained with f/3 OAP : 4 μm

Energy concentration in FWHM area : > 25%

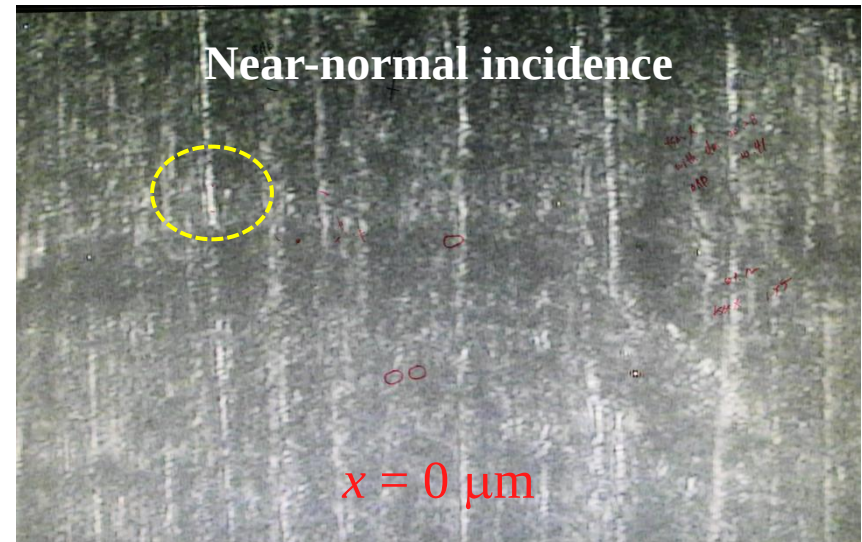
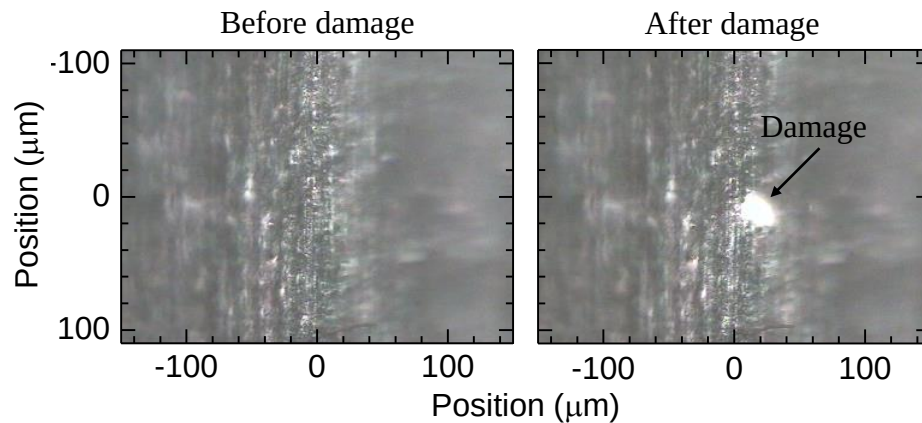
→ $7 \times 10^{20} \text{ W/cm}^2$ for PW laser + DPM



Accurate Target Alignment



45° incidence



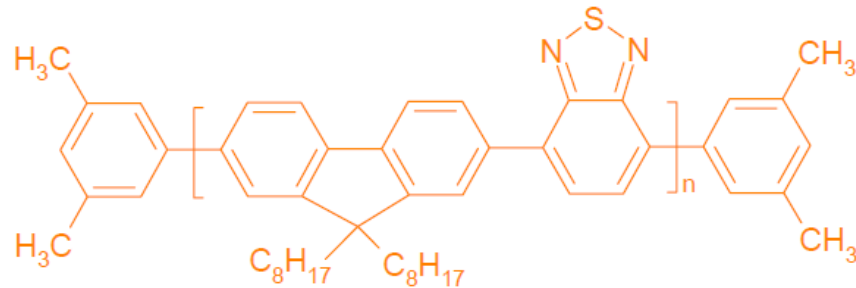
Much better accuracy than Rayleigh range $\sim 50 \mu\text{m}$



1. Commonly used targets : Al, Mylar, Si_3N_4 , Diamond-like carbon, etc.

2. Alternative ultrathin target proposed

- Conjugate polymer material : **F8BT**, poly(9,9-dioctylfluorene-co-benzothiadiazole)
 - Polyfluorene derivative used for in polymer LED, organic solar cell and transistor
 - Manufacture method : **spin coating** → **floating on water** → **transferring to a target frame**
 - Available thickness : 5-500 nm
 - Chemical formula : $(C_{35}H_{42}N_2S)_n$
- 
- The chemical structure diagram shows the repeat unit of the F8BT polymer. It consists of a fluorene ring substituted with two octyl groups (represented by H₃C and a wavy line) and a benzothiadiazole ring. The two rings are connected by a single bond, and the entire unit is enclosed in brackets with a subscript 'n'.

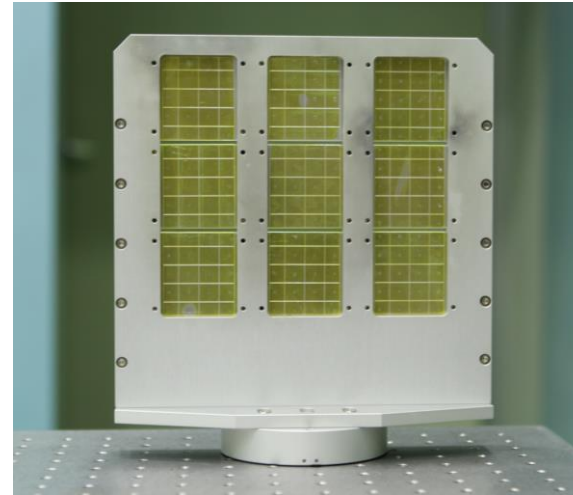
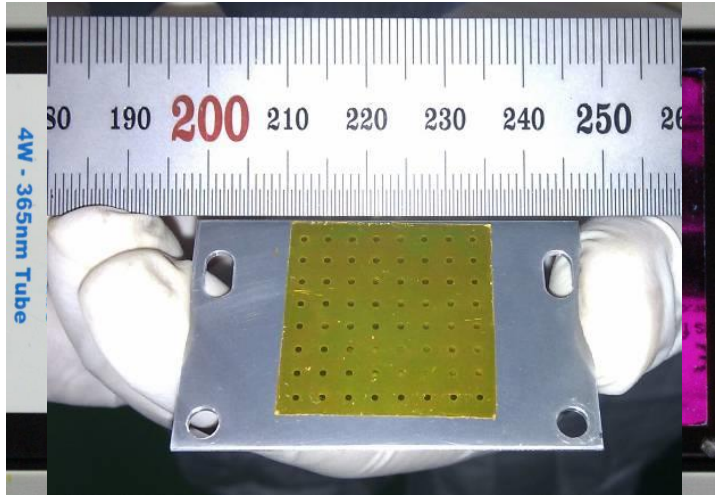


3. Advantages of the polymer target

- Easy manufacture, low material and production cost
- Low electron density of $\sim 200 \text{ n}_c$ for 800-nm wavelength laser
 - Realization of ultraintense laser-ultrathin target interaction using relatively low laser intensity, such as relativistic transparency, RPA, etc.



Ultrathin Free-standing Polymer Target



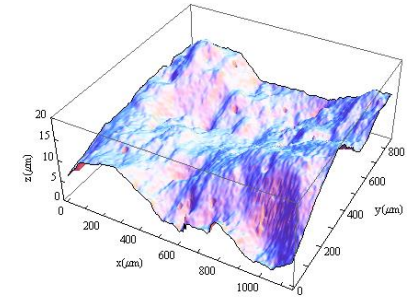
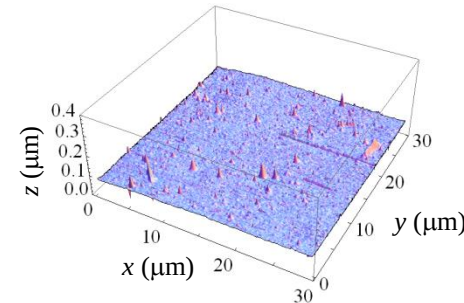
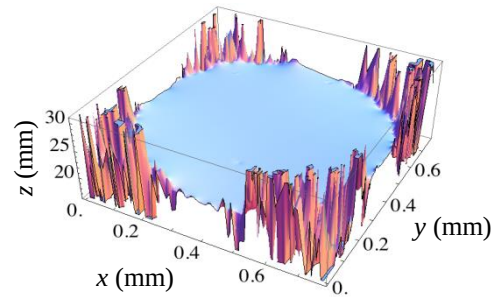
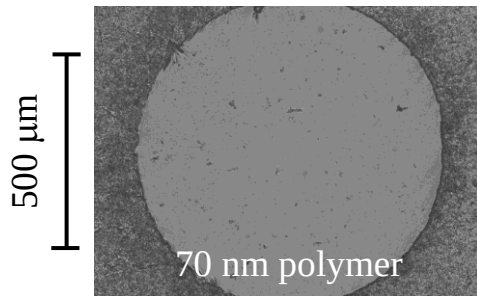
200-300 laser
shots possible
with one loading
in target chamber

Free-standing polymer
attached on target frame

Flatness of
100-nm thick polymer

Roughness of
100-nm thick polymer

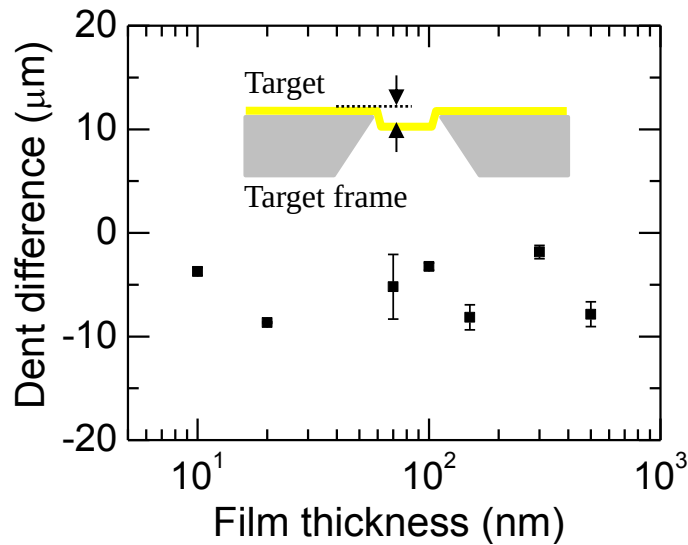
1.2- μm thick Al :
r.m.s roughness $\sim 1 \mu\text{m}$



I. W. Choi *et al.*, Appl. Phys. Lett. **99**, 181501 (2011).

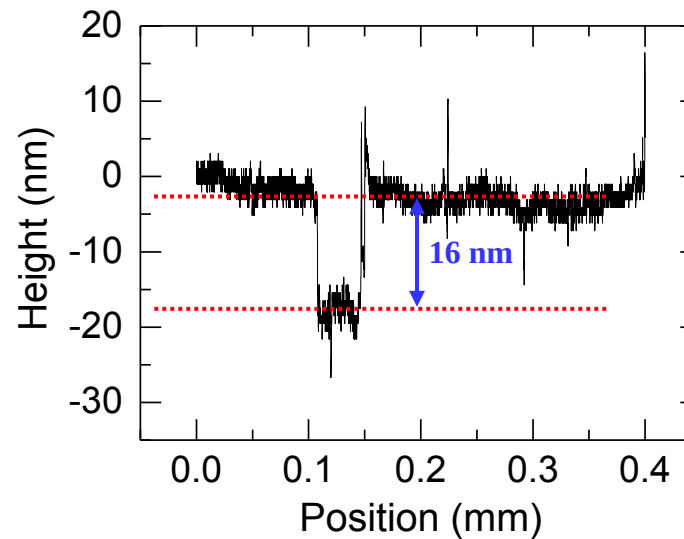
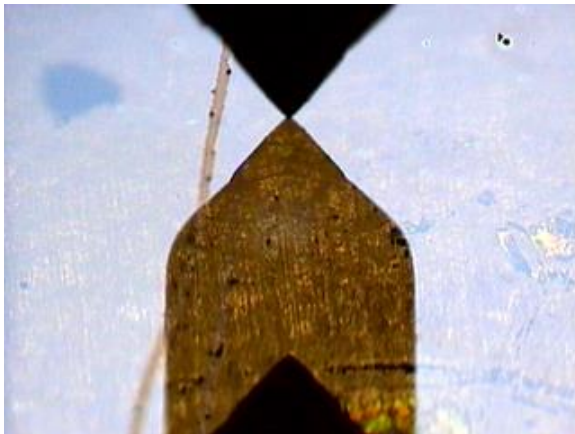
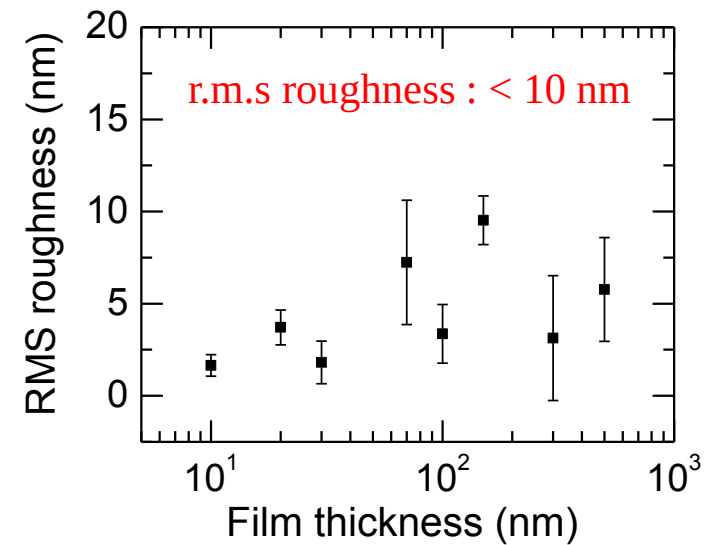


Characterization of Nanometer-Class Polymer Target



Raleigh range $\gg$
dent distance

→ Frame surface
alignment enough



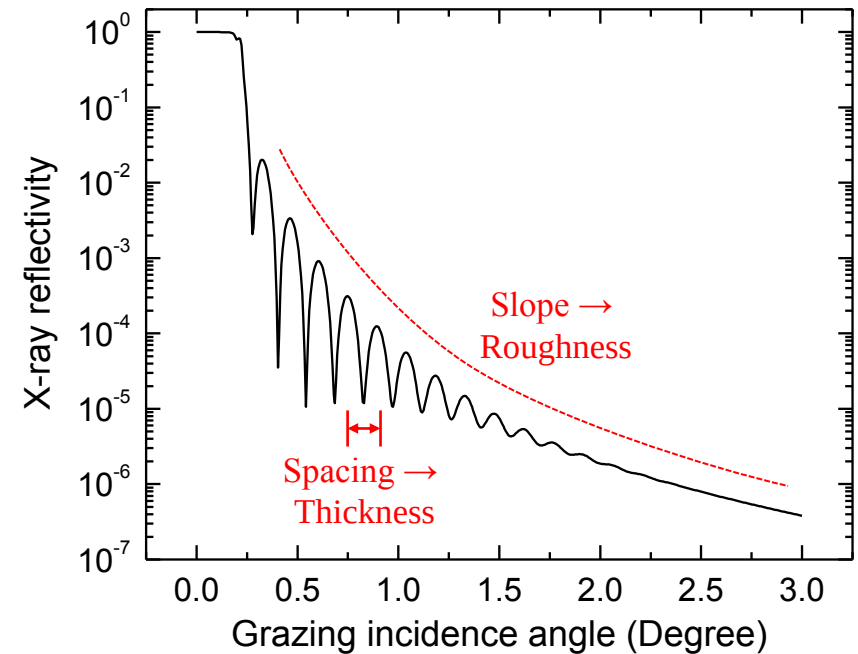
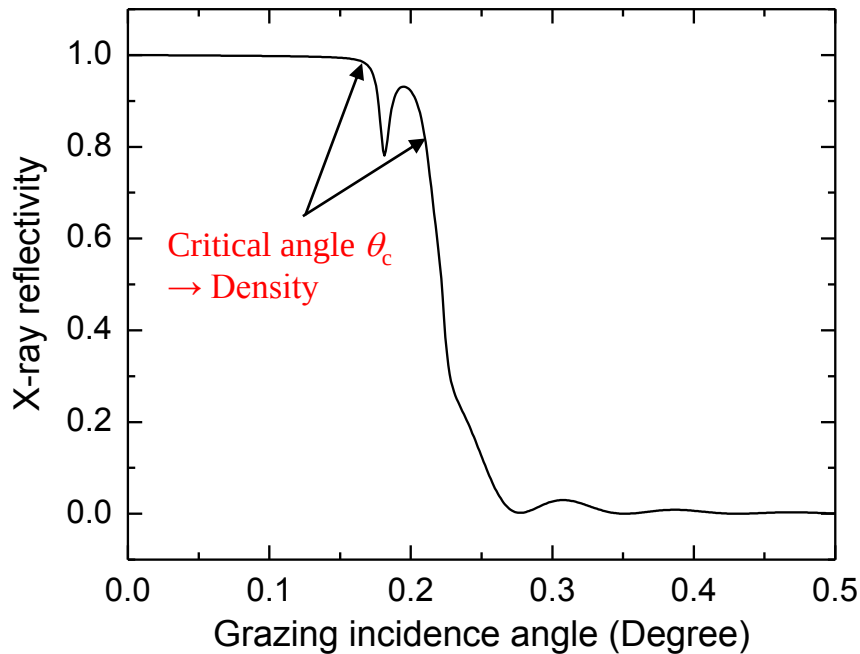
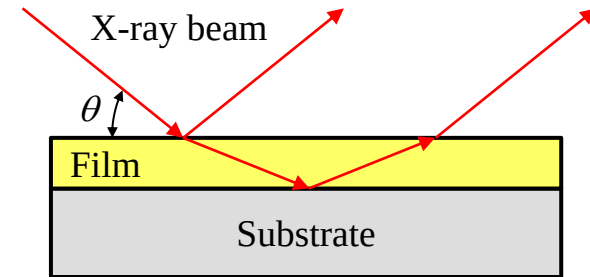
Alpha-step surface profiler
- Thickness measurement
range : $> \sim 20 \text{ nm}$

X-ray Reflectivity Measurement for Thickness and Density

X-ray reflectivity measurement

- Used for estimation of density, thickness, roughness
- Critical angle for total external reflection :

$$\cos \theta_c = \sqrt{1 - \omega_p^2 / \omega_0^2} \quad \theta_c \approx \omega_p / \omega_0 = \sqrt{n_e / n_c}$$



Thickness and Density of Nanometer-Class Polymer Target

X-ray reflectivity measurement

- Intensity maxima

$$2d \sqrt{\sin^2 \theta_m - \sin^2 \theta_c} = m\lambda$$

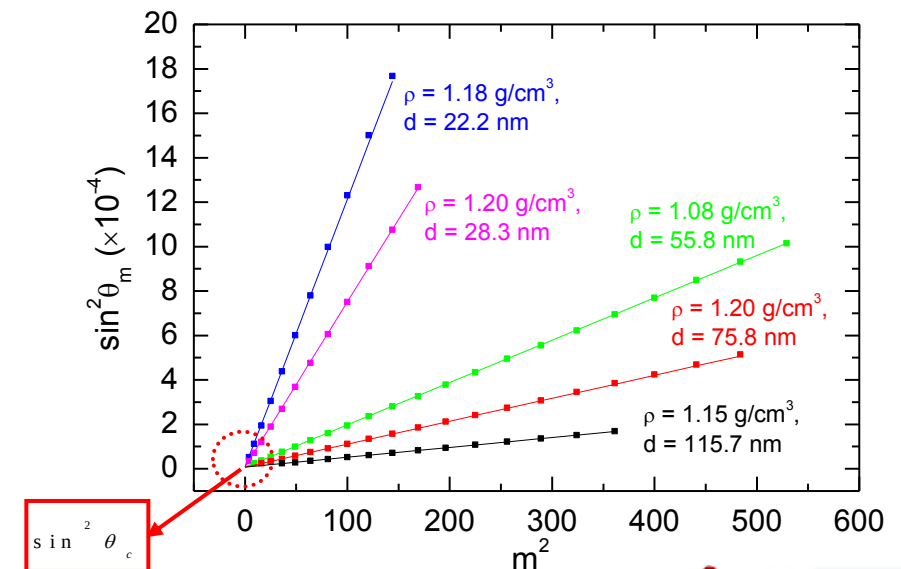
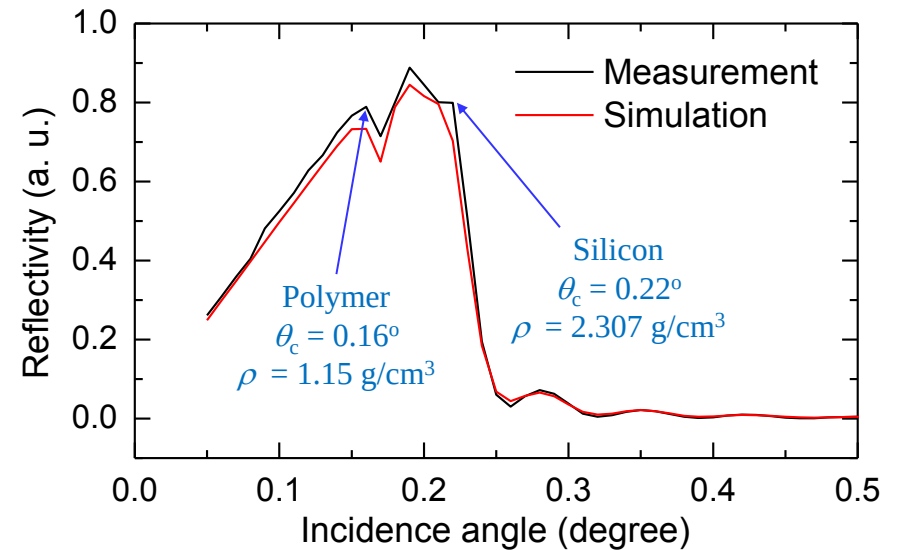
$$\sin^2 \theta_m = \sin^2 \theta_c + \left(\frac{\lambda}{2d} \right)^2 m^2$$

- Intercept with $m^2 = 0 \rightarrow$ critical angle θ_c
- Slope of the linear dependence $\rightarrow$ thickness d
- Thickness measurement range : $> \sim 1$ nm

X-ray photon energy : Cu K α 8.05 keV

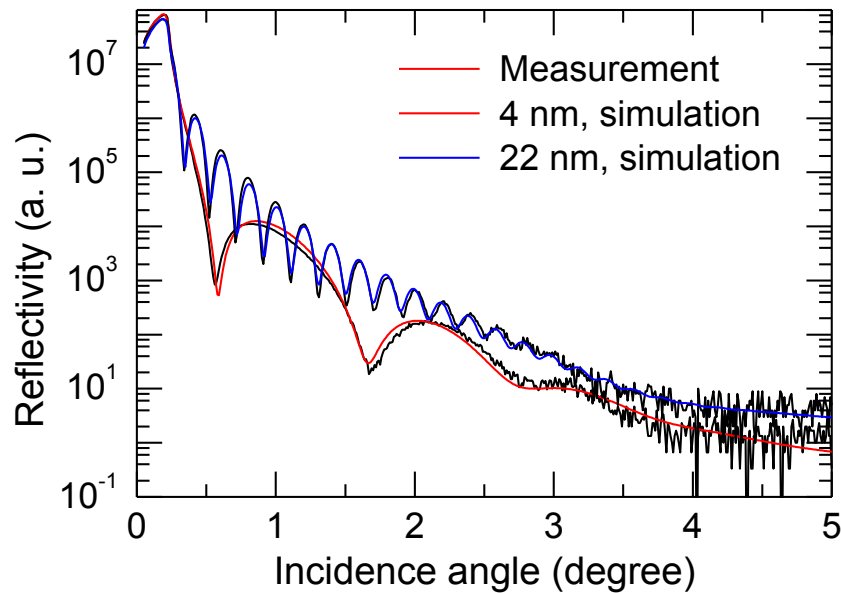
Conjugated polymer, F8BT

- Material density : 1.1-1.2 g/cm³
- Electron density : $3.5\text{-}3.8 \times 10^{23}/\text{cm}^3$ for C⁶⁺, H⁺, N⁷⁺, S¹⁰⁺
- $\rightarrow$ **200-220 n_c for 800-nm laser wavelength**

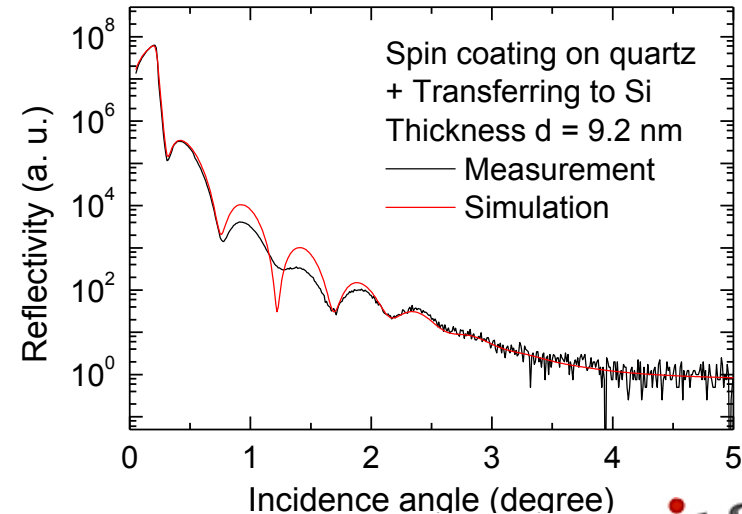
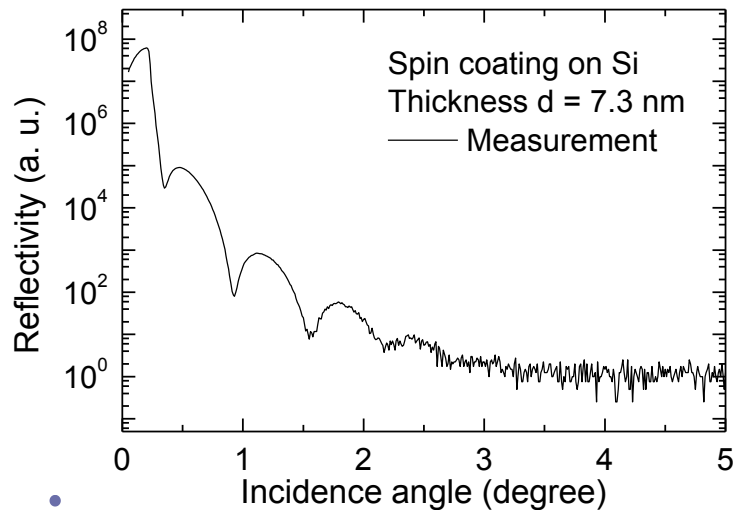




Thickness Possible Down to ~4 nm



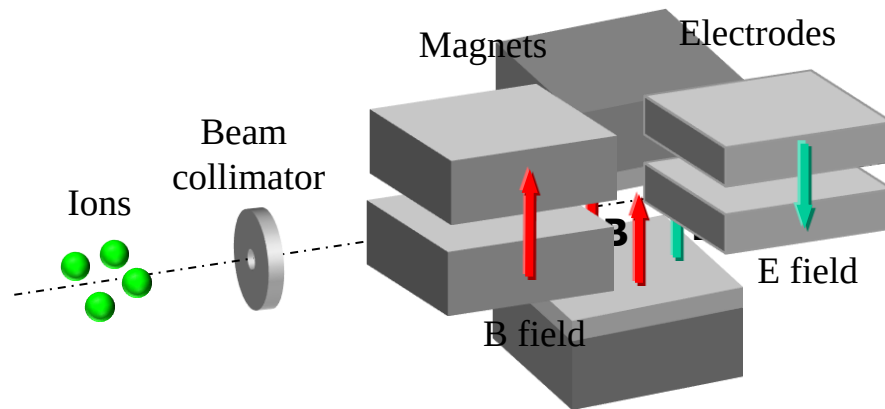
- Available thickness : < 5 nm
- Thickness reproducibility : $\sim 90\%$
- Thickness uniformity over the surface : $\sim 90\%$



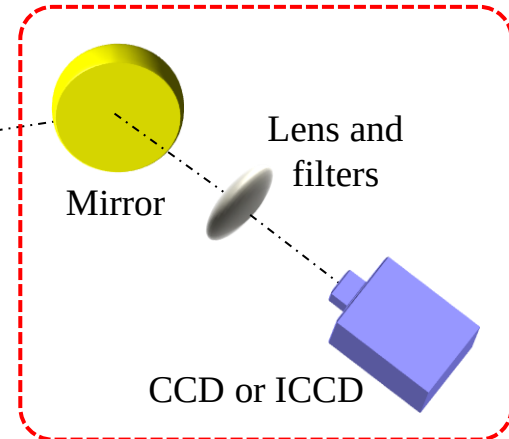


Thomson Parabola Spectrometer (TPS)

Thomson parabola spectrometer

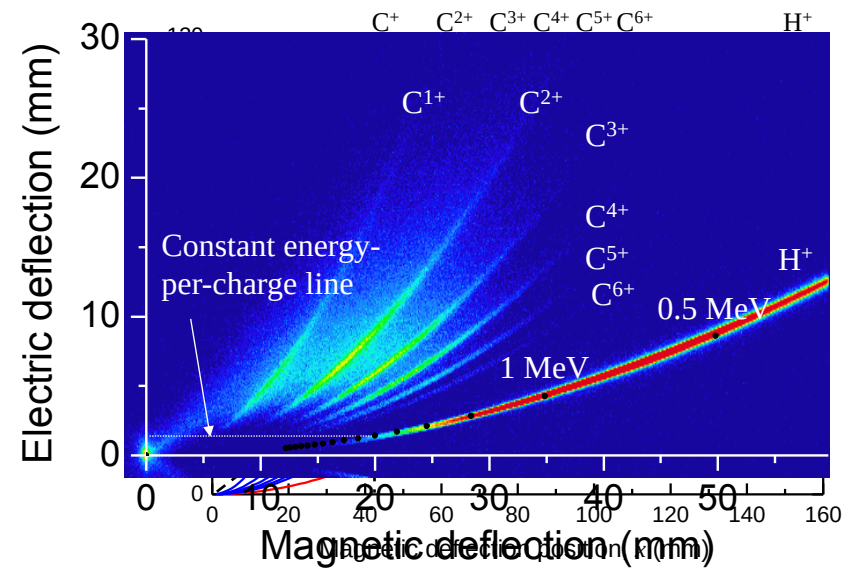


Optional depending on detector



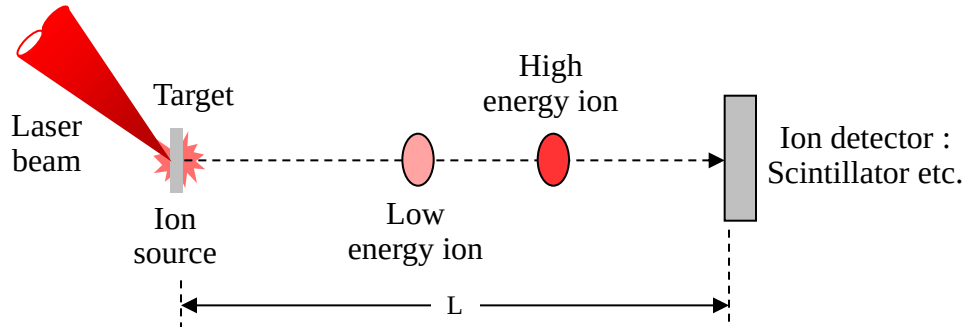
$$x = \frac{q B L_i}{m v} \left(\frac{L_i}{2} + L_f \right), \quad y = \frac{q E L_i}{m v^2} \left(\frac{L_i}{2} + L_f \right)$$

$$y = \frac{m}{q B^2 L_i (L_i + 2 L_f)} x^2, \quad y = \frac{E}{B v} x$$

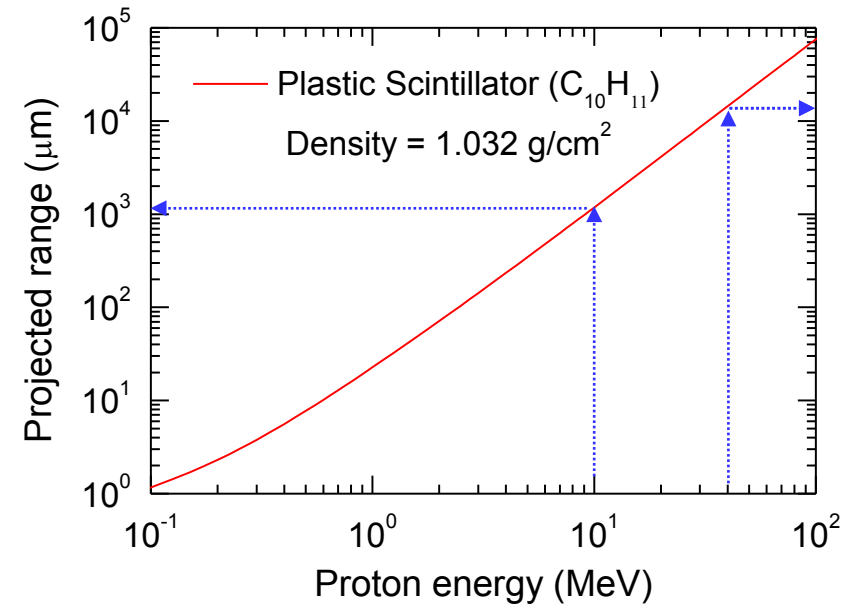
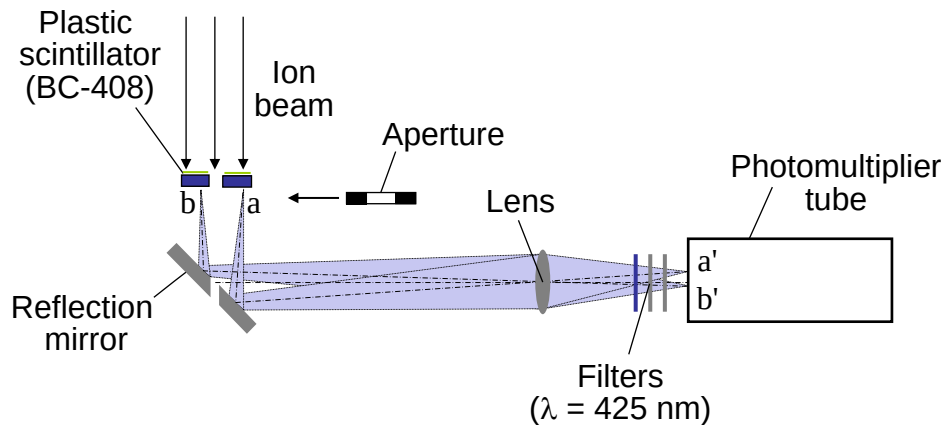




Time-Of-Flight (TOF) Spectrometer

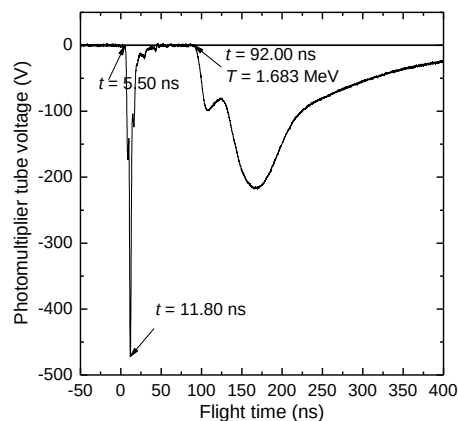
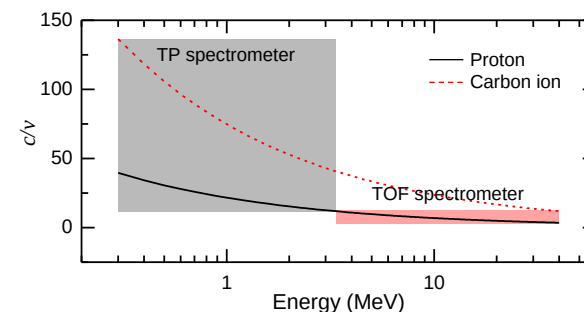
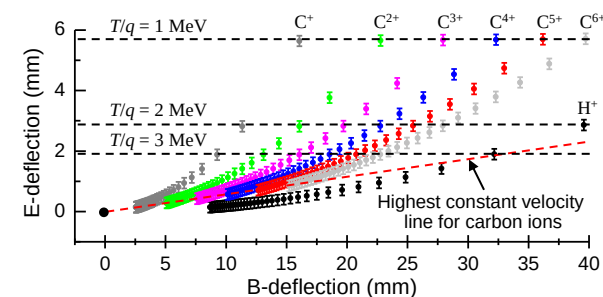
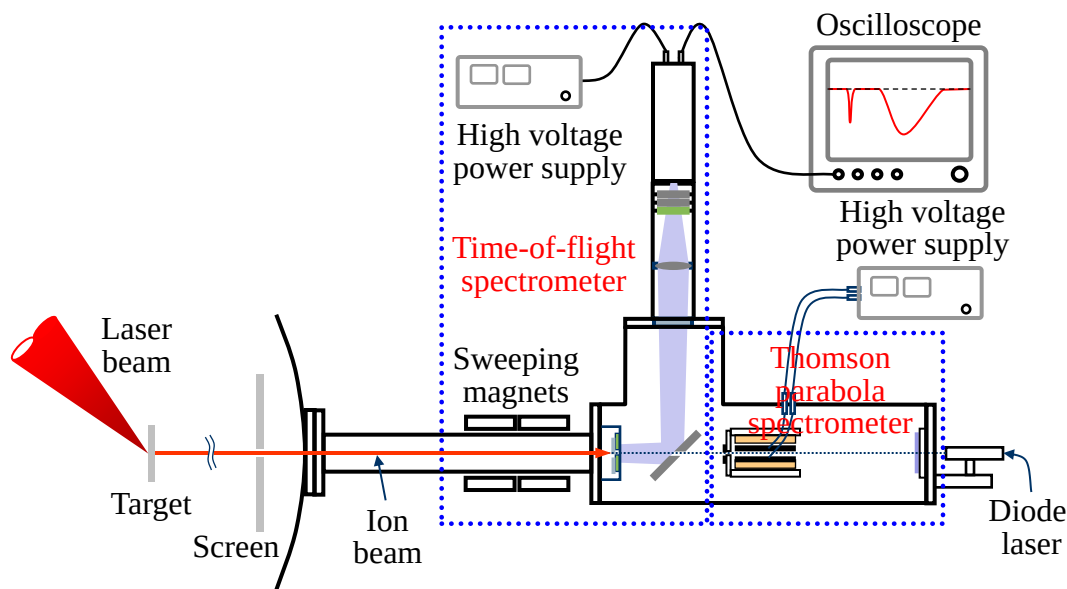


$$t = \frac{L}{c} \frac{1 + \left(\frac{E}{m_i c^2} \right)}{\sqrt{\left(\frac{E}{m_i c^2} \right)^2 + 2 \left(\frac{E}{m_i c^2} \right)}}, \quad E = m_i c^2 \left[\sqrt{1 + \frac{L^2}{(c t)^2}} - 1 \right]$$

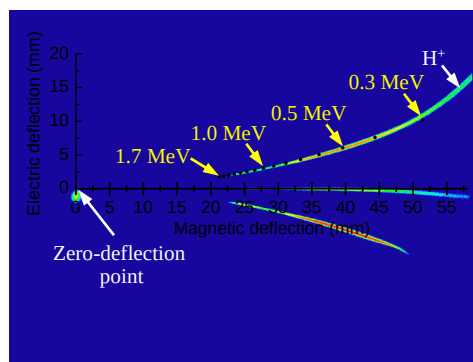


Selection of scintillator thickness

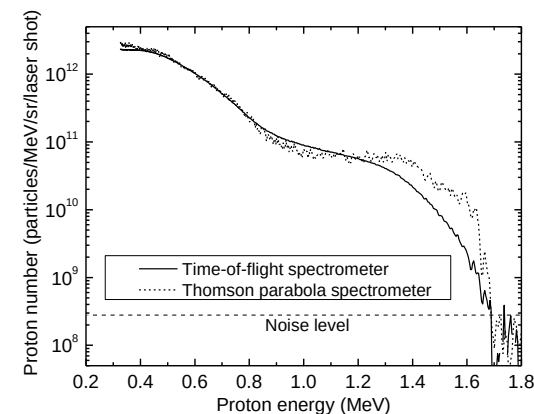
Ion Spectrometer Composed of TOF and TP Spectrometers



+



↑ E(up)
E = 0
↓ E(down)



I. W. Choi *et al.*, Rev. Sci. Instrum. **80**, 053302 (2009).

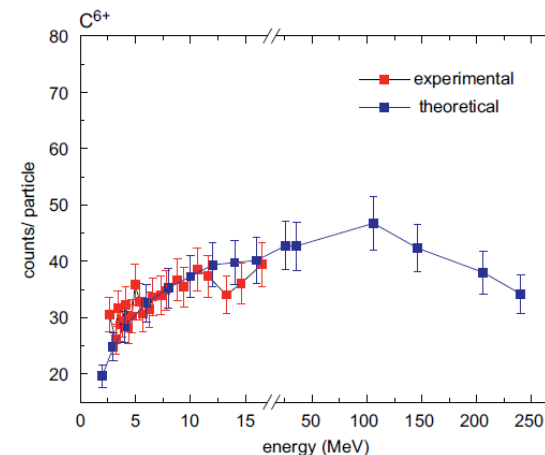
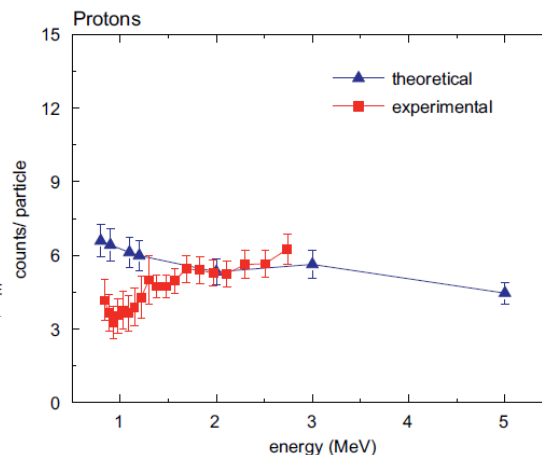
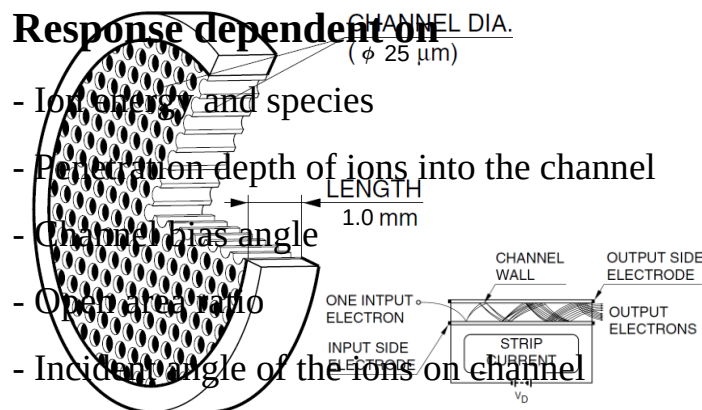
Ion Detectors : MCP, Imaging Pate (Limited Thickness)

Microchannel plate (MCP)

Stopped energies in 1-mm glass : 13 MeV (Proton), 275 MeV (Carbon)

Response dependent on

- Ion energy and species
- Penetration depth of ions into the channel
- Channel bias angle
- Open area ratio
- Incident angle of the ions on channel

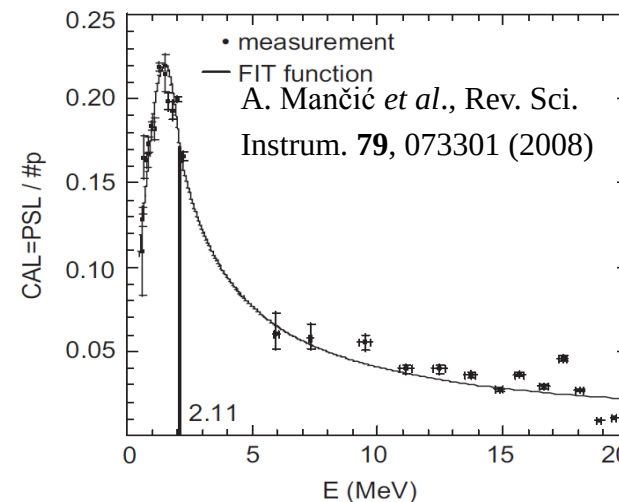


R. Prasad *et al.*, Nucl. Instrum. Methods Phys. Res. Sect. A. **623**, 712 (2010).

Imaging plate

IP type		Protective layer	Sensitive layer	Undercoat layer	Base film	Back layer
BAS-MS (white)	Area density (g/m ²)	14.9	380.3	16.5	266.7	443.7
	Thickness (μm)	9	115	12	190	160
BAS-SR (light blue)	Area density (g/m ²)	10.4	389.8	18.5	266.7	443.7
	Thickness (μm)	6	120	10	190	160
BAS-TR (intermediate blue)	Area density (g/m ²)	0	142.6	13.9	346.6	443.7
	Thickness (μm)	0	50	10	250	160
FDL-UR-V (deep blue, 25 μm)	Area density (g/m ²)	4.5	441.0	25.2	180.7	27.3
	Thickness (μm)	3	110	20	145	30

B. Hidding *et al.*, Rev. Sci. Instrum. **78**, 083301 (2007)

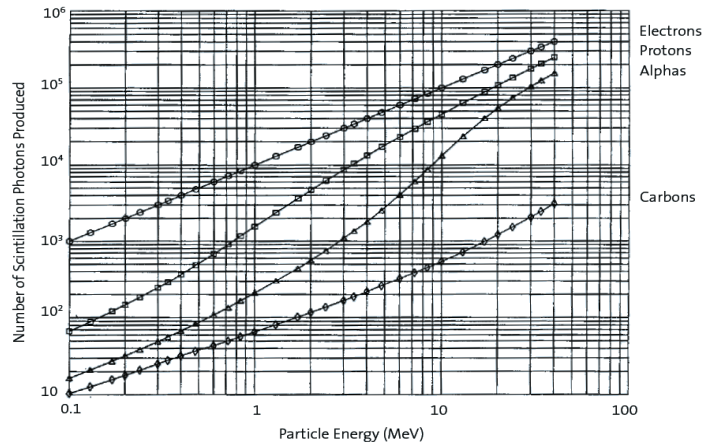




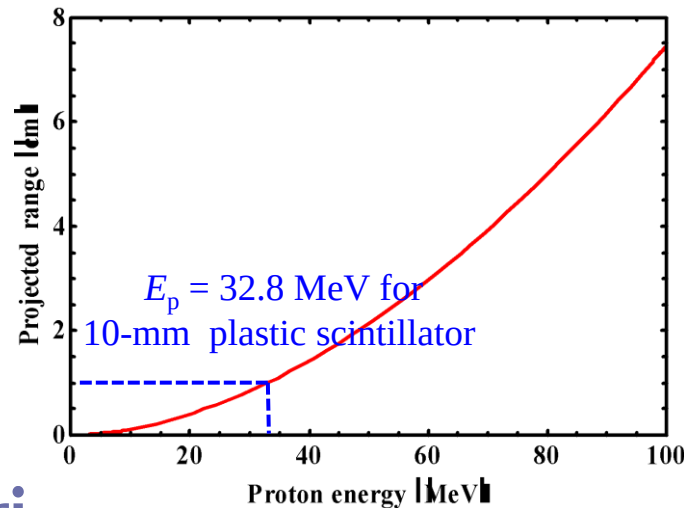
Ion Detectors : Plastic Scintillator

Plastic scintillator

Response of BC-400
Scintillation Light Produced vs. Particle Energy



<http://www.detectors.saint-gobain.com>



Birks's Formula

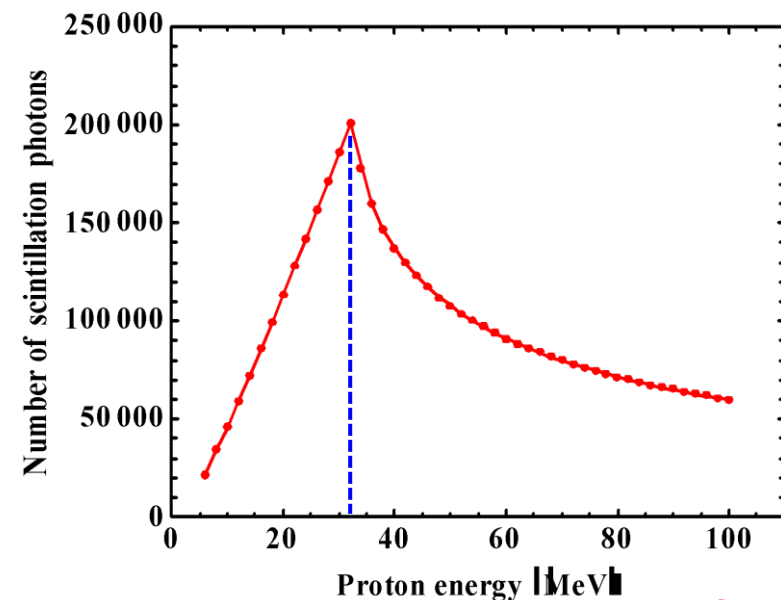
$$\frac{dL}{dx} = \frac{S \left(\frac{dE}{dx} \right)}{1 + k B \left(\frac{dE}{dx} \right) + C \left(\frac{dE}{dx} \right)^2}$$

Quenching effect

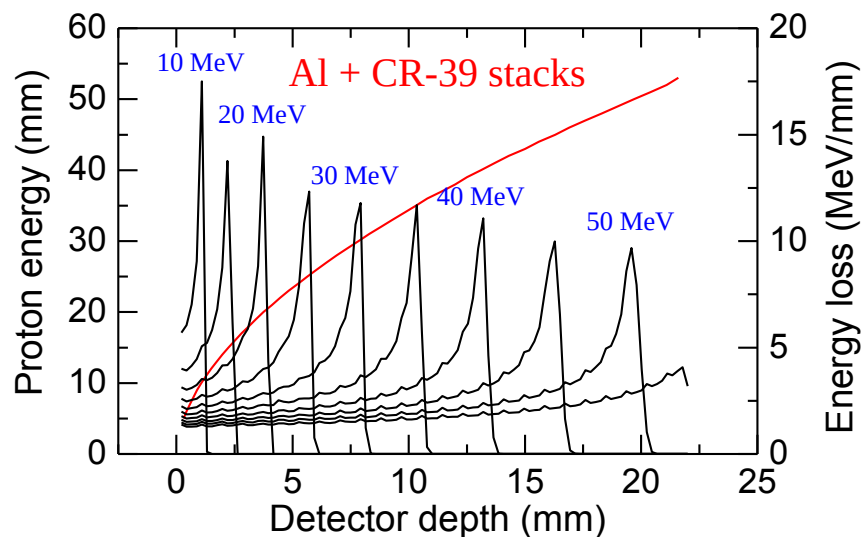
dL/dx = Fluorescence light

dE/dx = Energy loss

S = Scintillation efficiency



Energy and Beam Profile Measurement Using Stacked Detectors

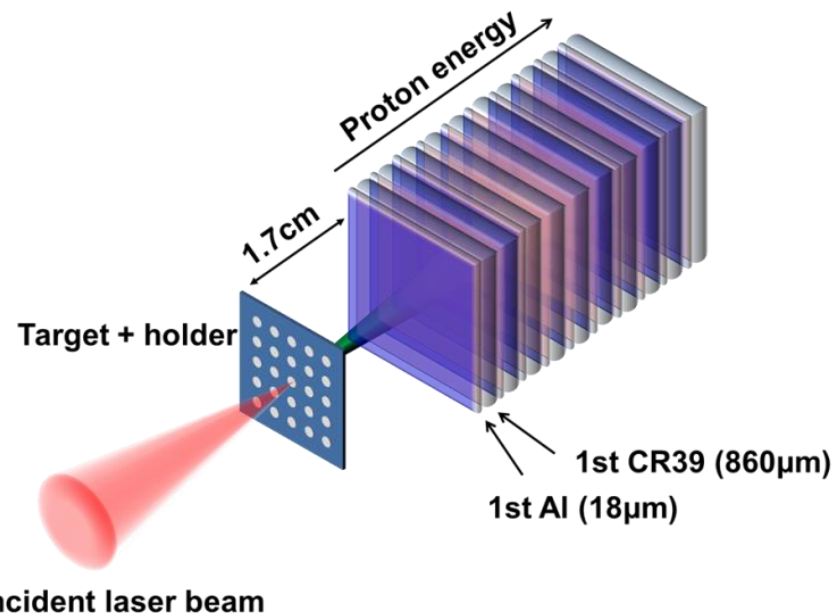
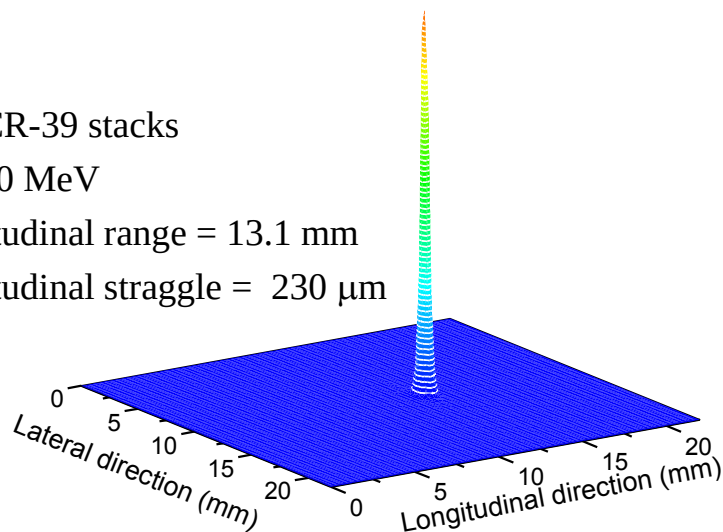


Al + CR-39 stacks

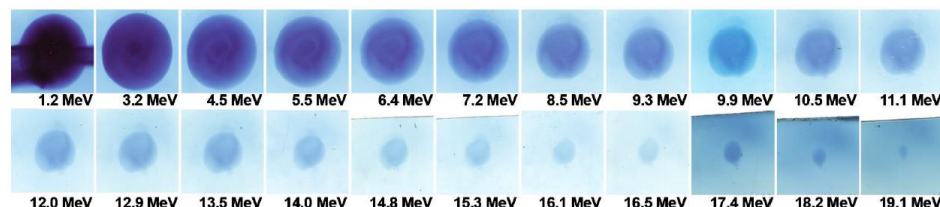
$E_p = 40$ MeV

Longitudinal range = 13.1 mm

Longitudinal straggle = 230 μ m



RCF stack : 19 films of HD-810 and 3 films of MD-55

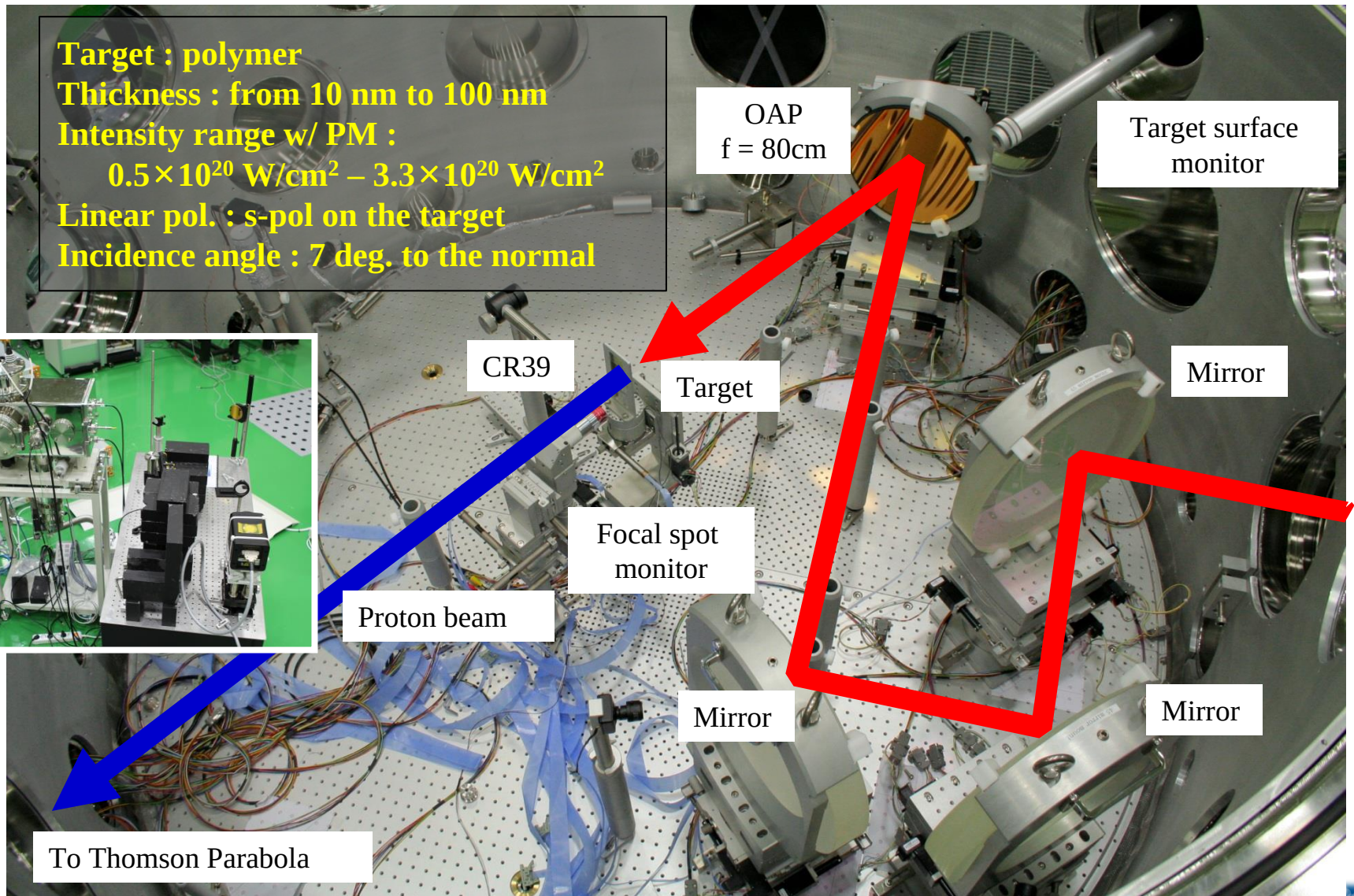
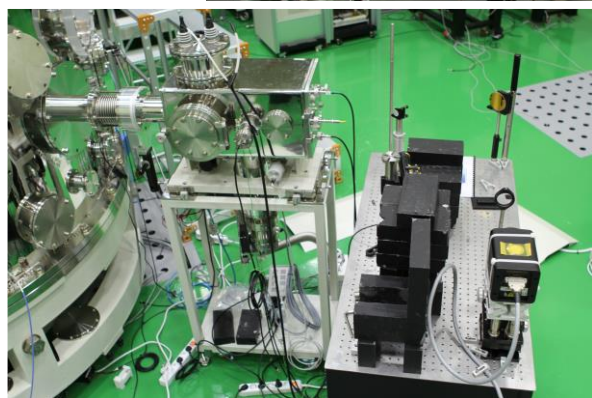


F. Nürnberg, Rev. Sci. Instrum. **80**, 033301 (2009)



Proton Acceleration Using PW Laser Pulses

Target : polymer
Thickness : from 10 nm to 100 nm
Intensity range w/ PM :
 $0.5 \times 10^{20} \text{ W/cm}^2 - 3.3 \times 10^{20} \text{ W/cm}^2$
Linear pol. : s-pol on the target
Incidence angle : 7 deg. to the normal

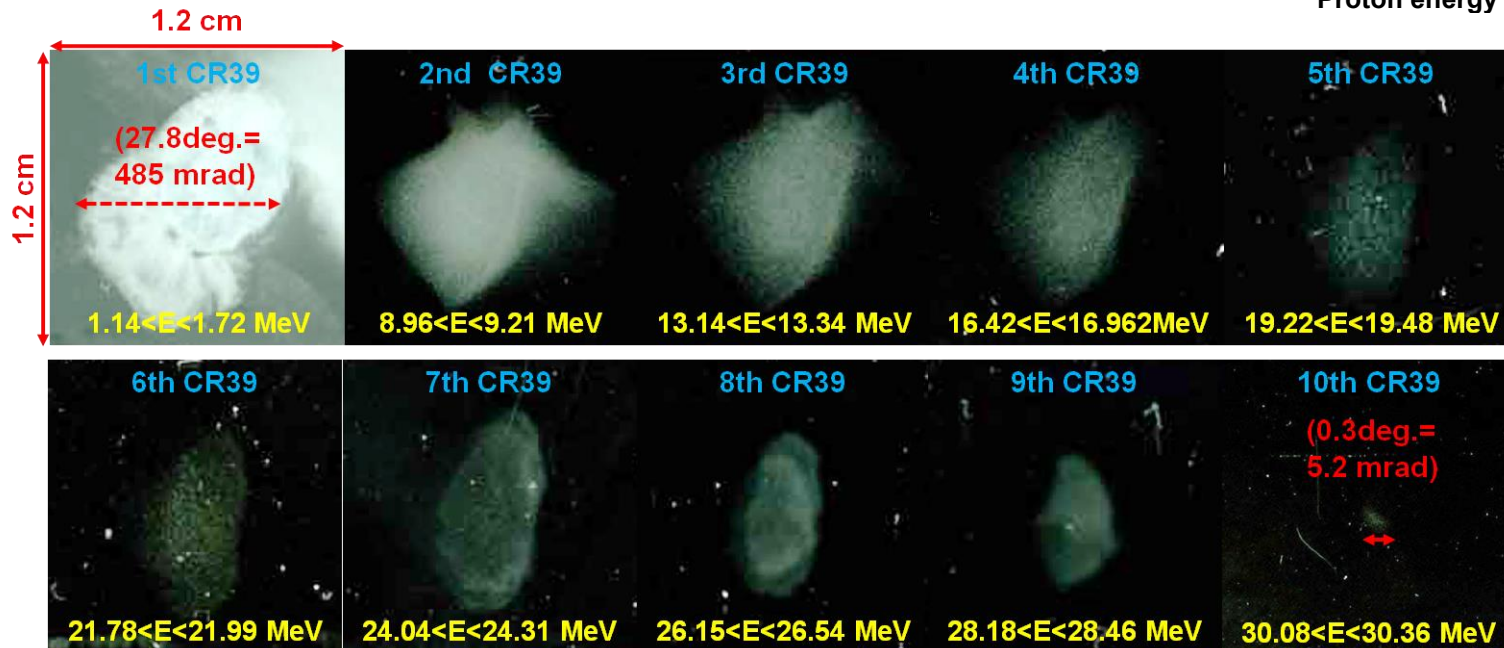
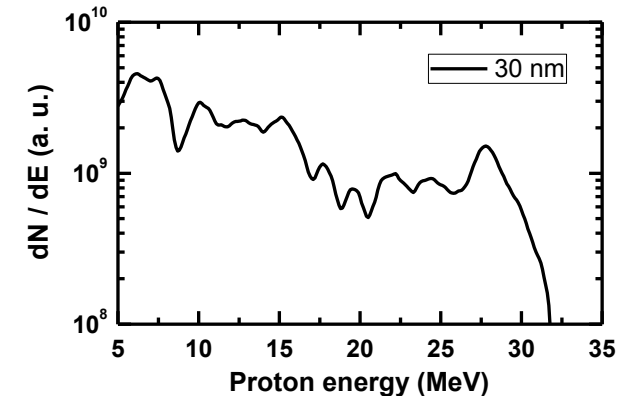
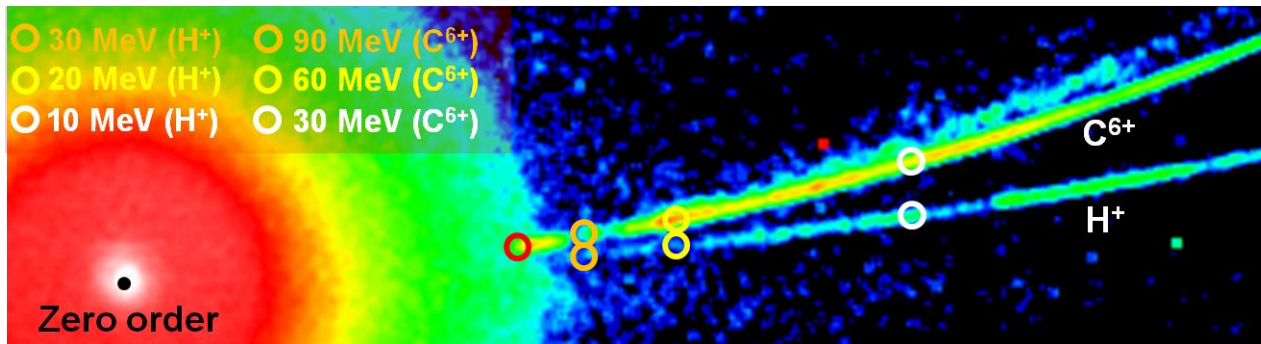




Good Agreement between TPS and CR-39 Measurement

- Target thickness : 30 nm

- Laser intensity : $3.3 \times 10^{20} \text{ W/cm}^2$

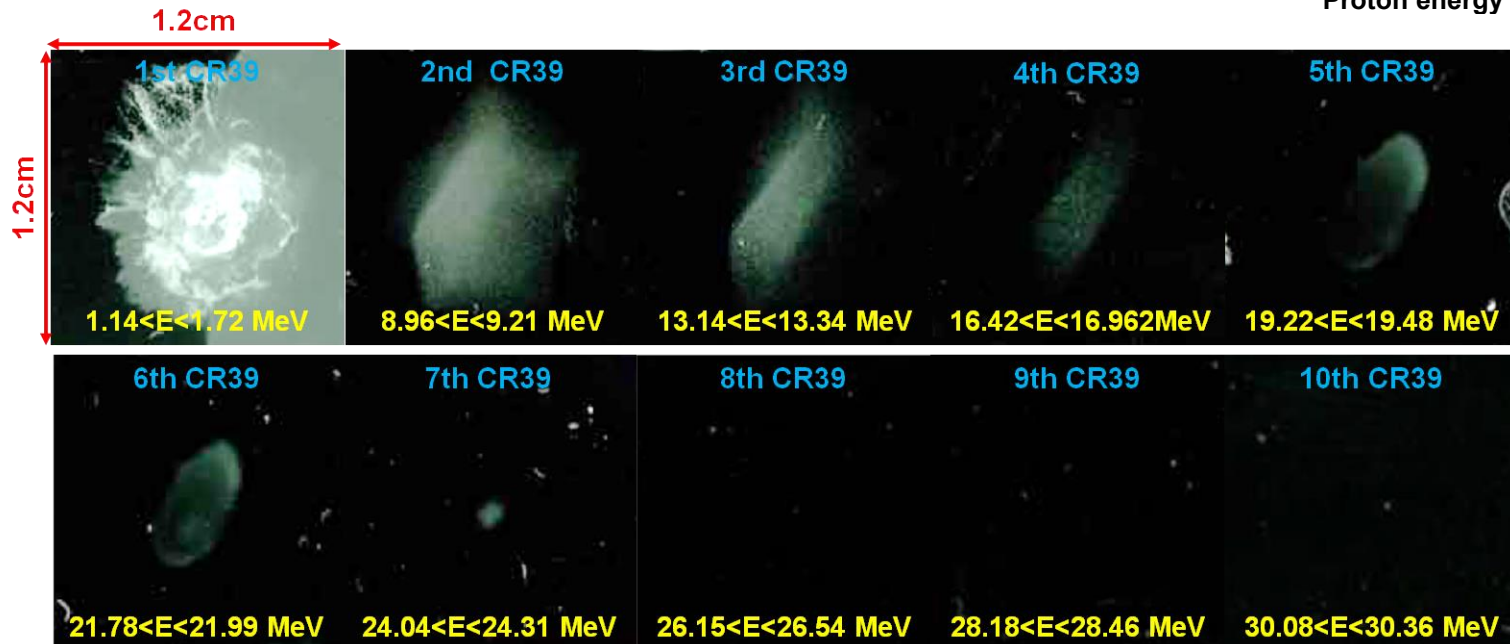
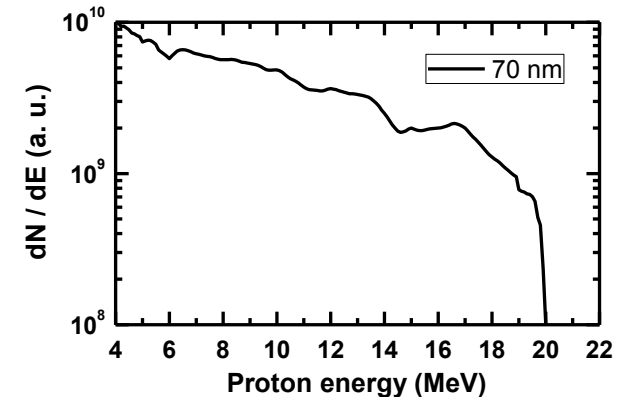
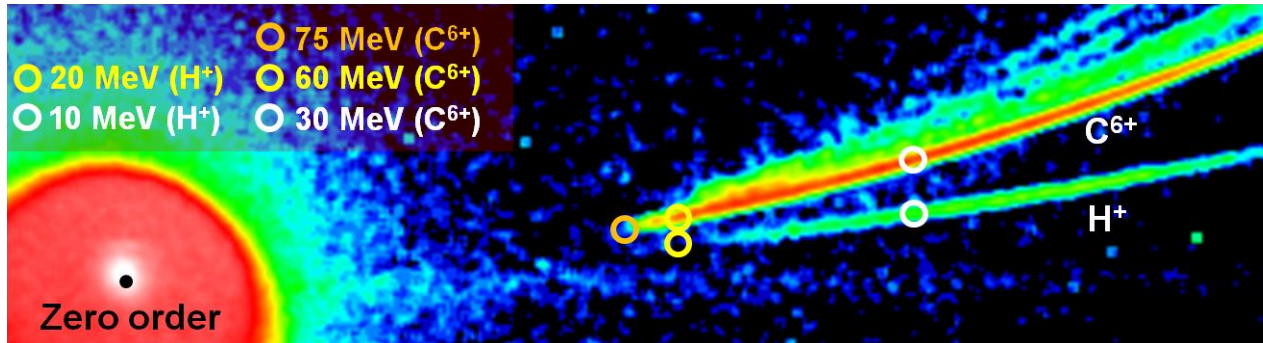




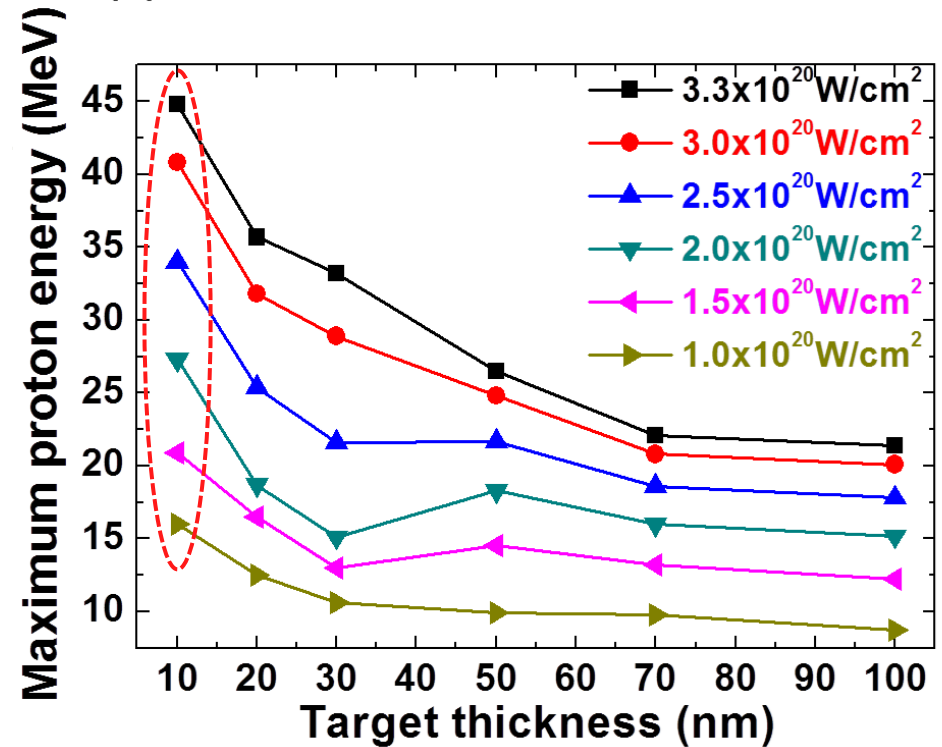
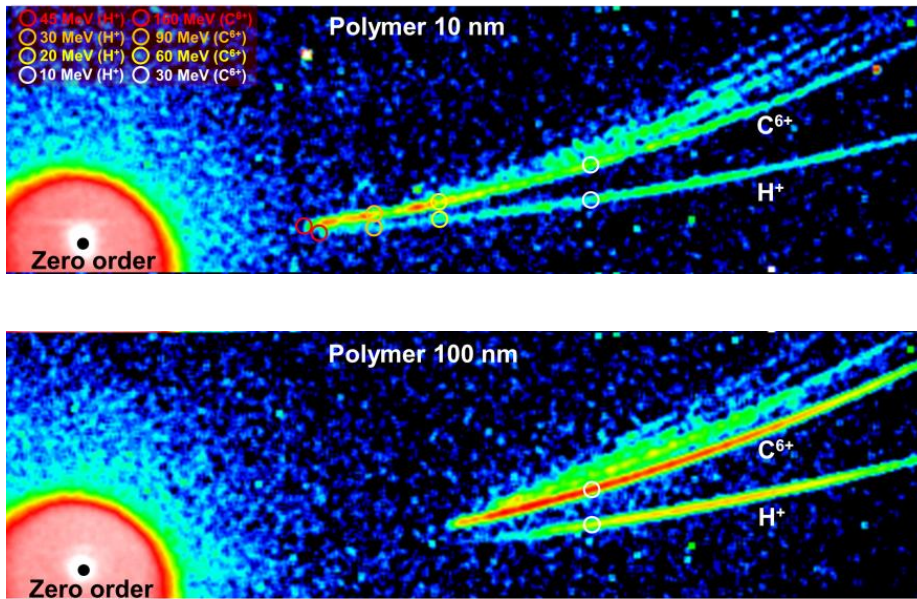
Good Agreement between TPS and CR-39 Measurement

- Target thickness : 70 nm

- Laser intensity : $3.3 \times 10^{20} \text{ W/cm}^2$



45 MeV Proton Energy Achieved with 10-nm Thick Polymer



- ✓ Thomson parabola and ion energy spectra obtained with a $3.3 \times 10^{20} \text{ W/cm}^2$ laser intensity and 10-nm thick polymer target
- ✓ Continuous energy increase until 10-nm target implies the high performance of double plasma mirror system, very high contrast up to several ps before main pulse arrival.



Conclusions

Several issues solved already or to be solved for real applications

Laser beam

- ✓ Well-controlled temporal and spatial properties
- ✓ Low- or high- contrast, depending on target type
- ✓ Rough alignment for each shot and robust shooting
 - Reproduced focusing quality
 - Precise target positioning onto laser focus

Target

- ✓ Production of ultrathin targets with large area
- ✓ Cost effective, stable, and reproducible way
- ✓ New and exotic targets : foam, nano-structure

Diagnostics system

- ✓ Real-time and fast characterization
- ✓ Extending detection range to ~ 100 MeV and higher

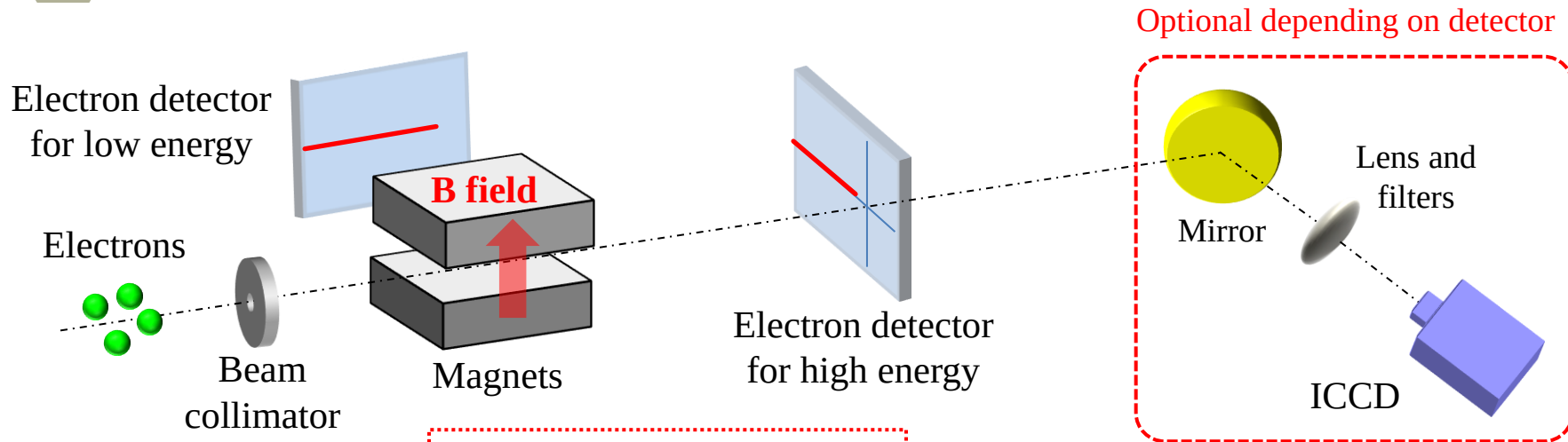


Thank you for your attention

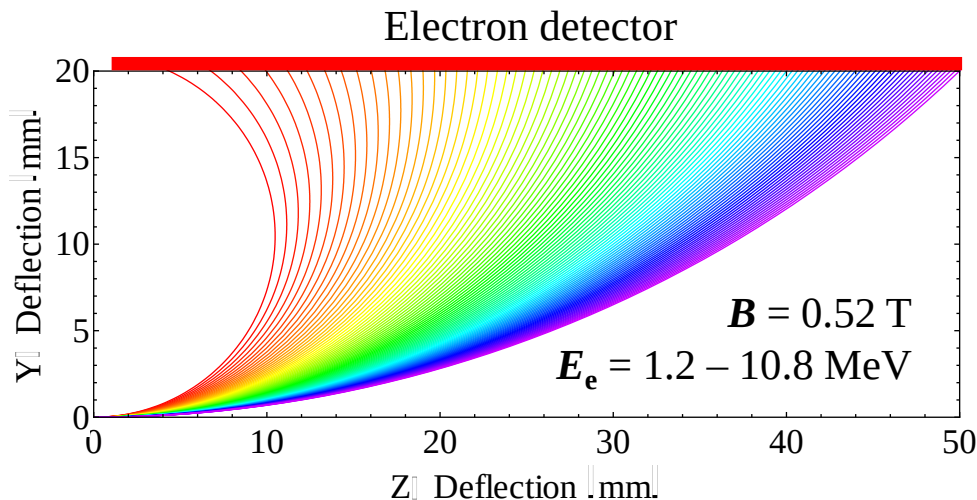




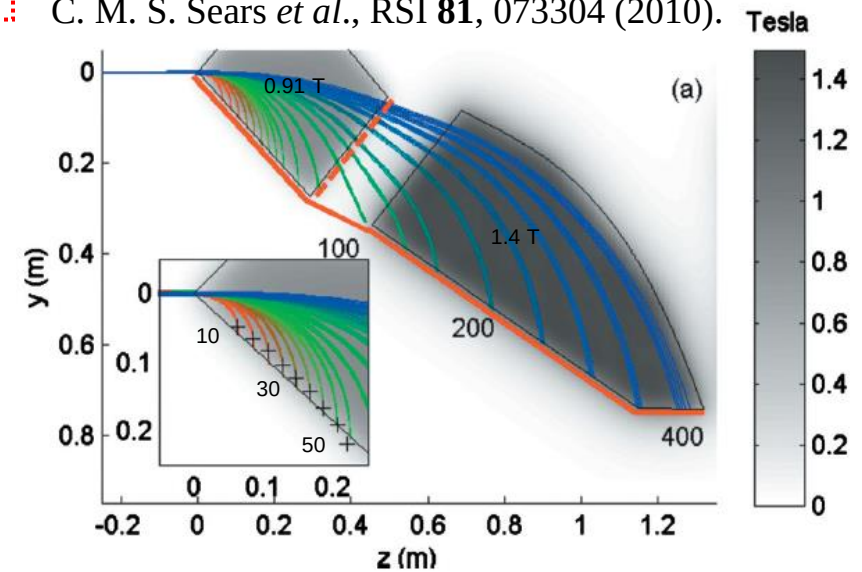
Electron Spectrometer and Detection



$$\rho = \frac{m_e c \beta \gamma}{e B} \approx \frac{E}{e c B} \text{ for } E \gg m_e c^2$$



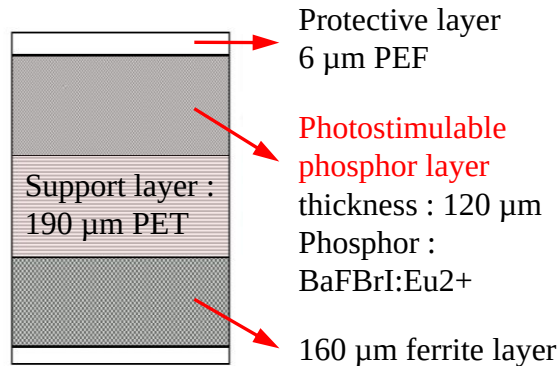
C. M. S. Sears *et al.*, RSI **81**, 073304 (2010).



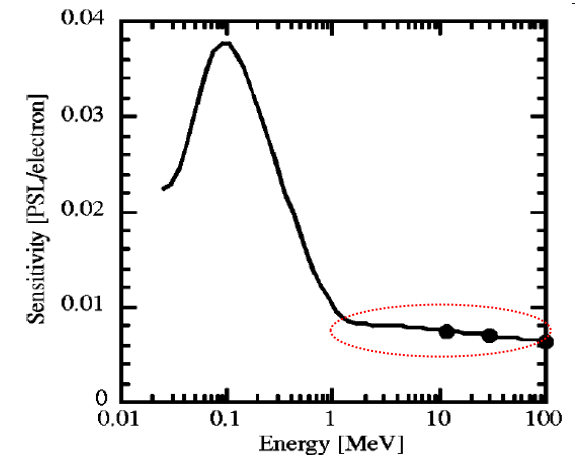
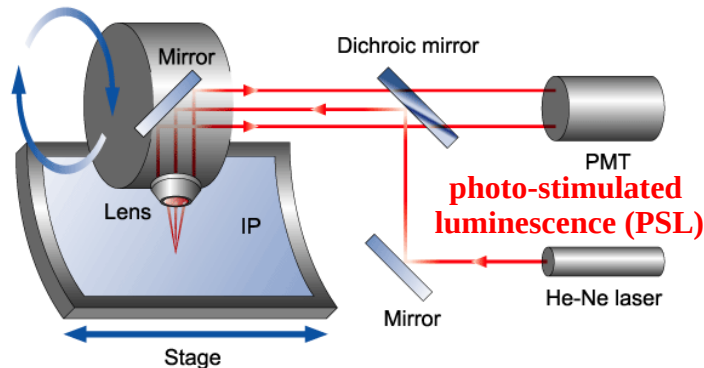


Electron Detectors : Imaging Pate, Lanex

Imaging plate : Fuji film



Structure of BAS-SR imaging plate

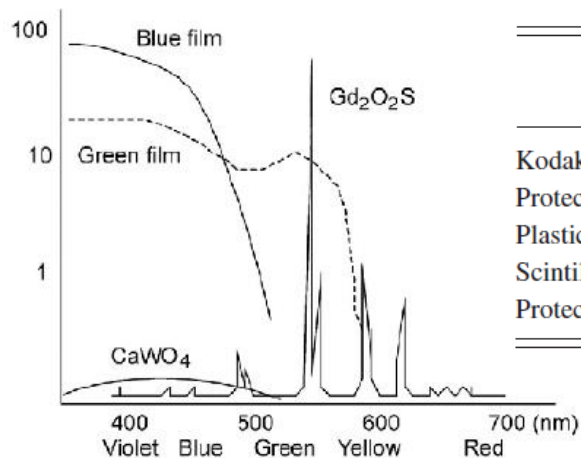


Response of BAS-SR to electrons

K. A. Tanaka, RSI 76, 013507 (2005).

Lanex screen : Kodak

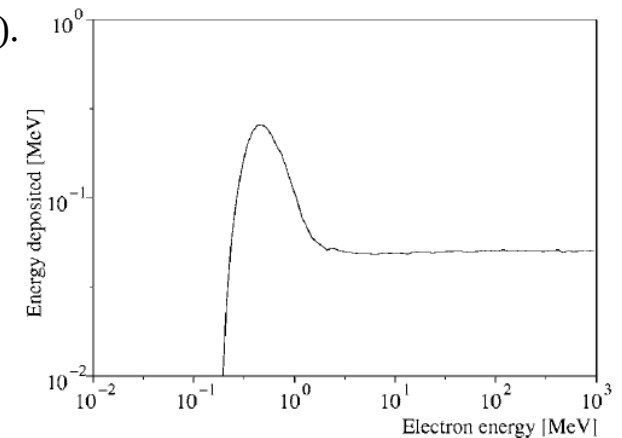
Y. Glinec, RSI 77, 103301 (2006).



Emission spectra of Lanex screen

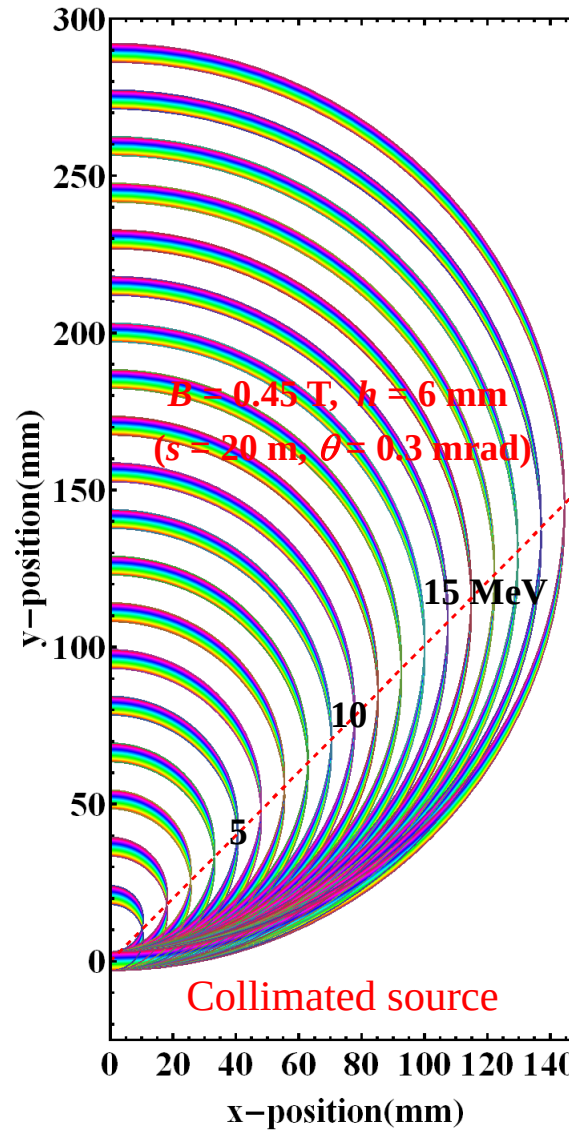
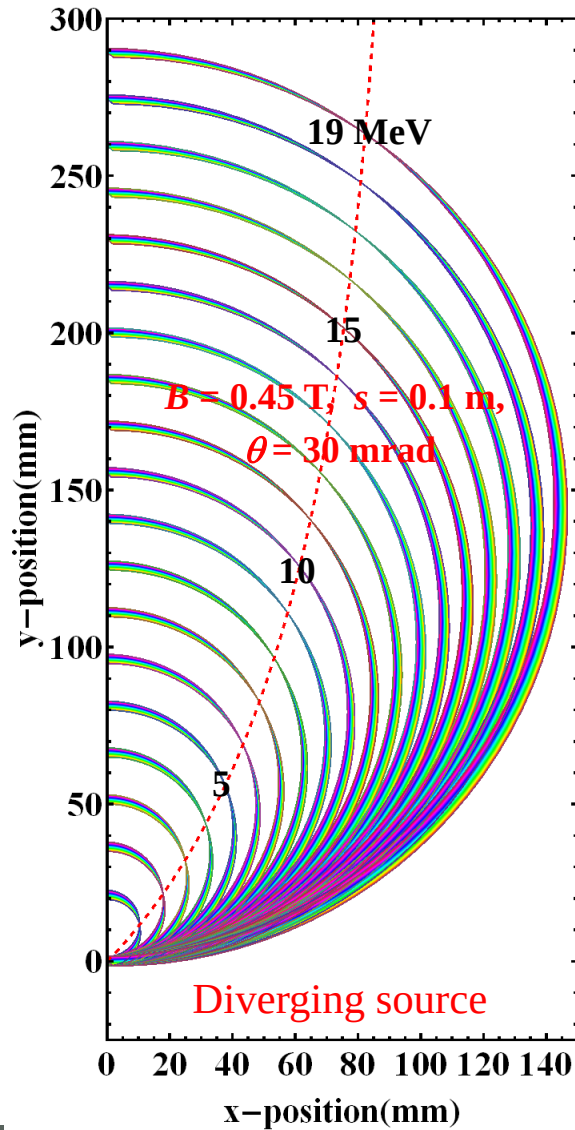
Item	Material	Density (g/cm ³)	Thickness (cm)
Kodak Lanex Fine screen			
Protective coating	Cellulose acetate1	1.32	0.0010
Plastic substrate	Poly(ethylene terephtalate)	1.38	0.0178
Scintillator	$\text{Gd}_2\text{O}_2\text{S}$ +urethane binder	4.25	0.0084
Protective coating	Cellulose acetate	1.32	0.0005

Composition of Kodak Lanex Fine screen



Energy deposited in the scintillator
layer of Lanex Fine screen

Enhancement in Energy Resolution Adapting Focusing Geometry



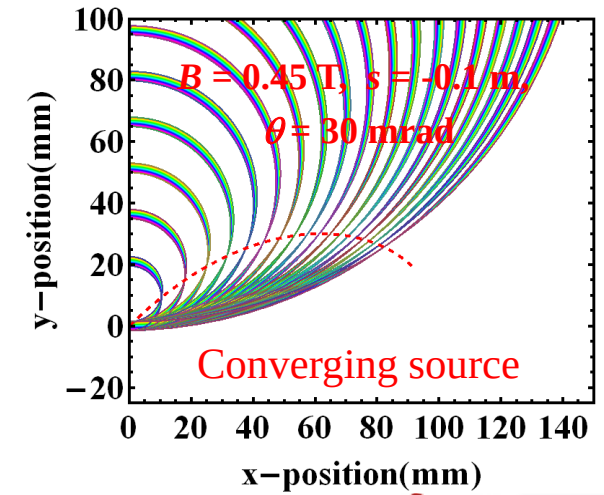
$$\Delta x = \frac{\partial x}{\partial \theta} \Delta \theta + \frac{\partial x}{\partial \rho} \Delta \rho$$

$$\approx \left[\left(a + d + f \right) + \left(\frac{d}{2} + \frac{3f}{2} \right) \left(\frac{d}{\rho} \right)^2 \right] \Delta \theta$$

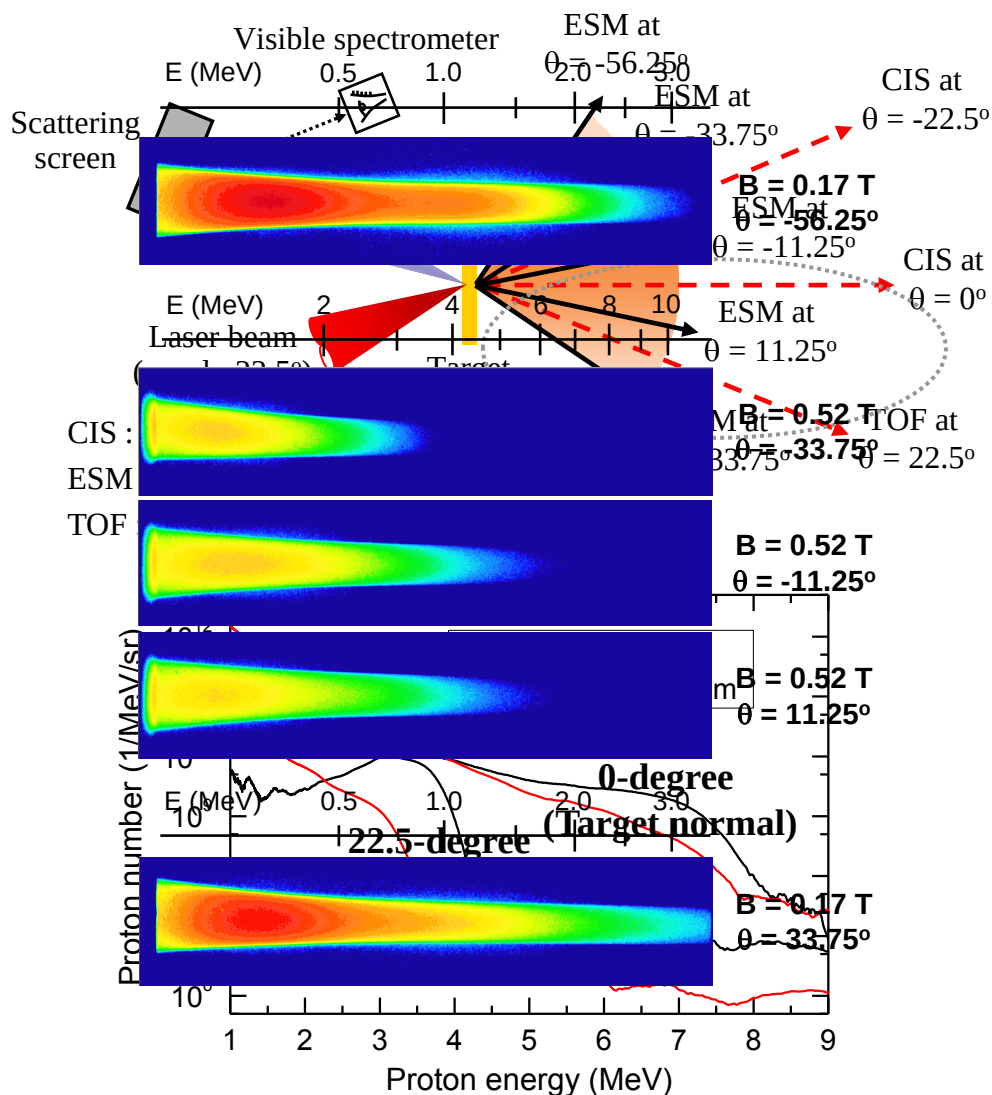
$$- \left[\left(\frac{d}{2} + f \right) \left(\frac{d}{\rho} \right) + (d + 3f) \left(\frac{d}{\rho} \right)^2 \theta \right] \left(\frac{\Delta \rho}{\rho} \right)$$

for non-focusing geometry

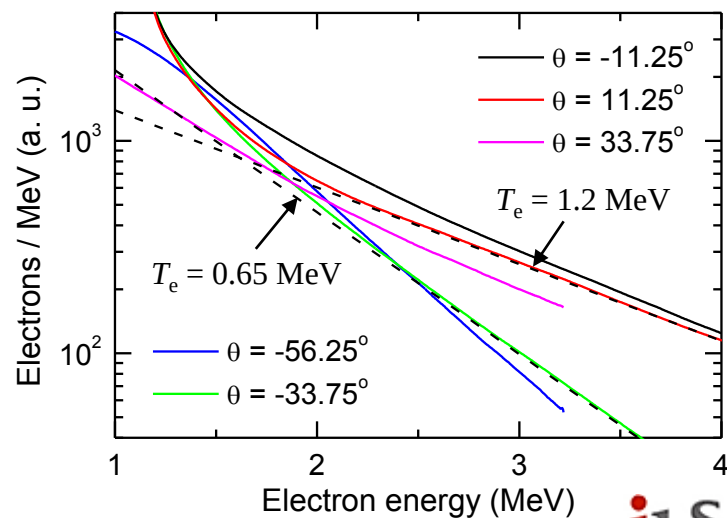
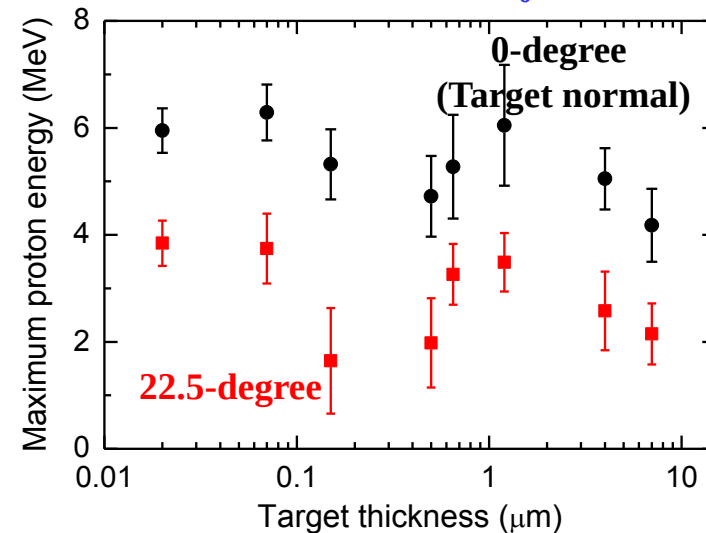
$$\sigma_x^2 = \left[\frac{\partial x}{\partial \theta} \right]^2 \sigma_\theta^2 + \left[\frac{\partial x}{\partial \rho} \right]^2 \sigma_\rho^2$$



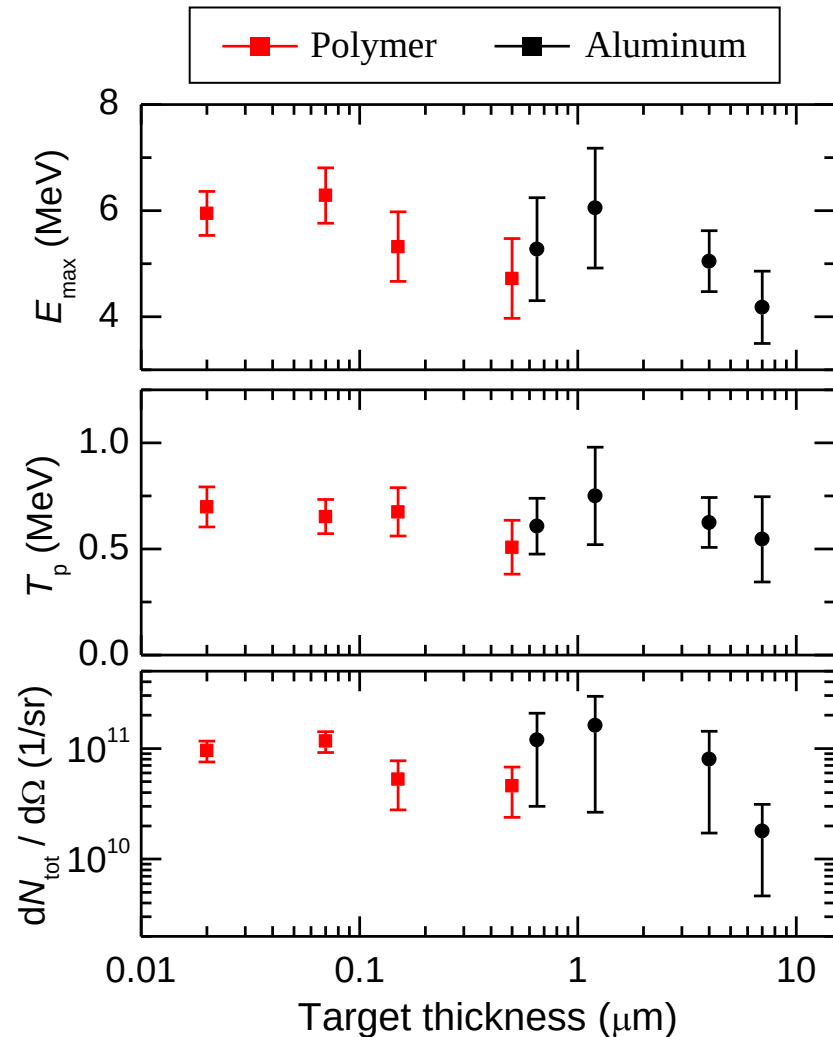
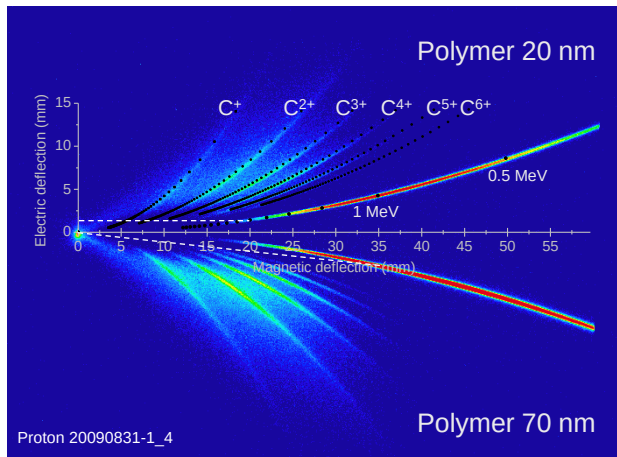
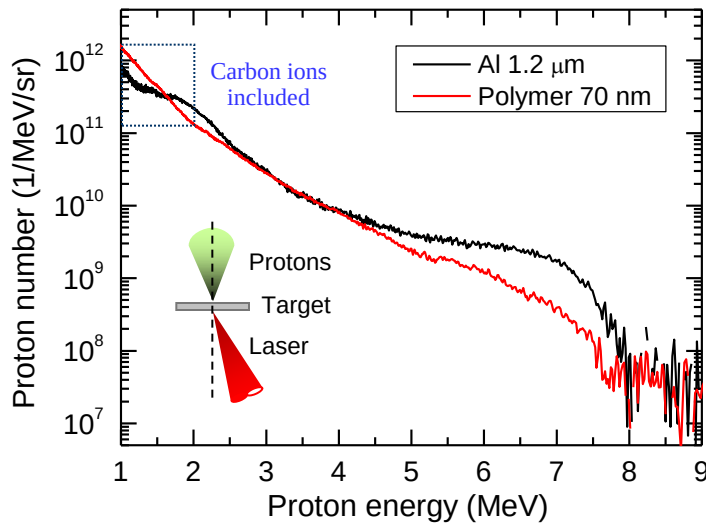
Proton Energy and Electron Spectra Dependent on Observation Angle



35 fs(FWHM) , 22.5° incidence angle
 $I = 4 \times 10^{19}\text{ W/cm}^2$, $a_0 = 4.33$,



Proton Energy Increased Using PM and Ultrathin Targets

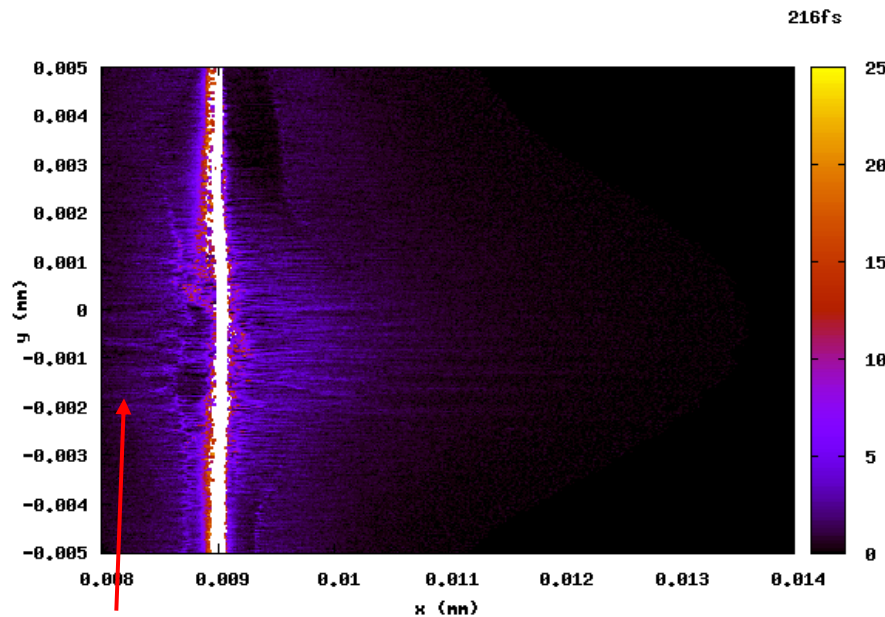


Maximum proton energy obtained : 8 MeV



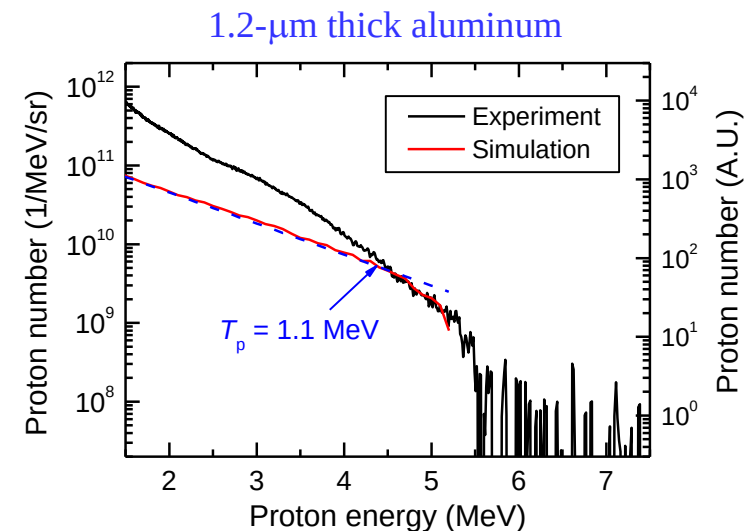
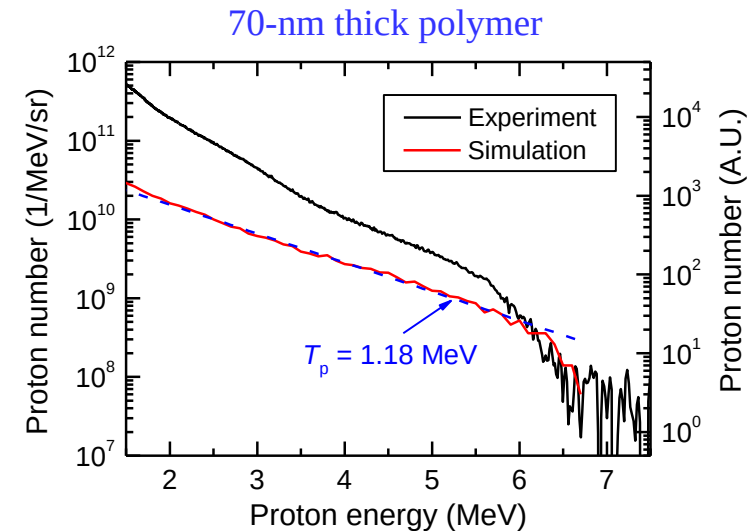
Current Results Reproduced Well with PIC Simulation

- $I = 5 \times 10^{19} \text{ W/cm}^2$, $\omega = 5 \text{ } \mu\text{m}$ (FWHM), $\tau = 34 \text{ fs}$,
- Linearly polarized pulse, 22.5-degree incident angle
- Assuming initial plasma density : $n = 250 n_{\text{cr}}$



Laser pulse

Proton density map at 216 fs

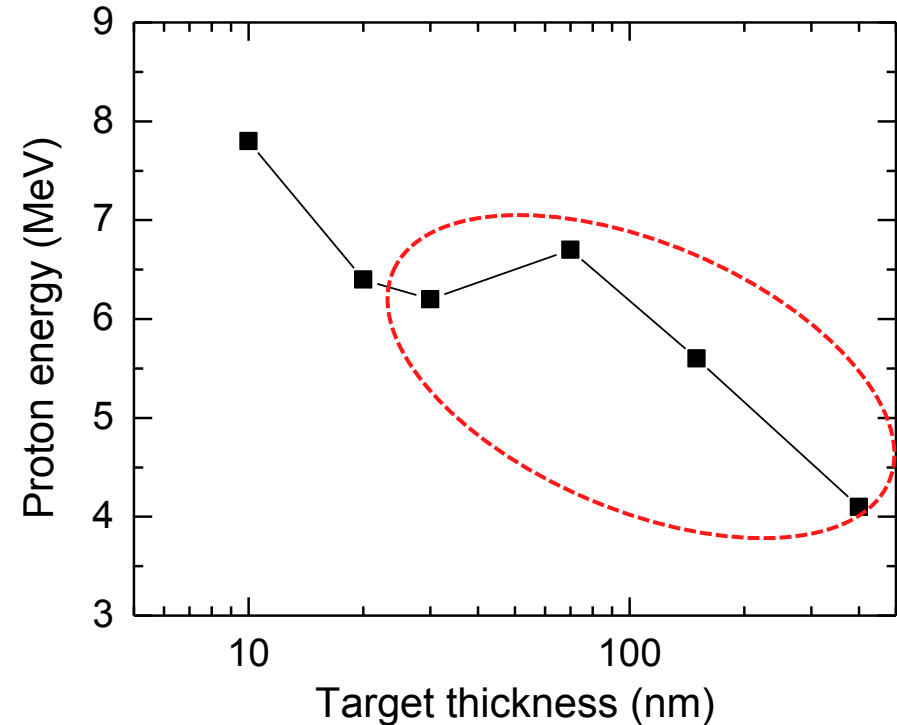
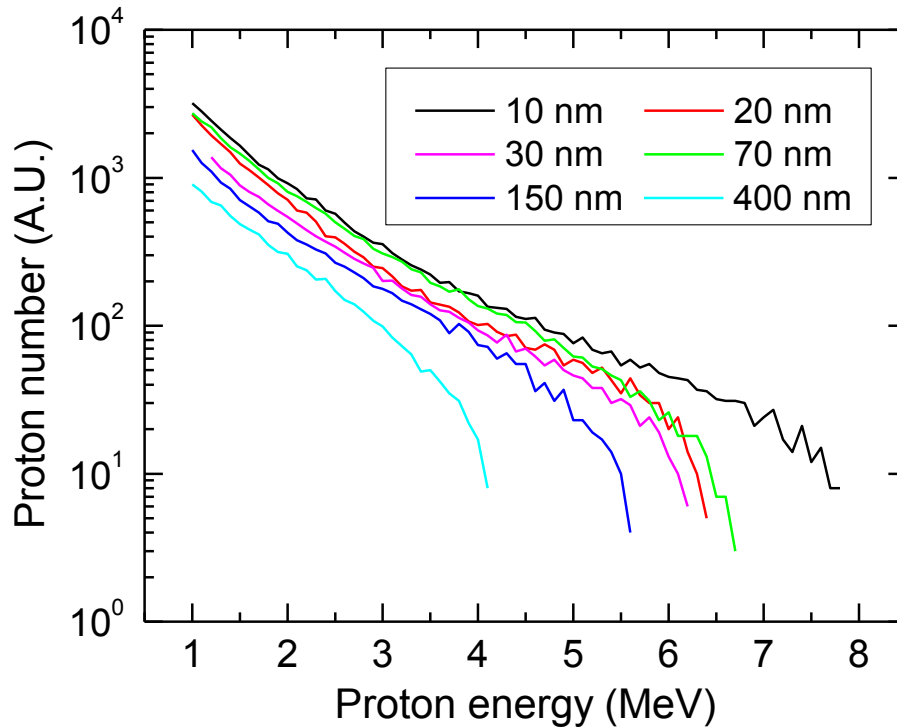


(Simulation with ALPS-2D code)



Optimal Target Thickness Well Agreed with PIC Simulation

PIC Simulation with ALPS-2D code



Accelerating sheath electric field

in TNSA
$$E_{\text{sheath}} \approx \frac{k_B T_e}{e \lambda_D} = \sqrt{4 \pi n_e k_B T_e}$$

Competition of two opposite tendencies :

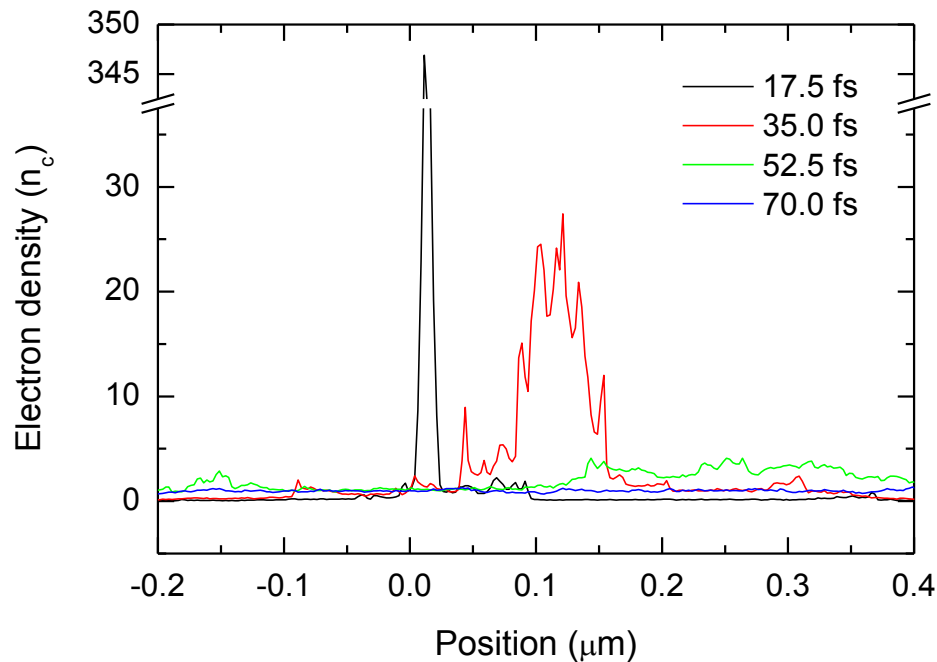
- Large recirculation effect at thinner target : enhancing n_e
- Large laser absorption at thicker target : enhancing T_e

Relativistic Transparency Effect at the Thinnest Target : RPA

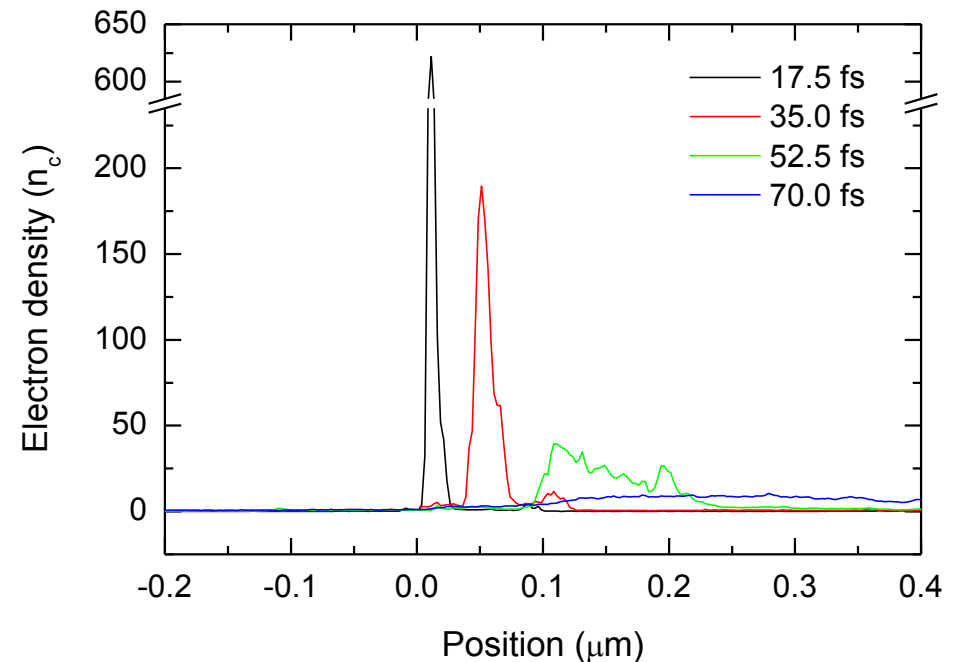
Dispersion relation : $\omega^2 = c^2 k^2 + \frac{\omega_{pe}^2}{\gamma}$, $n_c^{rel} = \gamma n_c$ Skin depth : $l_s = \frac{c}{\omega_{pe}^{rel}} = \frac{c}{\omega_{pe}} \sqrt{\gamma}$, where $\gamma = \sqrt{1 + a_0^2}$

$n_c^{rel} = 4.44 n_c$, $l_s = 19 \text{ nm}$ for $a_0 = 4.33$

10-nm target



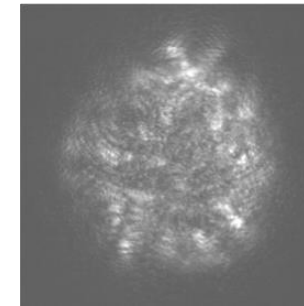
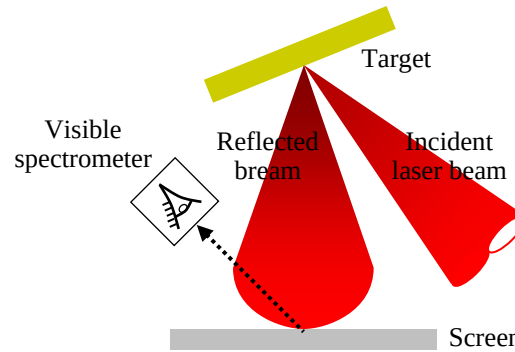
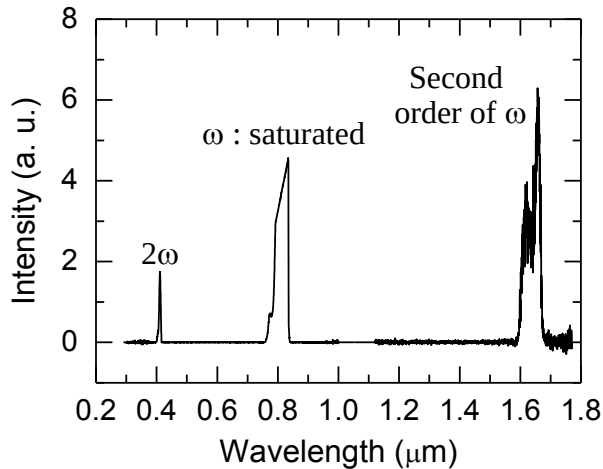
20-nm target



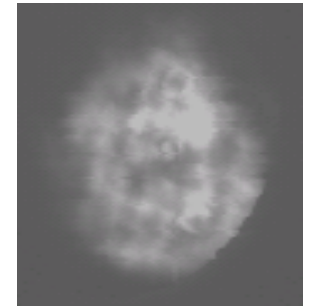
Relativistic transparency for an ultrathin target allows the additional heating.

Strong 2ω (in Experiment) and HOH (in PIC Simulation) Observed

- The 2ω spectra were not detected (or were nearly at the noise level) in the case of Al targets.
- The 2ω intensity shows similar dependence on the target position to proton energy.

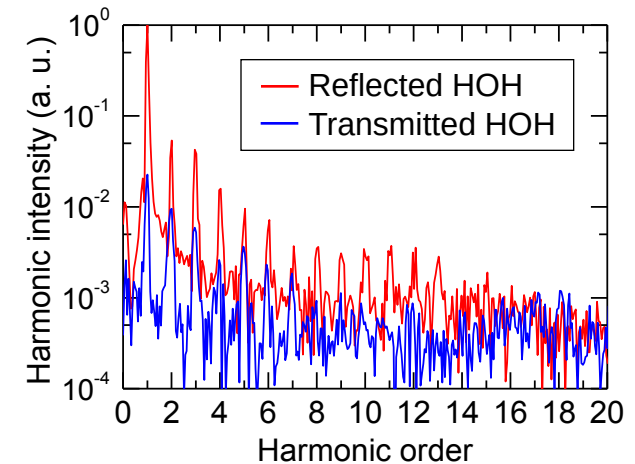
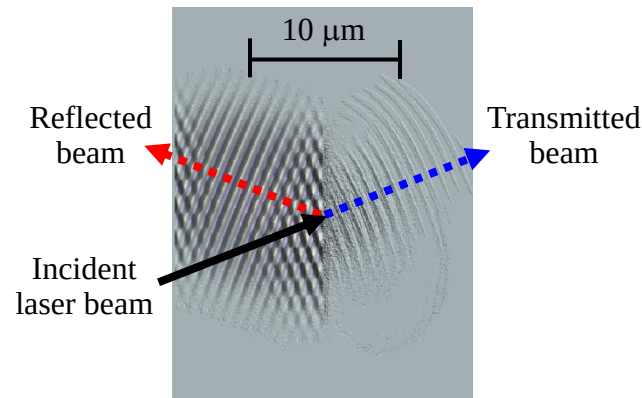
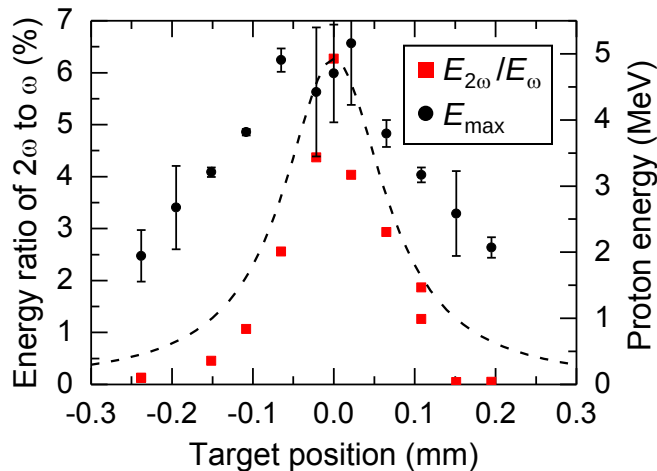


Incident laser beam profile on target



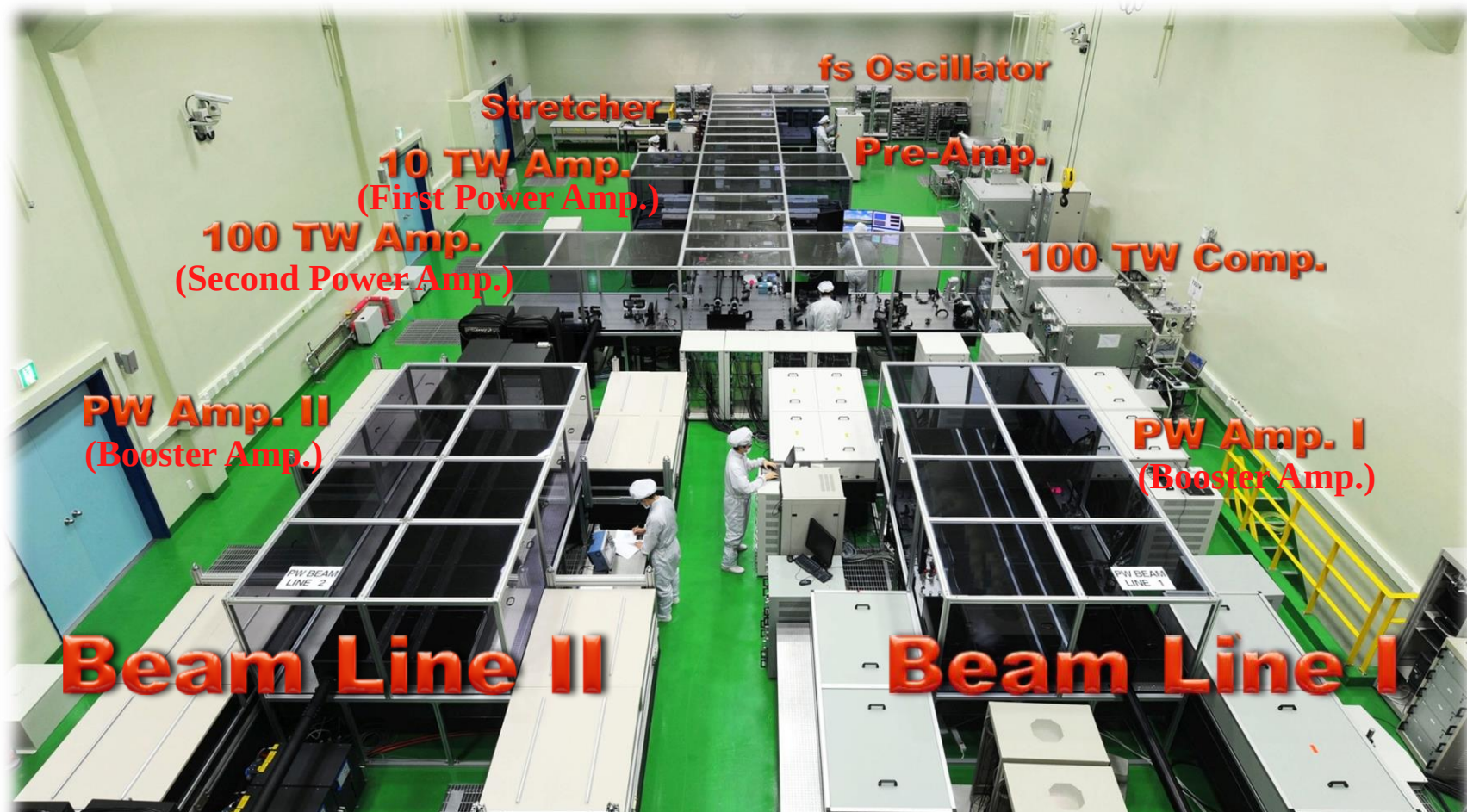
Reflected beam profile from target

PIC simulation on the harmonic generation with PIC simulation code



I. W. Choi *et al.*, Appl. Phys. Lett. **99**, 181501 (2011).

PW (PUSER) and 100 TW (LiFSA) Ti:Sapphire Laser System



PULSER (1 PW : Petawatt Ultrashort Laser Source for Extreme science Research)

LiFSA (100 TW : Light source for Femto Science and Applications)



Space-Resolving Flat-Field Soft X-ray Spectrometer

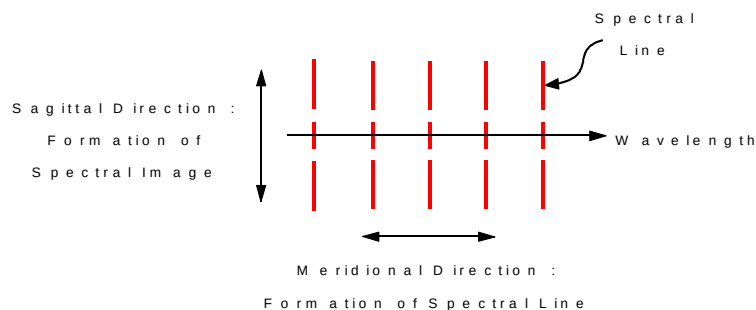
❑ Flat-field soft x-ray spectrometer with varied line-spacing concave grating

- Components : Varied line-spacing concave grating (1200 or 2400 grooves/mm), Entrance slit, Toroidal mirror, Soft X-ray detector(e.g. CCD), Vacuum housing

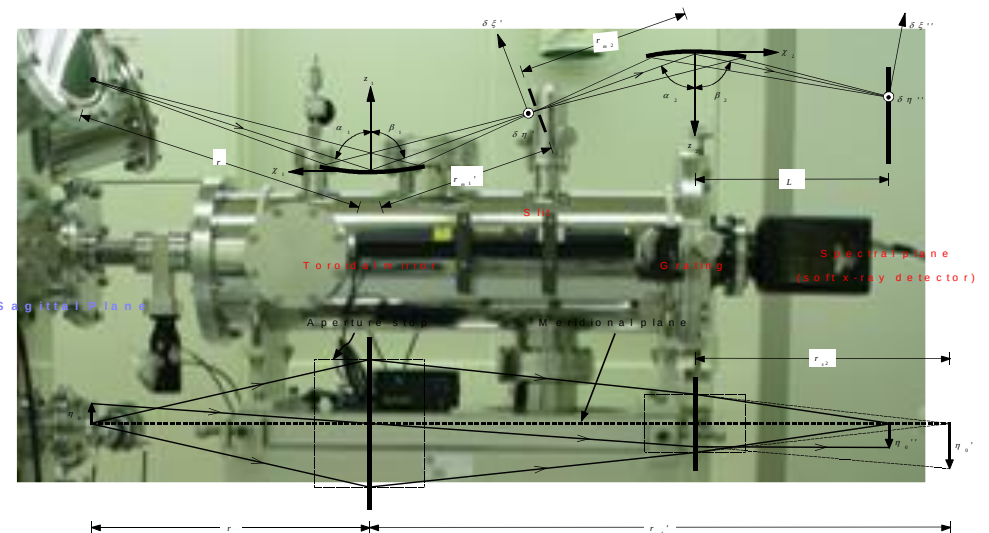
❑ Space-resolving capability using pre-focusing optics

- Increasing light collection efficiency
- Source characterization vs position

$$\begin{aligned}
 & * \text{ Tangential Focusing } \quad \frac{1}{r} + \frac{1}{r'_{m1}} = \frac{2}{R_1 \cos \alpha_1} \\
 & * \text{ Sagittal Focusing } \quad \frac{1}{r} + \frac{1}{r'_{s1}} = \frac{2 \cos \alpha_1}{\rho_1}
 \end{aligned}$$



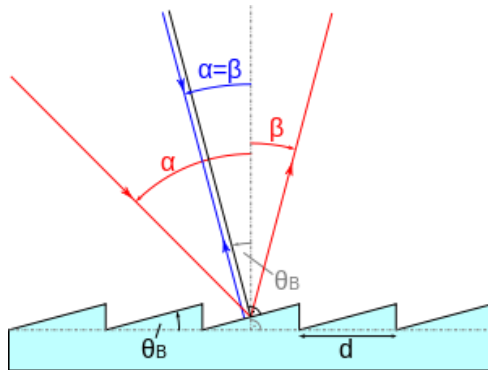
■ Meridional Plane



■ Sagittal Plane

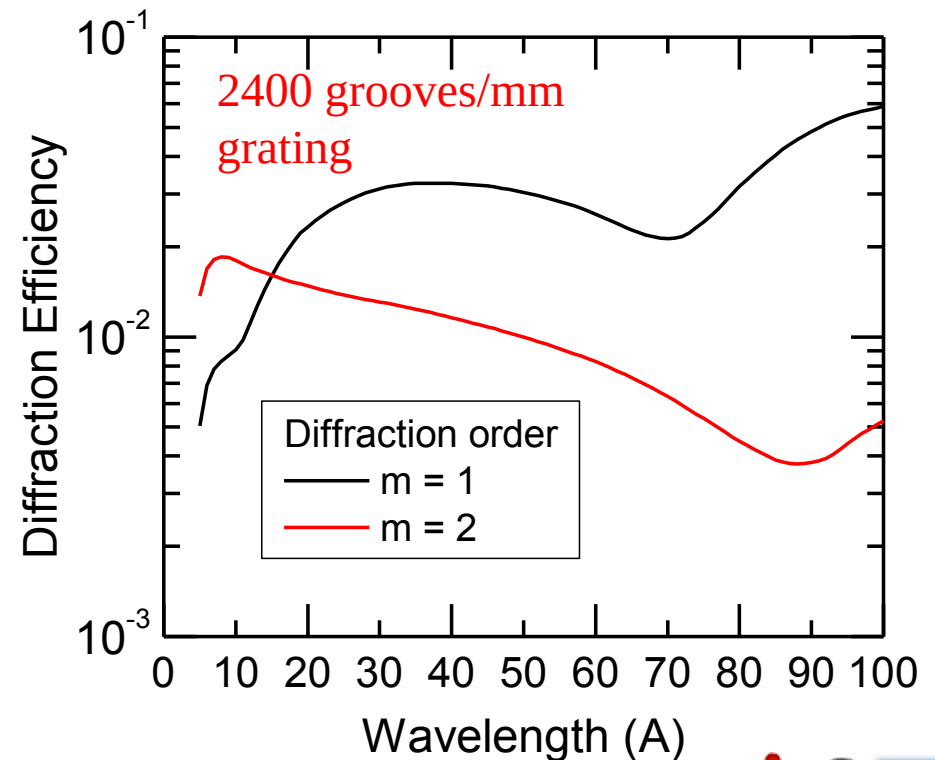
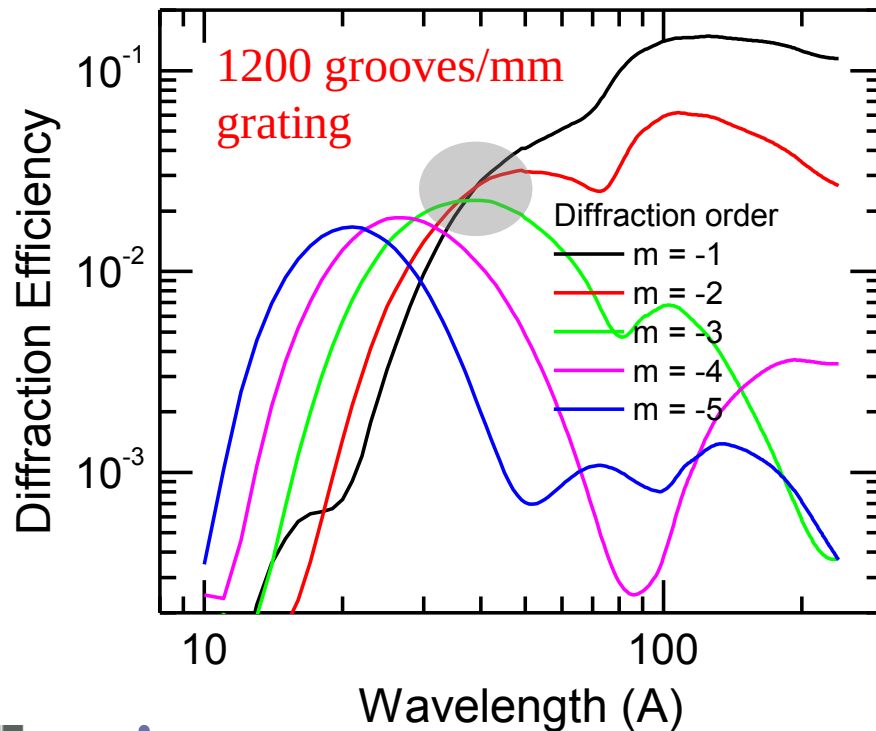


Diffraction Efficiency of VLS Grating



Blaze wavelengths

- $m\lambda_{b0} = 100.5 \text{ \AA}$ for 1200 grooves/mm grating
- $m\lambda_{b0} = 15.7 \text{ \AA}$ for 2400 grooves/mm grating

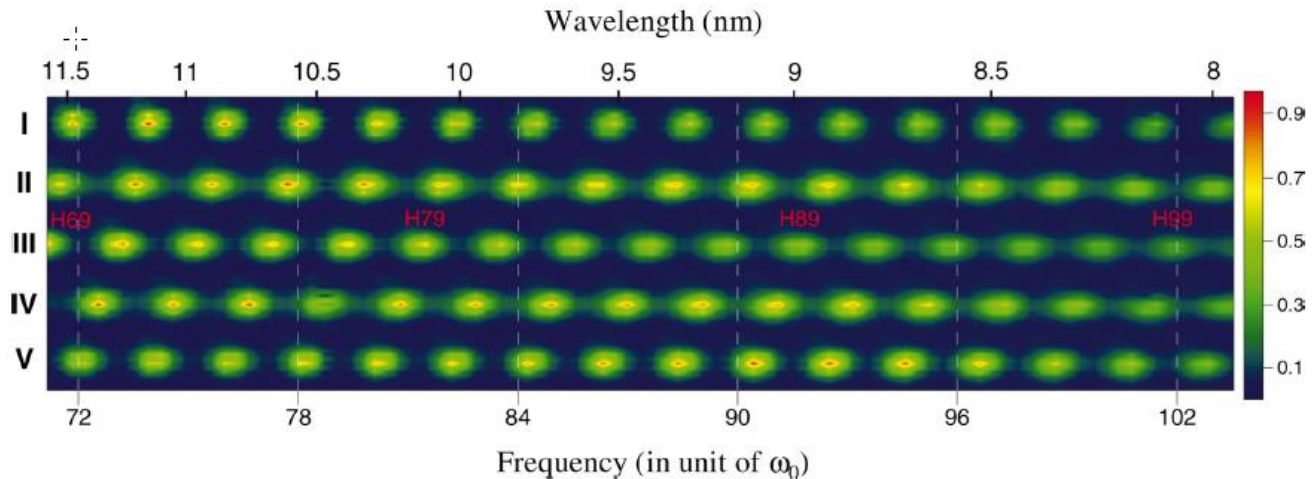




High Order Harmonics from Gas (He, Ar) Target

Continuously wavelength-tuned high-order harmonics from He atoms

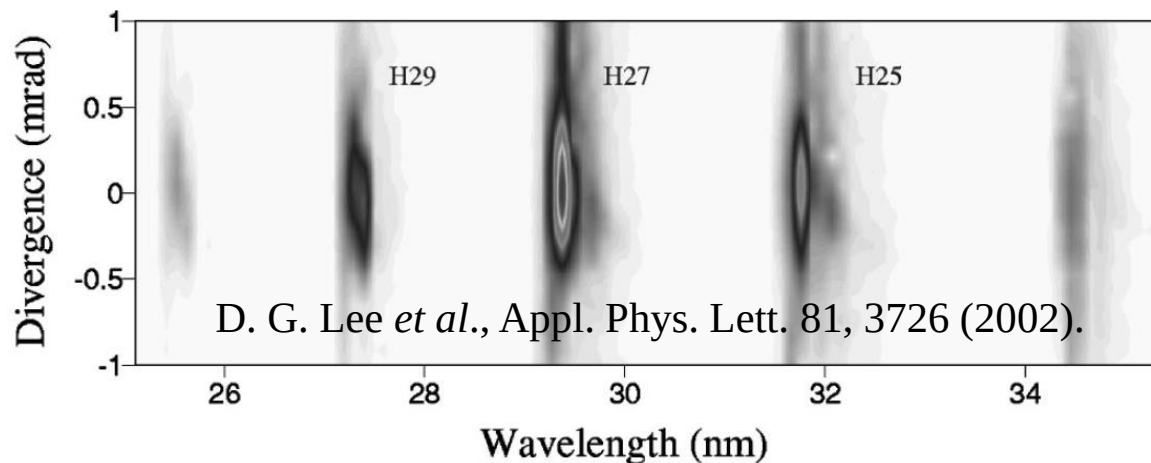
Sagittal focusing
(Toroidal mirror)
→ Enhancing light
collection



H. T. Kim *et al.*, Phys. Rev. A **67**, 051801(R) (2003).

Spectrally resolved divergence measurement of high-order harmonics

Sagittal diverging
(Cylindrical mirror)
→ beam profile
measurement



D. G. Lee *et al.*, Appl. Phys. Lett. **81**, 3726 (2002).

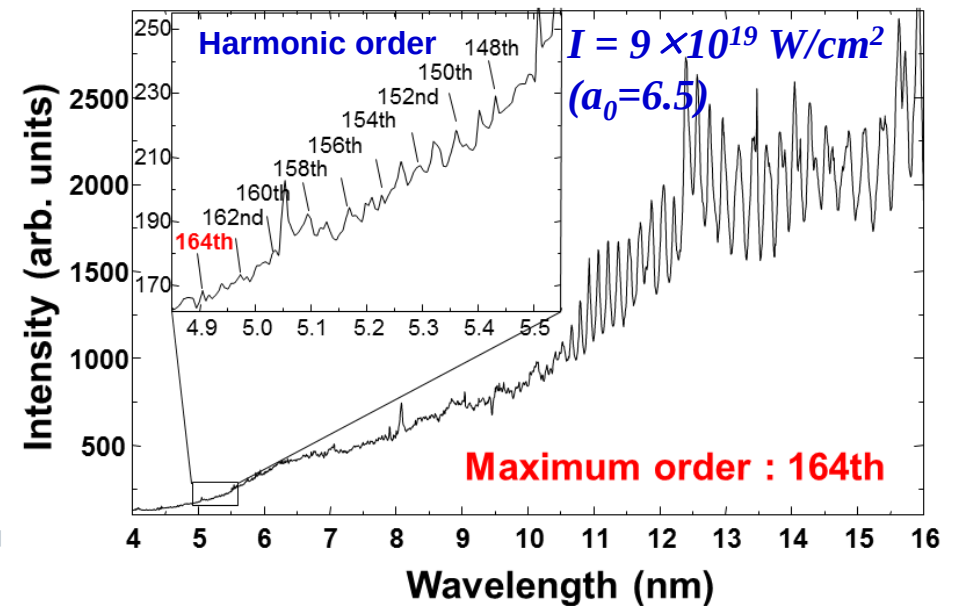
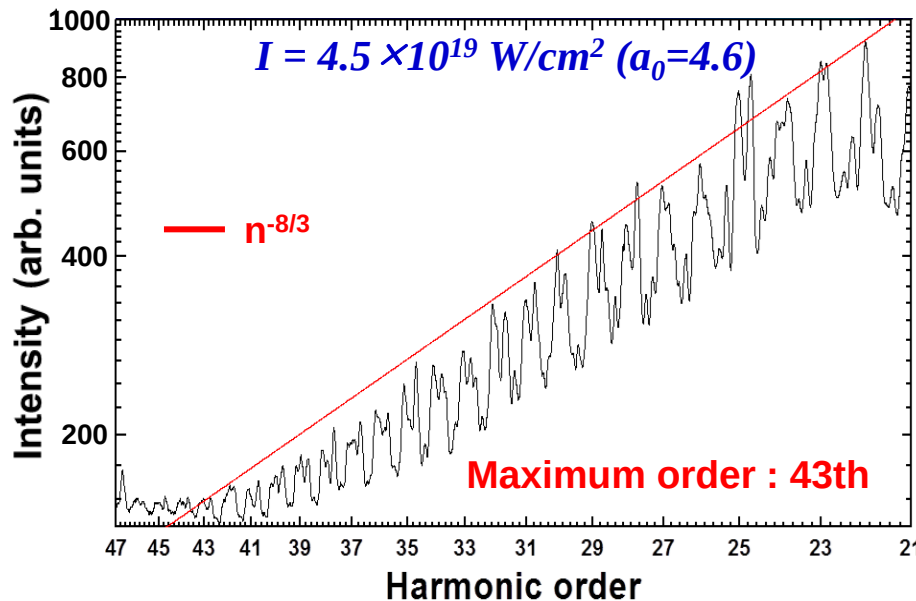
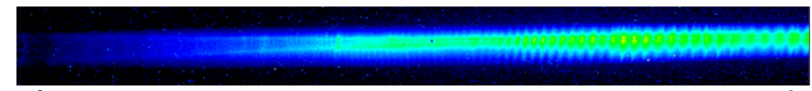
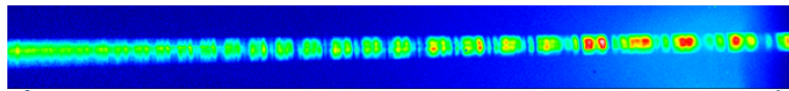


RHHG with High and Low Contrast Laser Pulses

Highest Relativistic Harmonics with < 100 fs Laser Pulses

- High Contrast condition -
(1.4×10^{-12} with PM)

- Optimal Contrast condition -
(7×10^{-8} without PM)



cf. When $a_0 = 4.6$, max order = 129 (6.4 nm)

I J. Kim, K.H. Pae, C.M. Kim, H.T. Kim, H. Yun, S.J. Yun, J.H. Sung, S.K. Lee, J.W. Yoon, T.J. Yu, T.M. Jeong, C.H. Nam, and J. Lee, "Relativistic frequency upshift to the XUV regime using self-induced oscillatory flying mirrors," *Nat. Commun.* (accepted).

Detectors Used for Laser-Driven Ion Diagnostics and Measurements

Rep. Prog. Phys. **75** (2012) 056401

H Daido *et al*

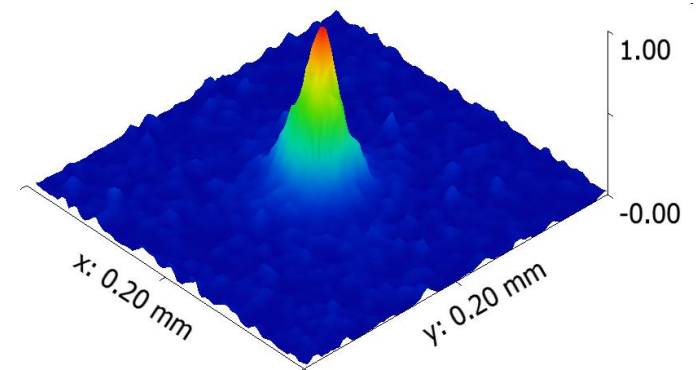
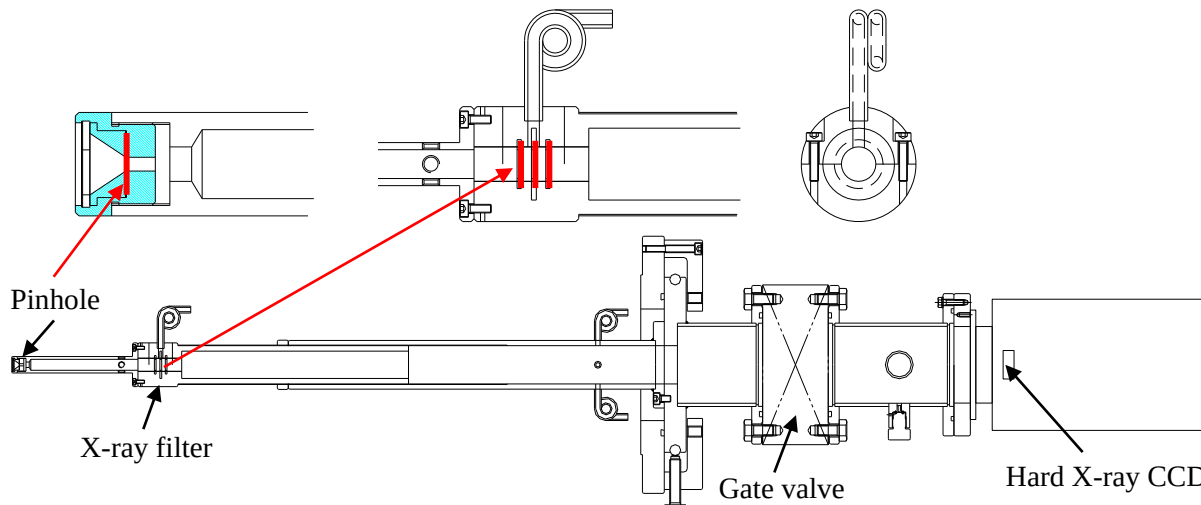
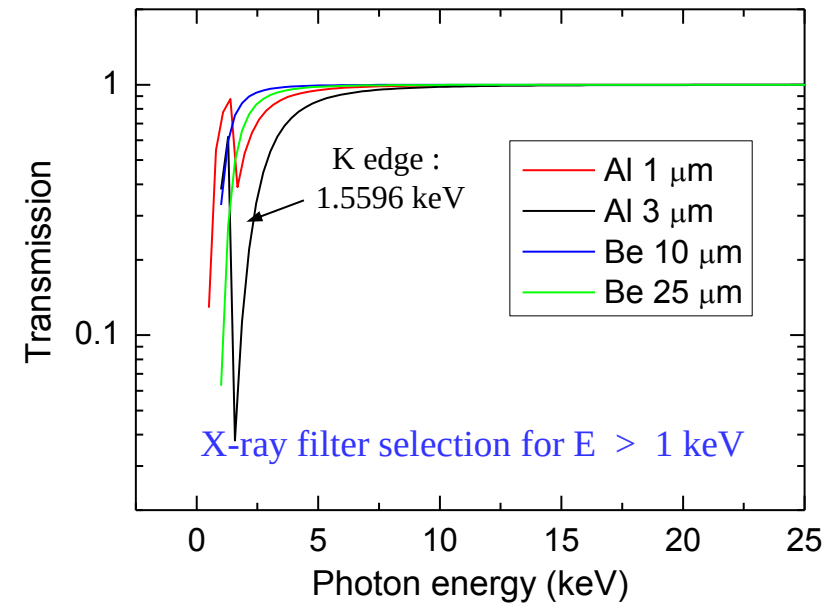
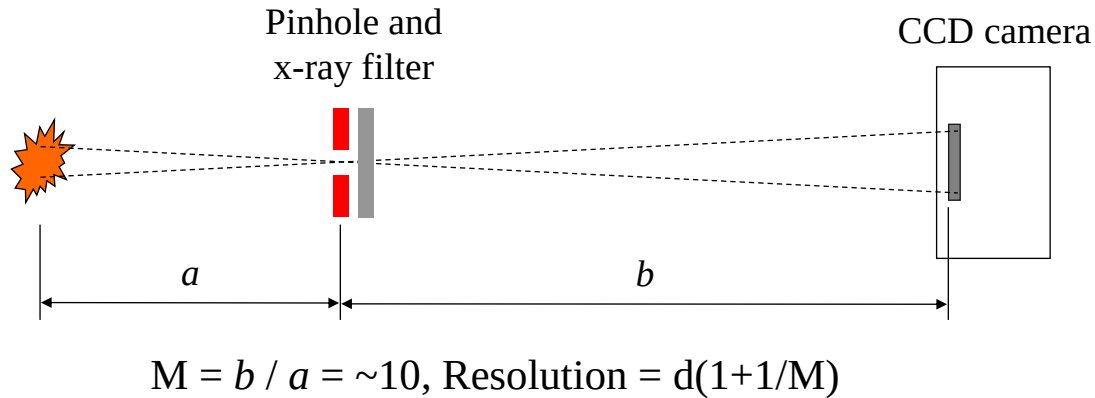
Table 1. Detectors commonly used for laser-driven ion diagnostics and measurements. Sensitivity: L: light, UV: ultraviolet, x: x-rays, e-: electrons; the notation ‘•’ represents ‘sensitive’.

	Spatial resolution	Time resolution	Treatment/display time	Single-particle sensitivity	Dynamic range (DR)	Sensitivity			Features/refs
						L	UV, x	e-	
Solid-state nuclear track detectors, e.g. CR-39 (allyl diglycol carbonate), etc	~ a few to a few tens of μm (pit size, depends on the ion kind and energy and etching time)	No	A few hours (etching, scanning, pit counting)	Yes	$\sim 10^2$ – 10^6 (background $\sim 10^2$ – 10^4 cm^{-2} , saturation $\sim 10^6$ – 10^8 cm^{-2})	—	—	—	(1) Sensitive to ions only ^a , single particles
Radiochromic film (RCF)	~ 3 – $10 \mu\text{m}$ (film, scanner)	No	Several minutes (scanning)	No	$\sim 10^2$ – 10^3 (e.g. 10 – 10^4 Gy)	—	•	•	(2) Self-developing
Imaging plate	Sub- $100 \mu\text{m}$ (scanner)	No	Several minutes (scanning)	No	$\sim 10^5$	—	•	•	(3) Reusable, high DR
Activation	Sub-mm (contact radiography)	No	Tens of minutes–a few hours (decay time)	No	Very high ($> 10^5$)	—	—	—	(4) Very high DR
Micro-channel plate (MCP)+phosphor screen + CCD	$\sim$ several 10 s of μm (imaging system)	$\sim$ a few 100 ps (MCP gate time)	$\sim$ a few seconds (CCD readout)	Yes	$\sim 10^3$	—	•	•	(5) Online, single particles
Scintillator + gated I-CCD or EM-CCD	$\sim$ several $100 \mu\text{m}$ (multiple scattering, imaging system)	$\sim$ a few 100 ps (scintillation time)	$\sim$ a few seconds (CCD readout)	No	$\sim 10^3$	•	•	•	(6) Online, stackable in depth

H. Daido, M. Nishiuchi, and A. S. Pirozhkov, Rep. Prog. Phys. **75**, 056401 (2012).



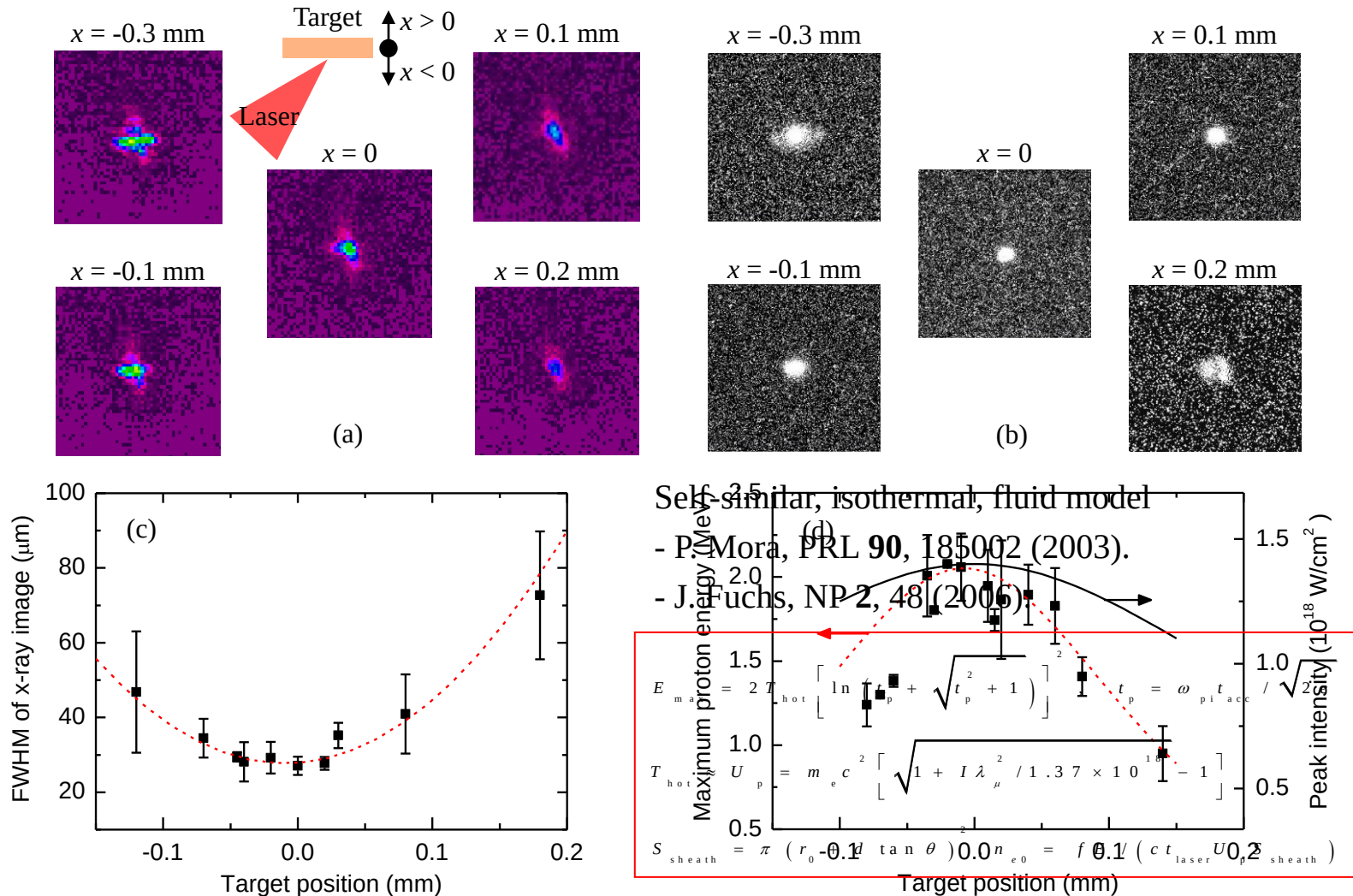
Hard X-Ray Image Acquisition with X-Ray Pinhole Camera





Correlation between Laser Focus Image, X-ray Image and Proton Energy

Hard X-ray image may give direct information on the hot electrons.

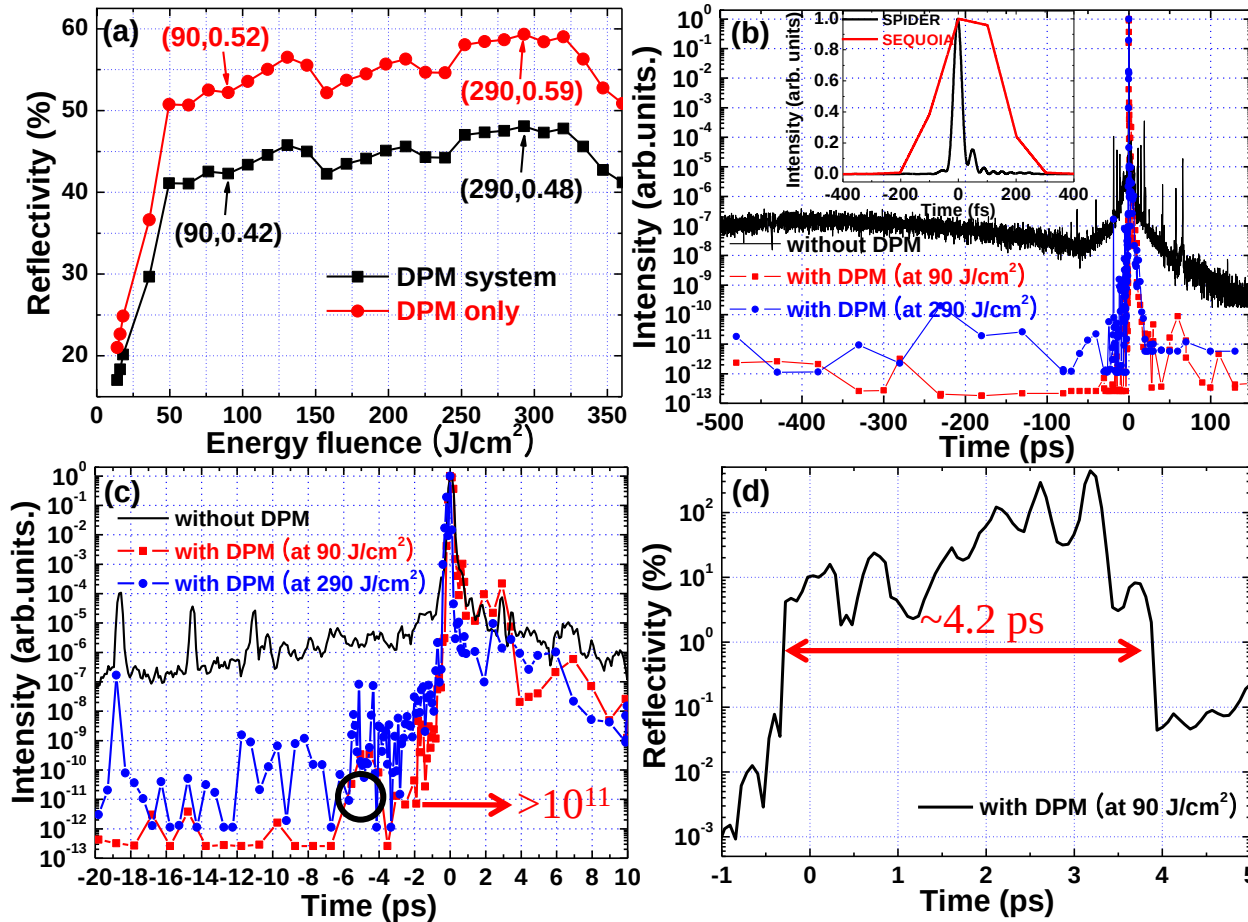




Contrast Ratio Enhancement Using Double Plasma Mirror System

Reflectivity of plasma mirror system : $> 40\%$ for laser energy fluences above 50 J/cm^2

Shock wave speed :
 $\sim 10 \text{ mm/ns}$
 $\sim 10 \text{ nm/ps}$



(a) Reflectivity as a function of the energy fluence incident on the first PM. (b) Temporal profiles of the laser beam between -500 ps and +150 ps, (c) between -20 ps and +10 ps and (d) Time-resolved reflectivity for the energy fluence of 90 J/cm^2 on DPM. The inset in Fig. (b) shows the temporal profiles of laser pulse measured with SPIDER and SEQUOIA respectively.